**Qualification Report**

**OpenCellular - Connect1**

**General Purpose Baseband Computing (GBC)**

Revision: 1.0

1. Purpose 39

2. Scope 39

3. References 39

4. Device-Under-Test (DUT) Details 39

5. Qualification Test Condition 40

6. Qualification Result Summary 40

7. Tools and Test Equipment 40

8. Abbreviation 40

9 Qualification Tests Results 42

9.1 Front Panel: 42

9.1.1 Solar Supply 42

9.1.1.1 Test ID / Test Name: FP.1.1 / Voltage accuracy 42

9.1.1.1.1 Purpose 42

9.1.1.1.2 Test and Measurement Method 42

9.1.1.1.3 Test Condition 42

9.1.1.1.4 DUT Sample Information 42

9.1.1.1.5 Test Results 42

9.1.1.1.6 Measurement Logs 43

9.1.1.2 Test ID / Test Name: FP.1.2 / Input supply range 43

9.1.1.2.1 Purpose 43

9.1.1.2.2 Test and Measurement Method 43

9.1.1.2.3 Test Condition 44

9.1.1.2.4 DUT Sample Information 44

9.1.1.2.5 Test Results 44

9.1.1.2.6 Measurement Logs 44

9.1.2 AUX Supply 45

9.1.2.1 Test ID / Test Name: FP.2.1 / Voltage accuracy 45

9.1.2.1.1 Purpose 45

9.1.2.1.2 Test and Measurement Method 45

9.1.2.1.3 Test Condition 45

9.1.2.1.4 DUT Sample Information 45

9.1.2.1.5 Test Results 45

9.1.2.1.6 Measurement Logs 45

9.1.2.2 Test ID / Test Name: FP.2.2 / Input supply range 46

9.1.2.2.1 Purpose 46

9.1.2.2.2 Test and Measurement Method 46

9.1.2.2.3 Test Condition 46

9.1.2.2.4 DUT Sample Information 47

9.1.2.2.5 Test Results 47

9.1.2.2.6 Measurement Logs 47

9.1.3 PoE In 48

9.1.3.1 Test ID / Test Name: FP.3.1 / Voltage Accuracy 48

9.1.3.1.1 Purpose 48

9.1.3.1.2 Test and Measurement Method 48

9.1.3.1.3 Test Condition 48

9.1.3.1.4 DUT Sample Information 48

9.1.3.1.5 Test Results 48

9.1.3.1.6 Measurement Logs 48

9.1.3.2 Test ID / Test Name: FP.3.2 / Input Voltage Range 49

9.1.3.2.1 Purpose 49

9.1.3.2.2 Test and Measurement Method 49

9.1.3.2.3 Test Condition 49

9.1.3.2.4 DUT Sample Information 49

9.1.3.2.5 Test Results 49

9.1.3.2.6 Measurement Logs 50

9.1.4 PoE – Data 50

9.1.4.1 Test ID / Test Name: FP.5.1 / Ethernet Compliance 50

9.1.4.1.1 Purpose 50

9.1.4.1.2 Test and Measurement Method 50

9.1.4.1.3 Test Condition 51

9.1.4.1.4 DUT Sample Information 51

9.1.4.1.5 Test Results 52

9.1.5 Protection 54

9.1.5.1 Test ID / Test Name: FP.6.1 / Output Voltage Accuracy 54

9.1.5.2 Test ID / Test Name: FP.6.2 / Solar AUX Present Test 54

9.1.5.2.1 Purpose 54

9.1.5.2.2 Test and Measurement Method 54

9.1.5.2.3 Test Condition 54

9.1.5.2.4 DUT Sample Information 54

9.1.5.2.5 Test Results 54

9.1.5.2.6 Measurement Logs 54

9.1.5.3 Test ID / Test Name: FP.6.3 / Protection Limit 55

9.1.5.3.1 Purpose 55

9.1.5.3.2 Test and Measurement Method 55

9.1.5.3.3 Test Condition 55

9.1.5.3.4 DUT Sample Information 55

9.1.5.3.5 Test Results 56

9.1.5.3.6 Measurement Logs 56

9.2 Power: 57

9.2.1 PoE 57

9.2.1.1 Test ID / Test Name: PWR.1.1 / Voltage Accuracy 57

9.2.1.2 Test ID / Test Name: PWR.1.2 / Ripple Measurement 57

9.2.1.2.1 Purpose 57

9.2.1.2.2 Test and Measurement Method 57

9.2.1.2.3 Test Condition 57

9.2.1.2.4 DUT Sample Information 57

9.2.1.2.5 Test Results 58

9.2.1.2.6 Measurement Logs 58

9.2.1.3 Test ID / Test Name: PWR.1.3 /PoE Present Check 58

9.2.1.3.1 Purpose 58

9.2.1.3.2 Test and Measurement Method 58

9.2.1.3.3 Test Condition 58

9.2.1.3.4 DUT Sample Information 59

9.2.1.3.5 Test Results 59

9.2.1.3.6 Measurement Logs 59

9.2.1.4 Test ID / Test Name: PWR.1.4 / Data transfer validation 59

9.2.1.4.1 Purpose 59

9.2.1.4.2 Test and Measurement Method 59

9.2.1.4.3 Test Condition 59

9.2.1.4.4 DUT Sample Information 60

9.2.1.4.5 Test Results 60

9.2.1.4.6 Measurement Logs 60

9.2.1.5 Test ID / Test Name: PWR.1.5 / Power delivery 60

9.2.1.5.1 Purpose 60

9.2.1.5.2 Test and Measurement Method 60

9.2.1.5.3 Test Condition 60

9.2.1.5.4 DUT Sample Information 61

9.2.1.5.5 Test Results 61

9.2.1.5.6 Measurement Logs 61

9.2.2 Isolated DC-DC Converter 61

9.2.2.1 Test ID / Test Name: PWR.3.1 / Output Voltage Accuracy 61

9.2.2.1.1 Purpose 61

9.2.2.1.2 Test and Measurement Method 62

9.2.2.1.3 Test Condition 62

9.2.2.1.4 DUT Sample Information 62

9.2.2.1.5 Test Results 62

9.2.2.1.6 Measurement Logs 62

9.2.2.2 Test ID / Test Name: PWR.3.2 / Solar AUX and PoE Or'ring circuit 63

9.2.2.2.1 Purpose 63

9.2.2.2.2 Test and Measurement Method 63

9.2.2.2.3 Test Condition 63

9.2.2.2.4 DUT Sample Information 63

9.2.2.2.5 Test Results 63

9.2.2.2.6 Measurement Logs 63

9.2.3 Lead Acid battery 64

9.2.3.1 Test ID / Test Name: PWR.4.1 / Output Voltage Accuracy 64

9.2.3.1.1 Purpose 64

9.2.3.1.2 Test and Measurement Method 64

9.2.3.1.3 Test Condition 64

9.2.3.1.4 DUT Sample Information 65

9.2.3.1.5 Test Results 65

9.2.3.1.6 Measurement Logs 65

9.2.3.2 Test ID / Test Name: PWR.4.2 / Charge current measurement 65

9.2.3.2.1 Purpose 65

9.2.3.2.2 Test and Measurement Method 66

9.2.3.2.3 Test Condition 66

9.2.3.2.4 DUT Sample Information 66

9.2.3.2.5 Test Results 66

9.2.3.3 Test ID / Test Name: PWR.4.3 / Load current measurement 67

9.2.3.3.1 Purpose 67

9.2.3.3.2 Test and Measurement Method 67

9.2.3.3.3 Test Condition 67

9.2.3.3.4 DUT Sample Information 67

9.2.3.3.5 Test Results 67

9.2.3.3.6 Measurement Logs 68

9.2.3.4 Test ID / Test Name: PWR.4.4 / LDO Output voltage 68

9.2.3.4.1 Purpose 68

9.2.3.4.2 Test and Measurement Method 68

9.2.3.4.3 Test Condition 68

9.2.3.4.4 DUT Sample Information 68

9.2.3.4.5 Test Results 68

9.2.3.4.6 Measurement Logs 69

9.2.3.5 Test ID / Test Name: PWR.4.5 / Temperature Measurement 69

9.2.3.5.1 Purpose 69

9.2.3.5.2 Test and Measurement Method 69

9.2.3.5.3 Test Condition 69

9.2.3.5.4 DUT Sample Information 69

9.2.3.5.5 Test Results 70

9.2.3.5.6 Measurement Logs 70

9.2.3.6 Test ID / Test Name: PWR.4.6 / Charge control 70

9.2.3.6.1 Purpose 70

9.2.3.6.2 Test and Measurement Method 70

9.2.3.6.3 Test Condition 70

9.2.3.6.4 DUT Sample Information 71

9.2.3.6.5 Test Results 71

9.2.3.7 Test ID / Test Name: PWR.4.7 / Lead Acid and LiON battery or ‘ring circuit 71

9.2.3.7.1 Purpose 71

9.2.3.7.2 Test and Measurement Method 71

9.2.3.7.3 Test Condition 71

9.2.3.7.4 DUT Sample Information 72

9.2.3.7.5 Test Results 72

9.2.3.7.6 Measurement Logs 72

9.2.3.8 Test ID / Test Name: PWR.4.8 / Power delivery 72

9.2.3.8.1 Purpose 72

9.2.3.8.2 Test and Measurement Method 72

9.2.3.8.3 Test Condition 73

9.2.3.8.4 DUT Sample Information 73

9.2.3.8.5 Test Results 73

9.2.3.8.6 Measurement Logs 73

9.2.4 Lithium Ion Battery 74

9.2.4.1 Test ID / Test Name: PWR.5.1 / Output Voltage Accuracy 74

9.2.4.1.1 Purpose 74

9.2.4.1.2 Test and Measurement Method 74

9.2.4.1.3 Test Condition 74

9.2.4.1.4 DUT Sample Information 74

9.2.4.1.5 Test Results 74

9.2.4.1.6 Measurement Logs 74

9.2.4.2 Test ID / Test Name: PWR.5.2 / Charge Current Measurement 75

9.2.4.2.1 Purpose 75

9.2.4.2.2 Test and Measurement Method 75

9.2.4.2.3 Test Condition 75

9.2.4.2.4 DUT Sample Information 76

9.2.4.2.5 Measurement Logs 76

9.2.4.3 Test ID / Test Name: PWR.5.3 / Load current measurement 76

9.2.4.3.1 Purpose 76

9.2.4.3.2 Test and Measurement Method 76

9.2.4.3.3 Test Condition 76

9.2.4.3.4 DUT Sample Information 76

9.2.4.3.5 Test Results 76

9.2.4.3.6 Measurement Logs 77

9.2.4.4 Test ID / Test Name: PWR.5.4 / LDO Output Voltage 77

9.2.4.4.1 Purpose 77

9.2.4.4.2 Test and Measurement Method 77

9.2.4.4.3 Test Condition 77

9.2.4.4.4 DUT Sample Information 77

9.2.4.4.5 Test Result 77

9.2.4.4.6 Measurement Logs 77

9.2.4.5 Test ID / Test Name: PWR.5.5 / Temperature Measurement 78

9.2.4.5.1 Purpose 78

9.2.4.5.2 Test and Measurement Method 78

9.2.4.5.3 Test Condition 78

9.2.4.5.4 DUT Sample Information 78

9.2.4.5.5 Test Result 78

9.2.4.5.6 Measurement Logs 78

9.2.4.6 Test ID / Test Name: PWR.5.6 / Charge control (JEITA) 79

9.2.4.6.1 Purpose 79

9.2.4.6.2 Test and Measurement Method 79

9.2.4.6.3 Test Condition 79

9.2.4.6.4 DUT Sample Information 80

9.2.4.6.5 Test Results 80

9.2.4.6.6 Measurement Logs 80

9.2.4.7 Test ID / Test Name: PWR.5.7 / Lion – Lead Acid and LiON battery or ‘ing circuit 80

9.2.4.7.1 Purpose 80

9.2.4.7.2 Test and Measurement Method 80

9.2.4.7.3 Test Condition 80

9.2.4.7.4 DUT Sample Information 80

9.2.4.7.5 Test Results 81

9.2.4.7.6 Measurement Logs 81

9.2.4.8 Test ID / Test Name: PWR.5.8 / Charge time 81

9.2.4.8.1 Purpose 81

9.2.4.8.2 Test and Measurement Method 81

9.2.4.8.3 Test Condition 81

9.2.4.8.4 DUT Sample Information 82

9.2.4.8.5 Test Results 82

9.2.4.8.6 Measurement Logs 82

9.2.4.9 Test ID / Test Name: PWR.5.9 / Power delivery 82

9.2.4.9.1 Purpose 82

9.2.4.9.2 Test and Measurement Method 82

9.2.4.9.3 Test Condition 82

9.2.4.9.4 DUT Sample Information 82

9.2.4.9.5 Test Results 83

9.2.4.9.6 Measurement Logs 83

9.2.5 Buck-Boost 83

9.2.5.1 Test ID / Test Name: PWR.6.1 / Line regulation 83

9.2.5.1.1 Purpose 83

9.2.5.1.2 Test and Measurement Method 84

9.2.5.1.3 Test Condition 84

9.2.5.1.4 DUT Sample Information 84

9.2.5.1.5 Test Results 84

9.2.5.1.6 Measurement Logs 84

9.2.5.2 Test ID / Test Name: PWR.6.2 / Load regulation 85

9.2.5.2.1 Purpose 85

9.2.5.2.2 Test and Measurement Method 86

9.2.5.2.3 Test Condition 86

9.2.5.2.4 DUT Sample Information 86

9.2.5.2.5 Test Results 86

9.2.5.2.6 Measurement Logs 86

9.2.5.3 Test ID / Test Name: PWR.6.3 / Ripple measurement 87

9.2.5.3.1 Purpose 87

9.2.5.3.2 Test and Measurement Method 87

9.2.5.3.3 Test Condition 87

9.2.5.3.4 DUT Sample Information 87

9.2.5.3.5 Test Results 87

9.2.5.3.6 Measurement Logs 88

9.2.5.4 Test ID / Test Name: PWR.6.4 / Load Current Measurement 89

9.2.5.4.1 Purpose 89

9.2.5.4.2 Test and Measurement Method 90

9.2.5.4.3 Test Condition 90

9.2.5.4.4 DUT Sample Information 90

9.2.5.4.5 Test Results 90

9.2.5.4.6 Measurement Logs 90

9.2.5.5 Test ID / Test Name: PWR.6.5 / Temperature Measurement 91

9.2.5.5.1 Purpose 91

9.2.5.5.2 Test and Measurement Method 91

9.2.5.5.3 Test Condition 91

9.2.5.5.4 DUT Sample Information 91

9.2.5.5.5 Test Results 91

9.2.5.5.6 Measurement Logs 91

9.2.6 TIVA Power Supply 92

9.2.6.1 Test ID / Test Name: PWR.7.3 / Ripple measurement 92

9.2.6.1.1 Purpose 92

9.2.6.1.2 Test and Measurement Method 92

9.2.6.1.3 Test Condition 92

9.2.6.1.4 DUT Sample Information 92

9.2.6.1.5 Test Results 93

9.2.6.1.6 Measurement Logs 93

9.2.6.2 Test ID / Test Name: PWR.7.4 / Load Current Measurement 93

9.2.6.2.1 Purpose 93

9.2.6.2.2 Test and Measurement Method 93

9.2.6.2.3 Test Condition 93

9.2.6.2.4 DUT Sample Information 93

9.2.6.2.5 Test Results 94

9.2.6.2.6 Measurement Logs 94

9.2.6.3 Test ID / Test Name: PWR.7.5 / Temperature Measurement 94

9.2.6.3.1 Purpose 94

9.2.6.3.2 Test and Measurement Method 94

9.2.6.3.3 Test Condition 95

9.2.6.3.4 DUT Sample Information 95

9.2.6.3.5 Test Results 95

9.2.6.3.6 Measurement Logs 95

9.2.7 FET Switch 96

9.2.7.1 Test ID / Test Name: PWR.9.3 / Ripple Measurement 96

9.2.7.1.1 Purpose 96

9.2.7.1.2 Test and Measurement Method 96

9.2.7.1.3 Test Condition 96

9.2.7.1.4 DUT Sample Information 96

9.2.7.1.5 Test Results 96

9.2.7.1.6 Measurement Logs 96

9.2.7.2 Test ID / Test Name: PWR.9.4 / Load Current Measurement 97

9.2.7.2.1 Purpose 97

9.2.7.2.2 Test and Measurement Method 97

9.2.7.2.3 Test Condition 97

9.2.7.2.4 DUT Sample Information 97

9.2.7.2.5 Test Results 97

9.2.7.2.6 Measurement Logs 97

9.2.7.3 Test ID / Test Name: PWR.9.5/ Temperature Measurement 98

9.2.7.3.1 Purpose 98

9.2.7.3.2 Test and Measurement Method 98

9.2.7.3.3 Test Condition 98

9.2.7.3.4 DUT Sample Information 98

9.2.7.3.5 Test Results 99

9.2.7.3.6 Measurement logs 99

9.2.8 PMIC 99

9.2.8.1 Test ID / Test Name: PWR.10.2 / Voltage accuracy of all output voltages 99

9.2.8.1.1 Purpose 99

9.2.8.1.2 Test and Measurement Method 99

9.2.8.1.3 Test Condition 99

9.2.8.1.4 DUT Sample Information 100

9.2.8.1.5 Test Results 100

9.2.8.1.6 Measurement Logs 100

9.2.8.2 Test ID / Test Name: PWR.10.3/ Secondary supplies enable functionality 101

9.2.8.2.1 Purpose 101

9.2.8.2.2 Test and Measurement Method 101

9.2.8.2.3 Test Condition 101

9.2.8.2.4 DUT Sample Information 101

9.2.8.2.5 Test Results 101

9.2.8.2.6 Measurement Logs 101

9.2.8.3 Test ID / Test Name: PWR.10.5/ PMIC debug circuit functionality 102

9.2.8.3.1 Purpose 102

9.2.8.3.2 Test and Measurement Method 102

9.2.8.3.3 Test Condition 102

9.2.8.3.4 DUT Sample Information 103

9.2.8.3.5 Test Results 103

9.2.8.3.6 Measurement Logs 103

9.2.9 System Power sequence 104

9.2.9.1 Test ID / Test Name: PWR.11.1 / Power-up 104

9.2.9.1.1 Purpose 104

9.2.9.1.2 Test and Measurement Method 104

9.2.9.1.3 Test Condition 104

9.2.9.1.4 DUT Sample Information 104

9.2.9.1.5 Test Results 104

9.2.9.1.6 Measurement Logs 104

9.2.9.2 Test ID / Test Name: PWR.11.2 / Power-down 105

9.2.9.2.1 Purpose 105

9.2.9.2.2 Test and Measurement Method 105

9.2.9.2.3 Test Condition 105

9.2.9.2.4 DUT Sample Information 105

9.2.9.2.5 Test Results 106

9.2.9.2.6 Measurement Logs 106

9.2.9.3 Test ID / Test Name: PWR.11.3 / Soft Reset 106

9.2.9.3.1 Purpose 106

9.2.9.3.2 Test and Measurement Method 106

9.2.9.3.3 Test Condition 107

9.2.9.3.4 DUT Sample Information 107

9.2.9.3.5 Test Results 107

9.2.9.3.6 Measurement Logs 107

9.2.9.4 Test ID / Test Name: PWR.11.4 / Hard Reset 107

9.2.9.4.1 Purpose 107

9.2.9.4.2 Test and Measurement Method 108

9.2.9.4.3 Test Condition 108

9.2.9.4.4 DUT Sample Information 108

9.2.9.4.5 Test Results 108

9.2.9.4.6 Measurement Logs 108

9.3 CPU 109

9.3.1 Intel Atom 109

9.3.1.1 Test ID / Test Name: CPU.1.1/ Boot configuration 109

9.3.1.1.1 Purpose 109

9.3.1.1.2 Test and Measurement Method 109

9.3.1.1.3 Test Condition 109

9.3.1.1.4 DUT Sample Information 109

9.3.1.1.5 Test Results 109

9.3.1.1.6 Measurement Logs 109

9.3.1.2 Test ID / Test Name: CPU.1.2/ Power-on sequence 110

9.3.1.2.1 Purpose 110

9.3.1.2.2 Test and Measurement Method 110

9.3.1.2.3 Test Condition 110

9.3.1.2.4 DUT Sample Information 110

9.3.1.2.5 Test Results 110

9.3.1.2.6 Measurement Logs 110

9.3.1.3 Test ID / Test Name: CPU.1.3/ Power-down sequence 111

9.3.1.4.1 Purpose 111

9.3.1.4.2 Test and Measurement Method 111

9.3.1.4.3 Test Condition 112

9.3.1.4.4 DUT Sample Information 112

9.3.1.4.5 Test Results 112

9.3.1.4.6 Measurement Logs 112

9.3.2 PMIC (IDTP9145) - I2C 113

9.3.2.1 Test ID / Test Name: CPU.2.1 / Electrical validation 113

9.3.2.1.1 Purpose 113

9.3.2.1.2 Test and Measurement Method 113

9.3.2.1.3 Test Condition 113

9.3.2.1.4 DUT Sample Information 113

9.3.2.1.5 Test Results 113

9.3.2.1.6 Measurement Logs 113

9.3.2.2 Test ID / Test Name: CPU.2.2/ Signal integrity 114

9.3.2.2.1 Purpose 114

9.3.2.2.2 Test and Measurement Method 114

9.3.2.2.3 Test Condition 114

9.3.2.2.4 DUT Sample Information 115

9.3.2.2.5 Test Results 115

9.3.2.2.6 Measurement Logs 115

9.3.2.3 Test ID / Test Name: CPU.2.3/ Functional validation 116

9.3.2.3.1 Purpose 116

9.3.2.3.2 Test and Measurement Method 116

9.3.2.3.3 Test Condition 116

9.3.2.3.4 DUT Sample Information 116

9.3.2.3.5 Test Results 116

9.3.2.3.6 Measurement Logs 116

9.3.3 DDR (TS512MSK64W6H-I) - SMBus 117

9.3.3.1 Test ID / Test Name: CPU.5.1/ Electrical validation 117

9.3.3.1.1 Purpose 117

9.3.3.1.2 Test and Measurement Method 117

9.3.3.1.3 Test Condition 117

9.3.3.1.4 DUT Sample Information 117

9.3.3.1.5 Test Results 117

9.3.3.1.6 Measurement Logs 117

9.3.3.2 Test ID / Test Name: CPU.5.2 / Signal integrity 119

9.3.3.2.1 Purpose 119

9.3.3.2.2 Test and Measurement Method 119

9.3.3.2.3 Test Condition 119

9.3.3.2.4 DUT Sample Information 119

9.3.3.2.5 Test Results 119

9.3.3.2.6 Measurement Logs 119

9.3.3.3 Test ID / Test Name: CPU.5.3 / Functional validation 121

9.3.3.3.1 Purpose 121

9.3.3.3.2 Test and Measurement Method 121

9.3.3.3.3 Test Condition 121

9.3.3.3.4 DUT Sample Information 121

9.3.3.3.5 Test Results 121

9.3.3.3.6 Measurement Logs 121

9.3.4 PCU (ADT7481) - SMBus 122

9.3.4.1 Test ID / Test Name: CPU.6.1/ Electrical validation 122

9.3.4.1.1 Purpose 122

9.3.4.1.2 Test and Measurement Method 122

9.3.4.1.3 Test Condition 122

9.3.4.1.4 DUT Sample Information 122

9.3.4.1.5 Test Results 122

9.3.4.1.6 Measurement Logs 123

9.3.4.2 Test ID / Test Name: CPU.6.2 / Signal Integrity 123

9.3.4.2.1 Purpose 123

9.3.4.2.2 Test and Measurement Method 124

9.3.4.2.3 Test Condition 124

9.3.4.2.4 DUT Sample Information 124

9.3.4.2.5 Test Results 124

9.3.4.2.6 Measurement Logs 124

9.3.4.3 Test ID / Test Name: CPU.6.3 / Functional validation 125

9.3.4.3.1 Purpose 125

9.3.4.3.2 Test and Measurement Method 126

9.3.4.3.3 Test Condition 126

9.3.4.3.4 DUT Sample Information 126

9.3.4.3.5 Test Results 126

9.3.4.3.6 Measurement Logs 126

9.3.5 Springville 1 - MDI 127

9.3.5.1 Test ID / Test Name: CPU.7.1/ Signal characteristics 127

9.3.5.1.1 Purpose 127

9.3.5.1.2 Test and Measurement Method 127

9.3.5.1.3 Test Condition 127

9.3.5.1.4 DUT Sample Information 127

9.3.5.1.5 Test Results 127

9.3.5.1.6 Measurement Logs 127

9.3.5.2 Test ID / Test Name: CPU.7.2/ Functional validation 128

9.3.5.2.1 Purpose 128

9.3.5.2.2 Test and Measurement Method 128

9.3.5.2.3 Test Condition 129

9.3.5.2.4 DUT Sample Information 129

9.3.5.2.5 Test Results 129

9.3.6 TIVA - UART 129

9.3.6.1 Test ID / Test Name: CPU.8.1 / Electrical validation 129

9.3.6.1.1 Purpose 129

9.3.6.1.2 Test and Measurement Method 129

9.3.6.1.3 Test Condition 130

9.3.6.1.4 DUT Sample Information 130

9.3.6.1.5 Test Results 130

9.3.6.1.6 Measurement Logs 130

9.3.6.2 Test ID / Test Name: CPU.8.2 / Functional validation 131

9.3.6.2.1 Purpose 131

9.3.6.2.2 Test and Measurement Method 131

9.3.6.2.3 Test Condition 131

9.3.6.2.4 DUT Sample Information 131

9.3.6.2.5 Test Results 131

9.3.6.2.6 Measurement Logs 132

9.3.7 Memory - DDR 132

9.3.7.1 Test ID / Test Name: CPU.9.1 / Reference voltage measurement 132

9.3.7.1.1 Purpose 132

9.3.7.1.2 Test and Measurement Method 132

9.3.7.1.3 Test Condition 132

9.3.7.1.4 DUT Sample Information 132

9.3.7.1.5 Test Results 133

9.3.7.1.6 Measurement Logs 133

9.3.7.2 Test ID / Test Name: CPU.9.2 / VREF Schmoo test 133

9.3.7.2.1 Purpose 133

9.3.7.2.2 Test and Measurement Method 133

9.3.7.2.3 Test Condition 134

9.3.7.2.4 DUT Sample Information 134

9.3.7.2.5 Test Results 134

9.3.7.2.6 Measurement Logs 134

9.3.7.3 Test ID / Test Name: CPU.9.3 / Functional validation 136

9.3.7.3.1 Purpose 136

9.3.7.3.2 Test and Measurement Method 136

9.3.7.3.3 Test Condition 136

9.3.7.3.4 DUT Sample Information 136

9.3.7.3.5 Test Results 136

9.3.7.3.6 Measurement Logs 136

9.3.7.4 Test ID / Test Name: CPU.9.4 / Throughput measurement 137

9.3.7.4.1 Purpose 137

9.3.7.4.2 Test and Measurement Method 137

9.3.7.4.3 Test Condition 137

9.3.7.4.4 DUT Sample Information 137

9.3.7.4.5 Test Results 137

9.3.7.4.6 Measurement Logs 138

9.3.8 Memory SPI NOR Flash 138

9.3.8.1 Test ID / Test Name: CPU.10.1 / Electrical validation 138

9.3.8.1.1 Purpose 138

9.3.8.1.2 Test and Measurement Method 138

9.3.8.1.3 Test Condition 138

9.3.8.1.4 DUT Sample Information 138

9.3.8.1.5 Test Results 139

9.3.8.1.6 Measurement Logs 139

9.3.8.2 Test ID / Test Name: CPU.10.2 / Signal Integrity 139

9.3.8.3.1 Purpose 139

9.3.8.3.2 Test and Measurement Method 139

9.3.8.3.3 Test Condition 140

9.3.8.3.4 DUT Sample Information 140

9.3.8.3.5 Test Results 140

9.3.8.3.6 Measurement Logs 140

9.3.9 Storage - mSATA 141

9.3.9.1 Test ID / Test Name: CPU.11.1 / Signal Integrity 141

9.3.9.1.1 Purpose 141

9.3.9.1.2 Test and Measurement Method 141

9.3.9.1.3 Test Condition 141

9.3.9.1.4 DUT Sample Information 141

9.3.9.1.5 Test Results 142

9.3.9.1.6 Measurement Logs 142

9.3.9.2 Test ID / Test Name: CPU.11.2 / IO Stress 143

9.3.9.2.1 Purpose 143

9.3.9.2.2 Test and Measurement Method 143

9.3.9.2.3 Test Condition 143

9.3.9.2.4 DUT Sample Information 143

9.3.9.2.5 Test Results 143

9.3.9.2.6 Measurement Logs 143

9.3.10 SpringVille1 – PCIe 144

9.3.10.1 Test ID / Test Name: CPU.13.1 and CPU.13.2 / Electrical Validation, Eye – plotting 144

9.3.10.1.1 Purpose 144

9.3.10.1.2 Test and Measurement Method 144

9.3.10.1.3 Test Condition 145

9.3.10.1.4 DUT Sample Information 145

9.3.10.1.5 Test Results 145

9.3.10.1.6 Measurement Logs 145

9.3.11 SpringVille2 – PCIe 146

9.3.11.1 Test ID / Test Name: CPU.14.1 and CPU14.2 / Electrical Validation, Eye – plotting 146

9.3.11.1.1 Purpose 146

9.3.11.1.2 Test and Measurement Method 147

9.3.11.1.3 Test Condition 147

9.3.11.1.4 DUT Sample Information 147

9.3.11.1.5 Test Results 148

9.3.12 TRXFE – GPIO 150

9.3.12.1 Test ID / Test Name: CPU.15.2 / Control outputs functional validation 150

9.3.12.1.1 Purpose 150

9.3.12.1.2 Test and Measurement Method 150

9.3.12.1.3 Test Condition 150

9.3.12.1.4 DUT Sample Information 150

9.3.12.1.5 Test Results 150

9.3.12.1.6 Measurement Logs 151

9.3.12.2 Test ID / Test Name: CPU.15.3 / Signaling characteristics 151

9.3.12.2.1 Purpose 151

9.3.12.2.2 Test and Measurement Method 151

9.3.12.2.3 Test Condition 151

9.3.12.2.4 DUT Sample Information 151

9.3.12.2.5 Test Results 152

9.3.12.2.6 Measurement Logs 152

9.3.13 TIVA - GPIO 153

9.3.13.1 Test ID / Test Name: CPU.17.1 / Control inputs functional validation 153

9.3.13.1.1 Purpose 153

9.3.13.1.2 Test and Measurement Method 153

9.3.13.1.3 Test Condition 153

9.3.13.1.4 DUT Sample Information 153

9.3.13.1.5 Test Results 153

9.3.13.1.6 Measurement Logs 154

9.3.13.2 Test ID / Test Name: CPU.17.2 / Control outputs functional validation 154

9.3.13.2.1 Purpose 154

9.3.13.2.2 Test and Measurement Method 154

9.3.13.2.3 Test Condition 154

9.3.13.2.4 DUT Sample Information 154

9.3.13.2.5 Test Results 154

9.3.13.2.6 Measurement Logs 155

9.3.13.3 Test ID / Test Name: CPU.17.3 / Signaling characteristics 155

9.3.13.3.1 Purpose 155

9.3.13.3.2 Test and Measurement Method 155

9.3.13.3.3 Test Condition 155

9.3.13.3.4 DUT Sample Information 155

9.3.13.3.5 Test Results 156

9.3.13.3.6 Measurement Logs 156

9.3.14 TRXFE- FX3 - USB 2.0 156

9.3.14.1 Test ID / Test Name: CPU.19.1 / Electrical validation 156

9.3.14.1.1 Purpose 156

9.3.14.1.2 Test and Measurement Method 156

9.3.14.1.3 Test Condition 157

9.3.14.1.4 DUT Sample Information 157

9.3.14.1.5 Test Results 157

9.3.14.1.6 Measurement Logs 157

9.3.14.2 Test ID / Test Name: CPU.19.2 / Throughput measurement 157

9.3.14.2.1 Purpose 157

9.3.14.2.2 Test and Measurement Method 157

9.3.14.2.3 Test Condition 158

9.3.14.2.4 DUT Sample Information 158

9.3.14.2.5 Test Results 158

9.3.14.2.6 Measurement Logs 158

9.3.14.3 Test ID / Test Name: CPU.19.3 / Functional validation 158

9.3.14.3.1 Purpose 158

9.3.14.3.2 Test and Measurement Method 158

9.3.14.3.3 Test Condition 159

9.3.14.3.4 DUT Sample Information 159

9.3.14.3.5 Test Results 159

9.3.14.3.6 Measurement Logs 159

9.3.15 TRXFE- FX3 - USB 3.0 159

9.3.15.1 Test ID / Test Name: CPU.20.2 / Throughput measurement 159

9.3.15.1.1 Purpose 159

9.3.15.1.2 Test and Measurement Method 160

9.3.15.1.3 Test Condition 160

9.3.15.1.4 DUT Sample Information 160

9.3.15.1.5 Test Results 160

9.3.15.1.6 Measurement Logs 160

9.3.15.2 Test ID / Test Name: CPU.20.3 / Functional validation 160

9.3.15.2.1 Purpose 160

9.3.15.2.2 Test and Measurement Method 161

9.3.15.2.3 Test Condition 161

9.3.15.2.4 DUT Sample Information 161

9.3.15.2.5 Test Results 161

9.3.15.2.6 Measurement Logs 161

9.3.16 Debug USB 2.0 162

9.3.16.1 Test ID / Test Name: CPU.21.1 / Functional validation 162

9.3.16.1.1 Purpose 162

9.3.16.1.2 Test and Measurement Method 162

9.3.16.1.3 Test Condition 162

9.3.16.1.4 DUT Sample Information 162

9.3.16.1.5 Test Results 162

9.3.16.1.6 Measurement Logs 162

9.3.17 Debug USB 3.0 163

9.3.17.1 Test ID / Test Name: CPU.22.1 / Functional validation 163

9.3.17.1.1 Purpose 163

9.3.17.1.2 Test and Measurement Method 163

9.3.17.1.3 Test Condition 163

9.3.17.1.4 DUT Sample Information 163

9.3.17.1.5 Test Results 163

9.3.17.1.6 Measurement Logs 163

9.3.18 Debug - Ethernet 164

9.3.18.1 Test ID / Test Name: CPU.23.1 / Functional validation 164

9.3.18.1.1 Purpose 164

9.3.18.1.2 Test and Measurement Method 164

9.3.18.1.3 Test Condition 164

9.3.18.1.4 DUT Sample Information 164

9.3.18.1.5 Test Results 165

9.3.18.1.6 Measurement Logs 165

9.3.19 Display-HDMI 165

9.3.19.1 Test ID / Test Name: CPU.24.1 / Functional validation with debug port 165

9.3.19.1.1 Purpose 165

9.3.19.1.2 Test and Measurement Method 165

9.3.19.1.3 Test Condition 165

9.3.19.1.4 DUT Sample Information 166

9.3.19.1.5 Test Results 166

9.3.19.1.6 Measurement Logs 166

9.3.20 Debug - UART 166

9.3.20.1 Test ID / Test Name: CPU.25.1 / Functional validation 166

9.3.20.1.1 Purpose 166

9.3.20.1.2 Test and Measurement Method 166

9.3.20.1.3 Test Condition 167

9.3.20.1.4 DUT Sample Information 167

9.3.20.1.5 Test Results 167

9.3.20.1.6 Measurement Logs 167

9.3.21 RFSDR – PCIe 167

9.3.21.1 Test ID / Test Name: CPU.26.1 and CPU26.2 / RFSDR-PCIe0 167

9.3.21.1.1 Purpose 167

9.3.21.1.2 Test and Measurement Method 168

9.3.21.1.3 Test Condition 168

9.3.21.1.4 DUT Sample Information 168

9.3.21.1.5 Test Results 168

9.3.21.1.6 Measurement Logs 168

9.4 TIVA 171

9.4.1 TIVA Access 171

9.4.1.1 Test ID / Test Name: TIV.1.1 / Configuration 171

9.4.1.1.1 Purpose 171

9.4.1.1.2 Test and Measurement Method 171

9.4.1.1.3 Test Condition 171

9.4.1.1.4 DUT Sample Information 171

9.4.1.1.5 Test Results 171

9.4.1.1.6 Measurement Logs 171

9.4.1.2 Test ID / Test Name: TIV.1.2 / System Reset sequence 172

9.4.1.2.1 Purpose 172

9.4.1.2.2 Test and Measurement Method 172

9.4.1.2.3 Test Condition 172

9.4.1.2.4 DUT Sample Information 172

9.4.1.2.5 Test Results 172

9.4.1.2.6 Measurement Logs 173

9.4.2 PSE – I2C (LTC4274AIUHF) 173

9.4.2.1 Test ID / Test Name: TIV.2.1 / Electrical validation 173

9.4.2.1.1 Purpose 173

9.4.2.1.2 Test and Measurement Method 173

9.4.2.1.3 Test Condition 174

9.4.2.1.4 DUT Sample Information 174

9.4.2.1.5 Test Results 174

9.4.2.1.6 Measurement Logs 174

9.4.2.2 Test ID / Test Name: TIV.2.2 / Signal Integrity 175

9.4.2.2.1 Purpose 175

9.4.2.2.2 Test and Measurement Method 175

9.4.2.2.3 Test Condition 176

9.4.2.2.4 DUT Sample Information 176

9.4.2.2.5 Test Results 176

9.4.2.2.6 Measurement Logs 176

9.4.2.3 Test ID / Test Name: TIV.2.3 / Functional validation 177

9.4.2.3.1 Purpose 177

9.4.2.3.2 Test and Measurement Method 177

9.4.2.3.3 Test Condition 177

9.4.2.3.4 DUT Sample Information 177

9.4.2.3.5 Test Results 177

9.4.2.3.6 Measurement Logs 177

9.4.3 Power Monitor (INA226) – I2C 178

9.4.3.1 Test ID / Test Name: TIV.3.1 / Electrical validation 178

9.4.3.1.1 Purpose 178

9.4.3.1.2 Test and Measurement Method 178

9.4.3.1.3 Test Condition 178

9.4.3.1.4 DUT Sample Information 178

9.4.3.1.5 Test Results 178

9.4.3.1.6 Measurement Logs 178

9.4.3.2 Test ID / Test Name: TIV.3.2 / Signal Integrity 179

9.4.3.2.1 Purpose 179

9.4.3.2.2 Test and Measurement Method 179

9.4.3.2.3 Test Condition 179

9.4.3.2.4 DUT Sample Information 180

9.4.3.2.5 Test Results 180

9.4.3.2.6 Measurement Logs 180

9.4.3.3 Test ID / Test Name: TIV.3.3 / Functional validation 180

9.4.3.3.1 Purpose 180

9.4.3.3.2 Test and Measurement Method 181

9.4.3.3.3 Test Condition 181

9.4.3.3.4 DUT Sample Information 181

9.4.3.3.5 Test Results 181

9.4.3.3.6 Measurement Logs 181

9.4.4 RF-SDR board – I2C (PCA9557PW,118) 182

9.4.4.1 Test ID / Test Name: TIV.4.1 / Electrical validation 182

9.4.4.1.1 Purpose 182

9.4.4.1.2 Test and Measurement Method 182

9.4.4.1.3 Test Condition 182

9.4.4.1.4 DUT Sample Information 182

9.4.4.1.5 Test Results 182

9.4.4.1.6 Measurement Logs 182

9.4.4.2 Test ID / Test Name: TIV.4.2 / Signal Integrity 183

9.4.4.2.1 Purpose 183

9.4.4.2.2 Test and Measurement Method 183

9.4.4.2.3 Test Condition 183

9.4.4.2.4 DUT Sample Information 184

9.4.4.2.5 Test Results 184

9.4.4.2.6 Measurement Logs 184

9.4.4.3 Test ID / Test Name: TIV.4.3 / Functional validation 185

9.4.4.3.1 Purpose 185

9.4.4.3.2 Test and Measurement Method 185

9.4.4.3.3 Test Condition 185

9.4.4.3.4 DUT Sample Information 185

9.4.4.3.5 Test Results 185

9.4.4.3.6 Measurement Logs 185

9.4.5 Temp Sensor (SE98ATP, 547) – I2C 186

9.4.5.1 Test ID / Test Name: TIV.5.1 / Electrical validation 186

9.4.5.1.1 Purpose 186

9.4.5.1.2 Test and Measurement Method 186

9.4.5.1.3 Test Condition 186

9.4.5.1.4 DUT Sample Information 186

9.4.5.1.5 Test Results 186

9.4.5.1.6 Measurement Logs 187

9.4.5.2 Test ID / Test Name: TIV.5.2 / Signal Integrity 188

9.4.5.2.1 Purpose 188

9.4.5.2.2 Test and Measurement Method 188

9.4.5.2.3 Test Condition 188

9.4.5.2.4 DUT Sample Information 188

9.4.5.2.5 Test Results 189

9.4.5.2.6 Measurement Logs 189

9.4.5.3 Test ID / Test Name: TIV.5.3 / Functional validation 189

9.4.5.3.1 Purpose 189

9.4.5.3.2 Test and Measurement Method 190

9.4.5.3.3 Test Condition 190

9.4.5.3.4 DUT Sample Information 190

9.4.5.3.5 Test Results 190

9.4.5.3.6 Measurement Logs 190

9.4.6 Sync Board I2C (PCA9557PW,118) 191

9.4.6.1 Test ID / Test Name: TIV.6.1 / Electrical Validation 191

9.4.6.1.1 Purpose 191

9.4.6.1.2 Test and Measurement Method 191

9.4.6.1.3 Test Condition 191

9.4.6.1.4 DUT Sample Information 191

9.4.6.1.5 Test Results 191

9.4.6.1.6 Measurement Logs 191

9.4.6.2 Test ID / Test Name: TIV.6.2 / Signal Integrity 192

9.4.6.2.1 Purpose 192

9.4.6.2.2 Test and Measurement Method 192

9.4.6.2.3 Test Condition 192

9.4.6.2.4 DUT Sample Information 192

9.4.6.2.5 Test Results 193

9.4.6.2.6 Measurement Logs 193

9.4.6.3 Test ID / Test Name: TIV.6.3 / Functional Validation 193

9.4.6.3.1 Purpose 193

9.4.6.3.2 Test and Measurement Method 193

9.4.6.3.3 Test Condition 194

9.4.6.3.4 DUT Sample Information 194

9.4.6.3.5 Test Results 194

9.4.6.3.6 Measurement Logs 194

9.4.7 LED board – I2C (SX1509BIULTRT) 194

9.4.7.1 Test ID / Test Name: TIV.7.1 / Electrical validation 194

9.4.7.1.1 Purpose 194

9.4.7.1.2 Test and Measurement Method 195

9.4.7.1.3 Test Condition 195

9.4.7.1.4 DUT Sample Information 195

9.4.7.1.5 Test Results 195

9.4.7.1.6 Measurement Logs 195

9.4.7.2 Test ID / Test Name: TIV.7.2 / Signal Integrity 196

9.4.7.2.1 Purpose 196

9.4.7.2.2 Test and Measurement Method 196

9.4.7.2.3 Test Condition 196

9.4.7.2.4 DUT Sample Information 196

9.4.7.2.5 Test Results 196

9.4.7.2.6 Measurement Logs 196

9.4.7.3 Test ID / Test Name: TIV.7.3 / Functional validation 197

9.4.7.3.1 Purpose 197

9.4.7.3.2 Test and Measurement Method 197

9.4.7.3.3 Test Condition 197

9.4.7.3.4 DUT Sample Information 197

9.4.7.3.5 Test Results 198

9.4.7.3.6 Measurement Logs 198

9.4.8 TIVA GPIO 198

9.4.8.1 Test ID / Test Name: TIV.10.1 / Control inputs functional validation 198

9.4.8.1.1 Purpose 198

9.4.8.1.2 Test and Measurement Method 198

9.4.8.1.3 Test Condition 198

9.4.8.1.4 DUT Sample Information 199

9.4.8.1.5 Test Results 199

9.4.8.1.6 Measurement Logs 199

9.4.9 TIVA GPIO 199

9.4.9.1 Test ID / Test Name: TIV.11.1 / Control outputs functional validation 199

9.4.9.1.1 Purpose 199

9.4.9.1.2 Test and Measurement Method 199

9.4.9.1.3 Test Condition 199

9.4.9.1.4 DUT Sample Information 200

9.4.9.1.5 Test Results 200

9.4.9.1.6 Measurement Logs 200

9.4.10 ETH SW MGMT Interface 200

9.4.10.1 Test ID / Test Name: TIV.12.1 / Functional validation 200

9.4.10.1.1 Purpose 200

9.4.10.1.2 Test and Measurement Method 200

9.4.10.1.3 Test Condition 201

9.4.10.1.4 DUT Sample Information 201

9.4.10.1.5 Test Results 201

9.4.10.1.6 Measurement Logs 201

9.5 Ethernet: 201

9.5.1 PoE (PD) - MDI 201

9.5.1.1 Test ID / Test Name: ETH.1.1/ Electrical Validation 201

9.5.1.1.1 Purpose 201

9.5.1.1.2 Test and Measurement Method 202

9.5.1.1.3 Test Condition 202

9.5.1.1.4 DUT Sample Information 202

9.5.1.1.5 Test Results 202

9.5.1.1.6 Measurement Logs 202

9.5.1.2 Test ID / Test Name: ETH.1.2/ Functional validation 203

9.5.1.2.1 Purpose 203

9.5.1.2.2 Test and Measurement Method 203

9.5.1.2.3 Test Condition 203

9.5.1.2.4 DUT Sample Information 203

9.5.1.2.5 Test Results 203

9.5.2 TIVA Ethernet 204

9.5.2.1 Test ID / Test Name: ETH.3.1/ Electrical Validation 204

9.5.2.1.1 Purpose 204

9.5.2.1.2 Test and Measurement Method 204

9.5.2.1.3 Test Condition 204

9.5.2.1.4 DUT Sample Information 204

9.5.2.1.5 Test Results 204

9.5.2.1.6 Measurement Logs 205

9.5.2.2 Test ID / Test Name: ETH.3.2/ Functional validation 205

9.5.2.2.1 Purpose 205

9.5.2.2.2 Test and Measurement Method 205

9.5.2.2.3 Test Condition 205

9.5.2.2.4 DUT Sample Information 206

9.5.2.2.5 Test Results 206

9.6 Clocks 206

9.6.1 Clock Sources 206

9.6.1.1 Test ID / Test Name: CLK.1.1 / Frequency Accuracy 206

9.6.1.1.1 Purpose 206

9.6.1.1.2 Test and Measurement Method 206

9.6.1.1.3 Test Condition 207

9.6.1.1.4 DUT Sample Information 207

9.6.1.1.5 Test Results 207

9.6.1.1.6 Measurement Logs 207

9.6.1.2 Test ID / Test Name: CLK.1.2 / Timing Jitter 210

9.6.1.2.1 Purpose 210

9.6.1.2.2 Test and Measurement Method 210

9.6.1.2.3 Test Condition 210

9.6.1.2.4 DUT Sample Information 210

9.6.1.2.5 Test Results 210

9.6.1.2.6 Measurement Logs 210

9.6.2 PCIe - GBE clock 211

9.6.2.1 Test ID / Test Name: CLK.2.1 / Frequency Accuracy 211

9.6.2.1.1 Purpose 211

9.6.2.1.2 Test and Measurement Method 211

9.6.2.1.3 Test Condition 212

9.6.2.1.4 DUT Sample Information 212

9.6.2.1.5 Test Results 212

9.6.2.1.6 Measurement Log 212

9.6.2.2 Test ID / Test Name: CLK.2.2 / Signal Integrity 213

9.6.2.2.1 Purpose 213

9.6.2.2.2 Test and Measurement Method 213

9.6.2.2.3 Test Condition 213

9.6.2.2.4 DUT Sample Information 213

9.6.2.2.5 Test Results 213

9.6.2.2.6 Measurement Log 213

9.6.2.3 Test ID / Test Name: CLK.2.3 / Timing Jitter 214

9.6.2.3.1 Purpose 214

9.6.2.3.2 Test and Measurement Method 214

9.6.2.3.3 Test Condition 214

9.6.2.3.4 DUT Sample Information 214

9.6.2.3.5 Test Results 214

9.6.2.3.6 Measurement Log 214

9.6.3 40 MHz GPSDO Clock 215

9.6.3.1 Test ID / Test Name: CLK.3.1 / Frequency Accuracy 215

9.6.3.1.1 Purpose 215

9.6.3.1.2 Test and Measurement Method 215

9.6.3.1.3 Test Condition 215

9.6.3.1.4 DUT Sample Information 215

9.6.3.1.5 Test Results 215

9.6.3.1.6 Measurement Log 216

9.6.3.2 Test ID / Test Name: CLK.3.2 / Signal Integrity 216

9.6.3.2.1 Purpose 216

9.6.3.2.2 Test and Measurement Method 216

9.6.3.2.3 Test Condition 216

9.6.3.2.4 DUT Sample Information 216

9.6.3.2.5 Test Results 217

9.6.3.2.6 Measurement Log 217

9.6.3.3 Test ID / Test Name: CLK.3.3 / Timing Jitter 217

9.6.3.3.1 Purpose 217

9.6.3.3.2 Test and Measurement Method 217

9.6.3.3.3 Test Condition 218

9.6.3.3.4 DUT Sample Information 218

9.6.3.3.5 Test Results 218

9.6.3.3.6 Measurement Log 218

9.6.4 HDMI clock 219

9.6.4.1 Test ID / Test Name: CLK.4.1 / Frequency Accuracy 219

9.6.4.1.1 Purpose 219

9.6.4.1.2 Test and Measurement Method 219

9.6.4.1.3 Test Condition 219

9.6.4.1.4 DUT Sample Information 219

9.6.4.1.5 Test Results 219

9.6.4.1.6 Measurement Log 219

9.6.4.2 Test ID / Test Name: CLK .4.2 / Signal Integrity 220

9.6.4.2.1 Purpose 220

9.6.4.2.2 Test and Measurement Method 220

9.6.4.2.3 Test Condition 220

9.6.4.2.4 DUT Sample Information 220

9.6.4.2.5 Test Results 220

9.6.4.2.6 Measurement Log 220

9.6.5 GPS 1pps clock 221

9.6.5.1 Test ID / Test Name: CLK.5.1 / Frequency Accuracy 221

9.6.5.1.1 Purpose 221

9.6.5.1.2 Test and Measurement Method 221

9.6.5.1.3 Test Condition 221

9.6.5.1.4 DUT Sample Information 221

9.6.5.1.5 Test Results 221

9.6.5.1.6 Measurement Logs 221

9.5.2.1 Test ID / Test Name: CLK.5.2 / Signal Integrity 222

9.6.5.1.7 Purpose 222

9.6.5.1.8 Test and Measurement Method 222

9.6.5.1.9 Test Condition 222

9.6.5.1.10 DUT Sample Information 222

9.6.5.1.11 Test Results 222

9.6.5.1.12 Measurement Log 222

10. Revision History 224

# Purpose

The purpose of this document is to capture test data for General Purpose Baseband Computing (GBC) module as part of OpenCellular Base Transceiver Station (BTS). The document provides formal report of measured and validated parameters to qualify GBC module as part of design validation testing to ensure consistent and reliable operation across all supported operating and environmental conditions.

# Scope

Scope of this document is to qualify different sections as mentioned below:

1. **Power Source section** which includes, PoE, Solar, Lead Acid battery and Li Ion battery
2. **CPU section** which includes Intel Baytrail SoC, PMIC, DDR, Springville, mSATA
3. **TIVA section** with various sensors
4. **Ethernet section** which covers Compliance testing at 100Mbps speed

# Device-Under-Test (DUT) Details

1. System : OpenCellular Connect -1
2. Sub-system : GBC
3. Hardware version : Life–1 & Life -2
4. Software version :
   * + - 1. Ubuntu – 14.04.64 bit
         2. CoreBoot - 4.4-575-gfee24cc-dirty
         3. RTOS- 2\_16\_00\_08
5. Sample Count : 01
6. DUT Sl. No : WZ1630LIFE2GBC0002, WZ1630LIFE2GBC0005 WZ1630LIFE2GBC0010, WZ1630LIFE2GBC0018 & WZ1630LIFE2GBC0021

# Qualification Test Condition

Ambient Temperature - 25˚C

Operating Voltage - +18V DC

Typical Load – 10.8 – 12.6W

# Qualification Result Summary



# Tools and Test Equipment

|  |  |
| --- | --- |
| Tools and Test Equipment | Model and Version Information |
| Oscilloscope | MSO4034, MSO9404A |
| DC Power Supply | DP832, E3633A, E3634A |
| Electronic Load | KMO64 |
| IR Thermometer | Fluke 59 |
| Multimeter | Fluke 17B+ |
| Solar cell array simulator | Agilent E4350B |
| PoE Injector | PS-201G++ |

# Abbreviation

GBC General Purpose Baseband Computing

PoE Power over Ethernet

PD Powered device

PSE Power Sourcing Equipment

RF-SDR Radio frequency Software-Defined Radio\

BTS Base Transceiver Station

# Qualification Tests Results

# Front Panel:

# Solar Supply

# Test ID / Test Name: FP.1.1 / Voltage accuracy

# Purpose

Solar power input is designed to work in the range of 16 to 22V. The purpose of the test case is to validate the range of solar input voltages for which GBC will be functional.

# Test and Measurement Method

This test is conducted by configuring Solar array simulator E4350B to give a voltage in the range of 16V to 22V by setting it to SAS Mode (Setting Voc, Vmp, Isc and Imp parameters accordingly). Vary the simulator settings for voltages in steps of 2V, measure the input voltage at JTB10A.1, R1304.2, C3M171.1 and C1685.1 and make sure the voltages are in the range of 16V to 22V. Please refer to Section **3.2.1.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 16V – 22V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0005

Software versions – NA

# Test Results

The measured voltages are in range of the set voltages of solar supply output.

# Measurement Logs

**NOTE:** Pass Criteria: Measured Voltage should be equal to input voltage ±5%

|  |  |  |  |  |  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- |
| Input Voltage Accuracy for Solar Supply | | | | | | | | | | | | | |
| Sl. No. | Test case No. | Voc(V) | Vmp(V) | Load current (A) | VPSOLAR (JTB10A.1) | VSLR\_OVUVOUT(R1304.2) | VSLRPOE\_VOUT(C3M171.1) | VPS\_VOUT(C1685.1) | Specification | | Margin (%) | PASS / FAIL |
| Min | Max |
| 1 | FP 1.1 | 16 | 15.6 | 2.25 | 15.54 | 15.53 | 15.5 | 15.49 | 14.82 | 16.38 | -4.52 | PASS |
| 2 | FP 1.1 | 18 | 17.6 | 2 | 17.7 | 17.69 | 17.67 | 17.66 | 16.72 | 18.48 | -4.44 | PASS |
| 3 | FP 1.1 | 20 | 19.6 | 1.8 | 19.84 | 19.83 | 19.81 | 19.8 | 18.62 | 20.58 | -3.79 | PASS |
| 4 | FP 1.1 | 22 | 21.6 | 1.63 | 21.96 | 21.96 | 21.93 | 21.92 | 20.52 | 22.68 | -3.35 | PASS |

**NOTE**: The detailed analysis report is embedded in the xls document attached in the end of this section.

# Test ID / Test Name: FP.1.2 / Input supply range

# Purpose

Solar supply input is designed to work in the range of 16 to 22V. The purpose of the test case is to validate the range of solar voltages for which GBC will be functional.

# Test and Measurement Method

This test is conducted by configuring Solar array simulator E4350B to give a voltage in the range of 16V to 22V by setting it to SAS Mode (Setting Voc, Vmp, Isc and Imp parameters accordingly). Vary the simulator settings for voltages in steps of 2V, measure the input voltage at JTB10A.1, R1304.2, C3M171.1. Make sure the voltages are in the range of 16V to 22V. For every change in input voltage, measure the output voltage of Buck-Boost converter (U88) at R10044.2 and should read 12V. Please refer to Section **3.2.1.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 16V – 22V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0005

Software versions – NA

# Test Results

By varying the solar input, it is ensured that Buck-Boost output is 12Vwhich in-turn ensures proper functionality of GBC module.

# Measurement Logs

|  |  |  |  |  |  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- |
| Input Voltage Range for Solar Supply | | | | | | | | | | | | | |
| Sl. No. | Test case No. | Voc (V) | Vmp(V) | Load current (A) | VPSOLAR (JTB10A.1) | VSLR\_OVUVOUT(R1304.2) | VSLRPOE\_VOUT(C3M171.1) | 12V\_IN (R10044.2) | Specification | | Margin (%) | PASS / FAIL |
| Min | Max |
| 1 | FP 1.2 | 16 | 15.6 | 2.25 | 15.54 | 15.53 | 15.5 | 12.06 | 11.76 | 12.24 | -1.47 | PASS |
| 2 | FP 1.2 | 18 | 17.6 | 2 | 17.7 | 17.69 | 17.67 | 12.06 | 11.76 | 12.24 | -1.47 | PASS |
| 3 | FP 1.2 | 20 | 19.6 | 1.8 | 19.84 | 19.83 | 19.81 | 12.06 | 11.76 | 12.24 | -1.47 | PASS |
| 4 | FP 1.2 | 22 | 21.6 | 1.63 | 21.96 | 21.96 | 21.93 | 12.06 | 11.76 | 12.24 | -1.47 | PASS |

**NOTE:**

1. Pass Criteria for input voltage range: Measured Voltage should be equal to input voltage ±5%
2. Pass Criteria for Buck-Boost converter: Measured Voltage should be 12V±2%

**The detailed analysis report for solar test cases executed is embedded in the xls document attached herewith.**



# AUX Supply

# Test ID / Test Name: FP.2.1 / Voltage accuracy

# Purpose

AUX power input is designed to work in the range of 16 to 24V. The purpose of the test case is to validate the range of AUX input voltages for which GBC will be functional.

# Test and Measurement Method

This test is conducted by configuring AUX supply to give a voltage in the range of 16V to 24V. Vary the simulator settings for voltages in steps of 2V, measure the input voltage at JTB10A.1, R1304.2, C3M171.1, and C1685.1 and make sure the voltages are in the range of 16V to 24V Please refer to Section **3.2.2.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 16V – 24V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0005

Software versions – NA

# Test Results

The measured voltages are in range of the set voltages of AUX supply output.

# Measurement Logs

|  |  |  |  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- |
| Input Voltage Accuracy for AUX Supply | | | | | | | | | | | |
| Sl. No. | Test case No. | Input Voltage (V) | VPSOLAR (JTB10A.1) | VSLR\_OVUVOUT(R1304.2) | VSLRPOE\_VOUT(C3M171.1) | VPS\_VOUT(C1685.1) | Specification | | Margin (%) | PASS / FAIL |
| Min | Max |
| 1 | FP 2.1 | 16 | 16.04 | 16.04 | 16.02 | 16.01 | 15.2 | 16.8 | -4.70 | PASS |
| 2 | FP 2.1 | 18 | 18.03 | 18.03 | 18 | 18 | 17.1 | 18.9 | -4.76 | PASS |
| 3 | FP 2.1 | 20 | 20.02 | 20.02 | 20 | 20 | 19 | 21 | -4.76 | PASS |
| 4 | FP 2.1 | 22 | 22.02 | 22.02 | 21.99 | 21.99 | 20.9 | 23.1 | -4.81 | PASS |
| 5 | FP 2.1 | 24 | 24.01 | 24.01 | 23.99 | 23.99 | 22.8 | 25.2 | -4.80 | PASS |

**NOTE**:

1. Pass Criteria: Measured Voltage should be equal to input voltage ±5%
2. The detailed analysis report is embedded in the xls document attached in the end of this section.

# Test ID / Test Name: FP.2.2 / Input supply range

# Purpose

AUX supply input is designed to work in the range of 16 to 24V. The purpose of the test case is to validate the range of AUX voltages for which GBC will be functional.

# Test and Measurement Method

This test is conducted by AUX power supply to give a voltage in the range of 16V to 24V. Varying the AUX supply settings for voltages in steps of 2V, measure the input voltage at JTB10A.1, R1304.2, and C3M171.1 and make sure the voltages are in the range of 16V to 24V. For every change in input voltage, measure the output voltage of Buck-Boost converter (U88) at R10044.2 and should read 12V. Please refer to Section **3.2.2.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 16V – 24V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0005

Software versions – NA

# Test Results

By varying the AUX input, it is ensured that Buck-Boost output is 12V which in-turn ensures proper functionality of GBC module.

# Measurement Logs

|  |  |  |  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- |
| Input Voltage Range for AUX Supply | | | | | | | | | | | |
| Sl. No. | Test case No. | Input Voltage(V) | VPSOLAR (JTB10A.1) | VSLR\_OVUVOUT(R1304.2) | VSLRPOE\_VOUT(C3M171.1) | 12V\_IN (R10044.2) | Specification | | Margin (%) | PASS / FAIL |
| Min | Max |
| 1 | FP 2.2 | 16 | 16.04 | 16.04 | 16.02 | 12.08 | 11.76 | 12.12 | -0.33 | PASS |
| 2 | FP 2.2 | 18 | 18.03 | 18.03 | 18 | 12.08 | 11.76 | 12.12 | -0.33 | PASS |
| 3 | FP 2.2 | 20 | 20.02 | 20.02 | 20 | 12.08 | 11.76 | 12.12 | -0.33 | PASS |
| 4 | FP 2.2 | 22 | 22.02 | 22.02 | 21.99 | 12.08 | 11.76 | 12.12 | -0.33 | PASS |
| 5 | FP 2.2 | 24 | 24.01 | 24.01 | 23.99 | 12.08 | 11.76 | 12.12 | -0.33 | PASS |

**NOTE:** Pass Criteria for Buck-Boost converter: Measured Voltage should be 12V±2%

**The detailed analysis report with for PoE test cases executed is embedded in the xls document attached herewith.**



# PoE In

# Test ID / Test Name: FP.3.1 / Voltage Accuracy

# Purpose

The purpose of this test case is to check the voltage accuracy of input side voltage rails when GBC is powered through PoE.

# Test and Measurement Method

This test is conducted by isolating input side of Tiva and Intel microprocessor, by removing R10054 and R10067 respectively. A constant input voltage of 56V is given from PoE injector (PS-201G++) to J1A connector. Measure the output voltages at C3M103.1, C3M171.1, C1685.1 and C3M96.1. Please refer to Section **3.2.3.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature - 25˚C

Operating Voltage - +56V DC

System load –Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0005

Software versions – NA

# Test Results

The input voltage accuracy of GBC when powered through PoE is within the system input voltage range as per design (10.8V to 28V).

# Measurement Logs

|  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **PoE In - Voltage Accuracy** | | | | | | | | |
| Sl. No. | Test case No. | Voltage Rail | Measuring Points | Measured Voltage(V) | Specification | | Design Margin (%) | PASS / FAIL |
| Min(V) | Max(V) |
| 1 | FP 3.1 | PV18POE | C3M103.1 | 18.62 | 10.8 | 28 | -33.50 | PASS |
| 2 | FP 3.1 | VSLRPOE\_VOUT | C3M171.1 | 18.6 | 10.8 | 28 | -33.57 | PASS |
| 3 | FP 3.1 | VPS\_VOUT | C1685.1 | 18.58 | 10.8 | 28 | -33.64 | PASS |
| 4 | FP 3.1 | VPOUT\_BUCK | C3M96.1 | 18.53 | 10.8 | 28 | -33.82 | PASS |

**NOTE:** The detailed analysis report is embedded in the xls document attached in the end of this section.

# Test ID / Test Name: FP.3.2 / Input Voltage Range

# Purpose

PoE input supply range must comply with LTPoE++ standard, i.e. it is designed to work in the range of 53.75V to 56V. The purpose of the test case is to validate the range for LTPoE++ voltage range for which GBC will be functional.

# Test and Measurement Method

This test is conducted by varying PoE injector input voltage from 53.75V to 56V. Varying the injector supply for voltages in steps of 1V, measure the input voltage at C2005.1. Load GBC up to 30W using an external electronic load. For every change in input voltage, measure the output voltage of 48V to 18V isolated converter (U38) at C3M171.1 and should read 18V. Please refer to Section **3.2.3.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 53.75V to 56V

System load – Typical + External electronic load on 12V rail.

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0005

Software versions – NA

# Test Results

By varying PoE input voltage; it is ensured that output of 48V to 18V isolated converter (U38) is 18V which in-turn ensures proper functionality of GBC module.

# Measurement Logs

|  |  |  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **PoE In - Input supply range** | | | | | | | | | | |
| Sl. No. | Test case No. | PoE input voltage(V) | VSLPOE\_VOUT (at C3M171) (V) | Load current on 12 V rail(A) | Total system current (A) | Total board power consumption (W) | Specification | | Design Margin (%) | PASS / FAIL |
| Min(V) | Max(V) |
| 1 | FP 3.2 | 53.75 | 18.57 | 1.82 | 0.605 | 32.52 | 17.1 | 18.9 | -1.75 | PASS |
| 2 | FP 3.2 | 55 | 18.58 | 1.82 | 0.597 | 32.84 | 17.1 | 18.9 | -1.69 | PASS |
| 3 | FP 3.2 | 55.5 | 18.57 | 1.82 | 0.59 | 32.75 | 17.1 | 18.9 | -1.75 | PASS |
| 4 | FP 3.2 | 56 | 18.57 | 1.82 | 0.587 | 32.87 | 17.1 | 18.9 | -1.75 | PASS |

**NOTE:** Pass Criteria for input voltage range: Measured Voltage should be equal to output voltage ±5%.

**The detailed analysis report for PoE test cases executed is embedded in the xls document attached herewith.**



# PoE – Data

# Test ID / Test Name: FP.5.1 / Ethernet Compliance

# Purpose

The purpose of this test case is to perform Ethernet Physical Layer Compliance Testing for 100BASE-TX MDI signal.

# Test and Measurement Method

This test is conducted by generating PRBS test pattern from Marvell switch using MDC and MDIO registers and probing signals at both PD port [J1A.1 and J1A.2 (TX pair); J1A.3 and J1A.6 (RX pair)] and PSE port [J1A.13 and J1A.14 (TX pair); J1A.15 and J1A.18 (RX pair)] and perform compliance as per IEEE 802.3 standard which cover these test cases, viz. Template Test, Differential Output Voltage Test, Signal Amplitude Symmetry Test, Rise and Fall Time Test, Waveform Overshoot Test, Jitter Test, Duty Cycle Distortion Test, Return Loss Test, common Mode Rejection. The test procedure and test setup has been performed as per document embed herewith.



Please refer to Section **3.2.4** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature - 25˚C

Operating Voltage - +18V DC

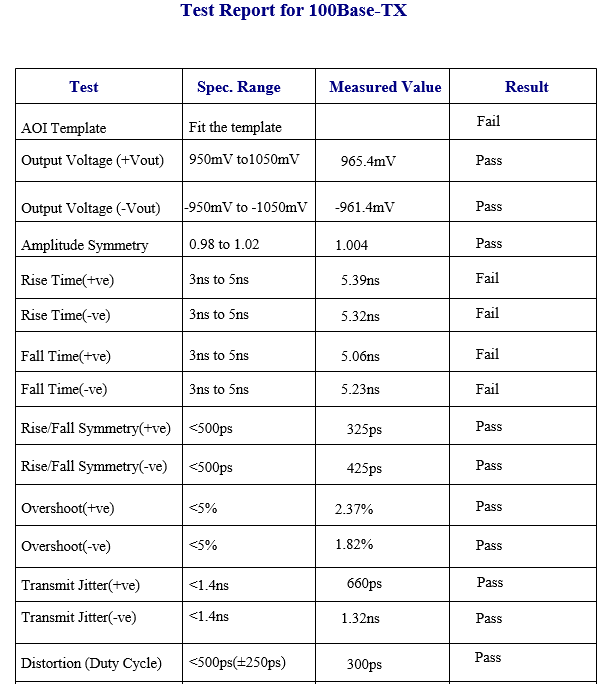
System load – Typical

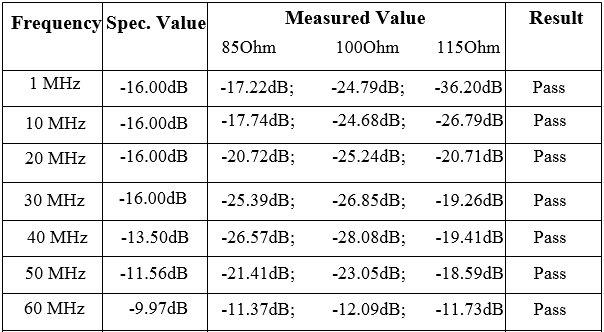
# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0002

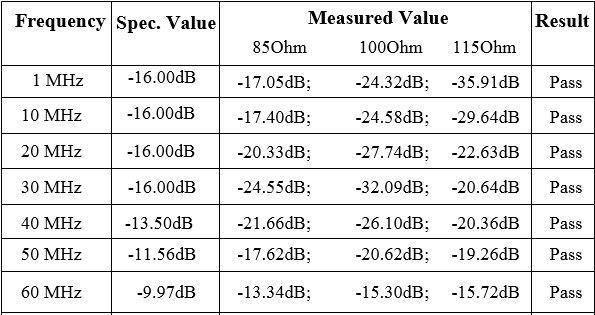
Software versions – NA

# Test Results



**Transmitter Return Loss**:****

**Receiver Return Loss**:

****

**NOTE:**

Rise, fall time and AOI template failure are attributed to physical layout of the Ethernet channel on Rev-B design. Channel implementation has been updated in Rev C design, which includes optimized center tap routing and channel length. These optimizations are expected to address the failures and will be validated as part of Rev C product qualification.

# Protection

# Test ID / Test Name: FP.6.1 / Output Voltage Accuracy

[Covered in FP.2.1](#_Test_ID_/_1)

# Test ID / Test Name: FP.6.2 / Solar AUX Present Test

# Purpose

The purpose of this test case is to check the presence of Solar or AUX supply.

# Test and Measurement Method

This test is conducted by isolating input side of Tiva and Intel microprocessor by removing R10054 and R10067 respectively. Connect an AUX supply to the input of GBC. Measure the voltage at R9957.2. When AUX or solar supply is present, the voltage on this resistor should measure <0.4V. Please refer to Section **3.2.5.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature - 25˚C

Operating Voltage - +18V DC

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0005

Software versions – NA

# Test Results

Measuring the voltage at R9957.2 to be < 0.4V, indicates that Solar/ AUX supply is present as the input source to GBC.

# Measurement Logs

|  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- |
| Sl. No. | Test case No. | Voltage Rail | Measuring Points | Measured Voltage | Specification | | Margin (%) | PASS / FAIL |
| Min(V) | Max(V) |
| 1 | FP 6.2 | VSLRPOE\_VOUT | R988.1 | 17.98 | 17.82 | 18.18 | -0.90 | PASS |
| 2 | FP 6.2 | SOLAR\_AUX\_PRSNT\_N | R9957.2 | 0.185 | 0 | 0.4 | -53.75 | PASS |
| 3 | FP 6.2 | VPS\_VOUT | R1056.1 | 17.98 | 17.82 | 18.18 | -0.90 | PASS |

**NOTE:**

1. Pass Criteria for Solar\_AUX\_Present: Measured Voltage at R9957.2 should be < 0.4V (designed value is for <0.4V)
2. The detailed analysis report is embedded in the xls document attached in the end of this section.

# Test ID / Test Name: FP.6.3 / Protection Limit

# Purpose

The purpose of this test case is to ensure the voltage protection limits are as per the designed value, i.e. input voltage to U91 (LT4256) is ≥11.5V.

# Test and Measurement Method

This test is conducted by isolating input side of Tiva and Intel microprocessor, by removing R10054 and R10067 respectively. Connect an AUX supply to the input of GBC. Vary the input voltage from 10.5V to 11.5V in steps of 0.2V. Measure the voltages at C3M171.1, R1053.2, R1056.1 and R10044.2. Input voltage for U91 should be greater than 11.5V for its proper operation. This test fails if input voltage of U91 (VSLRPOE\_VOUT) is less than 11.5V, or if the nodal voltage at R1053 and R1052 junction is greater than 3.96V. Please refer to Section **3.2.5.4** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature - 25˚C

Operating Voltage - +10.5V DC to +11.5V DC

System load –Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0005

Software versions – NA

# Test Results

Measuring the voltage at R1053.2 < 3.96V and input voltage to U91 greater than 11.5V indicates that U91 protects GBC at under voltages.

# Measurement Logs

|  |  |  |  |  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- |
| Sl. No. | Test case No. | Voltage Rail | | | | | | | | | | PASS / FAIL |
| VSLRPOE\_VOUT @ C3M171.2 | Node voltage at UV pin of U91 @ R1053.2 | VPS\_VOUT @ R1056.2 | Specification | | Design Margin (%) | 12V\_IN @ R10044.3 | Specification | | Design Margin (%) |
| Min (V) | Max (V) | Min (V) | Max (V) |
| 1 | FP 6.3 | 10.5 | 3.672 | 0 | 0 | 0 | 0.00 | 0 | 0 | 0 | 0.00 | PASS |
| 2 | FP 6.3 | 10.8 | 3.776 | 0 | 0 | 0 | 0.00 | 0 | 0 | 0 | 0.00 | PASS |
| 3 | FP 6.3 | 11 | 3.846 | 0 | 0 | 0 | 0.00 | 0 | 0 | 0 | 0.00 | PASS |
| 4 | FP 6.3 | 11.2 | 3.917 | 0 | 0 | 0 | 0.00 | 0 | 0 | 0 | 0.00 | PASS |
| 5 | FP 6.3 | 11.5 | 4.021 | 11.52 | 11.27 | 11.73 | -1.79 | 12.08 | 11.76 | 12.24 | -1.31 | PASS |

**NOTE:**

Pass Criteria for Protection Circuit:

1. Voltage measured at VSLRPOE\_VOUT should be ≥11.5V (11.5V is the designed value). This implies that the node voltage at R1053.2 should be >3.96V.
2. When the above two criteria are met, voltage at VPS\_VOUT should be equal to VSLRPOE\_VOUT and 12V\_IN should be equal to ±5% of 12V (i.e. between 11.4V and 12.6V)

**The detailed analysis report for PoE test cases executed is embedded in the xls document attached herewith.**



# Power:

# PoE

# Test ID / Test Name: PWR.1.1 / Voltage Accuracy

[Same as test case FP.3.1](#_Test_ID_/_3)

# Test ID / Test Name: PWR.1.2 / Ripple Measurement

# Purpose

The purpose of this test case is to check the maximum peak-to-peak ripple voltage of PoE supply.

# Test and Measurement Method

This test is conducted by isolating input side of Tiva and Intel microprocessor, by removing R10054 and R10067 respectively. A constant input voltage of 56V is given from PoE injector (PS-201G++) to J1A connector. An Isolated DC-DC converter in turn converts 56V to 18V. To measure the ripple voltage, operate the oscilloscope in AC coupling mode and measure the ripple voltage across C3M103.1. Please refer to Section **4.2.1.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure

# Test Condition

Ambient Temperature - 25˚C

Operating Voltage – PoE injector supply

System load – Idle/Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0018

Software versions – NA

# Test Results

The ripple voltage accuracy is within 5% of expected ripple voltage.

# Measurement Logs

|  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **PoE In - Ripple Measurement** | | | | | | | | |
| Sl. No. | Test case No. | Voltage Rail | Measuring Point | Ripple Voltage(mV) | Specification | | Margin (%) | PASS / FAIL |
| Min(mV) | Max(mV) |
| 1 | PWR1.2 | PV18POE | C3M103.1 | 13.2 | 0 | 900 | -98.53 | PASS |

**NOTE:**

1. Supporting waveform capture is provided at end of test case id [PWR 1.3](#_Measurement_Logs_1)
2. The detailed analysis report is embedded in the xls document attached in the end of this section.

# Test ID / Test Name: PWR.1.3 /PoE Present Check

# Purpose

The purpose of this test case is to check the presence of PoE as an input supply source.

# Test and Measurement Method

This test is conducted by isolating input side of Tiva and Intel microprocessor, by removing R10054 and R10067 respectively. A constant input voltage of 56V is given from PoE injector (PS-201G++) to J1A connector. A DC-DC in turn converts 56V to 18V. When PoE supply is present, the voltage on R9953.2 resistor should measure <1.155V. Any voltage less than 1.155V is considered as low signal for Tiva thus indicating the presence of PoE supply. Please refer to Section **4.2.1.4** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature - 25˚C

Operating Voltage - +18V DC

System load – Idle/Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0018

Software versions – NA

# Test Results

The voltage at R9953.2 was measured to be 0.192V.

# Measurement Logs

|  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **PoE In - Supply Present Check** | | | | | | | | |
| Sl. No. | Test case No. | Voltage Rail | Measuring Point | Measured Voltage(V) | Specification | | Margin (%) | PASS / FAIL |
| Min(mV) | Max(mV) |
| 1 | PWR1.3 | POE\_PRSNT\_N | R9953.2 | 0.192 | 0 | 1.155 | -83.38 | PASS |

**The detailed analysis report with waveform captured for PoE test cases executed is embedded in the xls document attached herewith.**



# Test ID / Test Name: PWR.1.4 / Data transfer validation

# Purpose

This test case indicates the data validation between PoE ports A and B.

# Test and Measurement Method

Connect Data In port of PoE injector to CPU1. Connect Port B of GBC to another machine (CPU2). Ping CPU2 from CPU1 and vice versa. Please refer to Section **4.2.1.5** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – AUX supply: + PoE injector supply

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0005

Software versions – NA

# Test Results

The number of packets transferred from CPU1 to CPU2 and vice versa should have a loss of 0%, then data validation through PoE is successful.

# Measurement Logs

# Test ID / Test Name: PWR.1.5 / Power delivery

# Purpose

The purpose of the test case is to validate the power delivery of PoE.

# Test and Measurement Method

This test is conducted by measuring the voltage at the sense resistor R10044 and calculating the current and power for the output section. PoE Voltage and Current are measured by connecting the injector to DC power supply and measuring the voltage at the input point of injector. The efficiency is calculated as η = 100% \* Pout / Pin. Please refer to Section **4.2.1.6** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – PoE injector supply

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0002

Software versions – NA

# Test Results

The efficiency is calculated to be 61.64%.

# Measurement Logs

|  |  |  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **PoE Power Delivery** | | | | | | | | | | |
| Section | Probing points | Resistor Value (mΩ) | Voltage (V) | Measured Voltage across sense resistor (mV) | Current (A) | Power (W) | Calculated Efficiency (%) | Specification (%) | | Design Margin (%) |
| Min | Max |
| Input Section | NA | NA | 47.97 | NA | 0.487 | 23.36139 | 61.64 | 60 | 70 | -2.73361 |
| Output Section | R10044 | 10 | 12 | 12 | 1.2 | 14.4 |
| **NOTE:** PoE Voltage and Current measured by connecting the injector to DC power supply and measuring the voltage at the output point of injector. | | | | | | | | | | |

**NOTE:** This test case was carried out for typical load condition. Full load condition will be tested in next version.

**The detailed analysis report for power delivery of PoE is embedded in the xls document attached herewith**.

****

# Isolated DC-DC Converter

# Test ID / Test Name: PWR.3.1 / Output Voltage Accuracy

# Purpose

The purpose of this test case is to check the voltage accuracy of output voltage rail of DC – DC converter when PoE input voltage is varied.

# Test and Measurement Method

A varying input PoE voltage from 40V to 48V is varied in steps and fed to J1A connector. Measure the input voltage at J1.A C2005.1 and output voltage of DC-DC converter at C1807.1. Please refer to Section **4.2.2.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature - 25˚C

Operating Voltage - +40V to +48V DC

System load –Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0005

Software versions – NA

# Test Results

The output voltage accuracy of DC-DC converter when powered through varying PoE input voltage is within 5% of expected voltage.

# Measurement Logs

|  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **Isolated DC-DC Converter -Output Voltage Accuracy** | | | | | | | | |
| Sl. No. | Test case No. | PoE Input Voltage (V) | VPORTA\_P(V) | PV18POE | Specification | | Margin (%) | PASS/ FAIL |
| Min(V) | Max(V) |
| 1 | PWR 3.1 | 44.2 | 44.2 | 18.58 | 17.1 | 18.9 | -1.69 | PASS |
| 2 | PWR 3.1 | 40.4 | 40.22 | 18.63 | 17.1 | 18.9 | -1.43 | PASS |
| 3 | PWR 3.1 | 47.4 | 47.2 | 18.57 | 17.1 | 18.9 | -1.75 | PASS |

**NOTE**: The detailed analysis report is embedded in the xls document attached in the end of this section.

# Test ID / Test Name: PWR.3.2 / Solar AUX and PoE Or'ring circuit

# Purpose

The purpose of this test case is to check the switching between AUX/ Solar supply and PoE supply.

# Test and Measurement Method

This test is conducted by isolating input side of Tiva and Intel microprocessor, by removing R10054 and R10067 respectively. A constant input voltage of 56V is given from PoE injector (PS-201G++) to J1A connector. A DC-DC in turn converts 56V to 18V. AUX/ Solar input supply is also given to JTB10A.1. Measure the output voltage at C3M171.1. As per design, output voltage should follow AUX/ Solar supply if AUX supply is greater than 16.3V; else output voltage will follow PoE. Please refer to Section **4.2.2.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature - 25˚C

Operating Voltage - +18V DC from PoE; AUX voltage range +15V DC to +24V DC

System load – Idle/Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0018

Software versions – NA

# Test Results

From AUX or solar input voltage equal to 16.27V, the output voltage follows the input.

# Measurement Logs

|  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **Isolated DC-DC Converter - Solar AUX and PoE OR'ing Circuit** | | | | | | | | |
| Sl. No. | Test case No. | Voltage Rail VSLR\_OVUVOUT(V) | Voltage Rail PV18POE(V) | Measured Voltage(V) | Specification | | Margin (%) | PASS/ FAIL |
| Min(V) | Max(V) |
| 1 | PWR 3.2 | 15 | 18.65 | 18.61 | 17.7175 | 19.5405 | -4.76 | PASS |
| 2 | PWR 3.2 | 15.7 | 18.65 | 18.61 | 17.7175 | 19.5405 | -4.76 | PASS |
| 3 | PWR 3.2 | 16.06 | 18.65 | 18.58 | 17.7175 | 19.509 | -4.76 | PASS |
| 4 | PWR 3.2 | 16.27 | 18.65 | 16.25 | 15.4565 | 17.0835 | -4.88 | PASS |
| 5 | PWR 3.2 | 17 | 18.65 | 16.97 | 16.15 | 17.85 | -4.93 | PASS |
| 6 | PWR 3.2 | 18 | 18.65 | 17.95 | 17.1 | 18.9 | -4.97 | PASS |
| 7 | PWR 3.2 | 24 | 18.65 | 23.91 | 22.8 | 25.2 | -4.87 | PASS |
| **NOTE:** When VSLR\_OVUVOUT is between 16.12V and 16.17V; then voltage source selection is based on the first available source. | | | | | | | | |
|

**The detailed analysis report for PoE test cases executed is embedded in the xls document attached herewith.**

****

# Lead Acid battery

# Test ID / Test Name: PWR.4.1 / Output Voltage Accuracy

# Purpose

The purpose of this test case is to check the output voltage accuracy of battery charger U82 (LTC4015).

# Test and Measurement Method

This test is conducted by isolating input side of Tiva and Intel microprocessor, by removing R10054 and R10067 respectively. Measure the voltages at C1685.1, JTB10B.3, C1741.1, and C1686.1. Please refer to Section **4.2.3.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature - 25˚C

Operating Voltage - Lead Acid battery voltage – 9.5V to 13.8V (12V nominal voltage)

System load – Idle/Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0018

Software versions – NA

# Test Results

Measured battery voltage at various input points are within the limits.

# Measurement Logs

|  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **Lead Acid Battery - Voltage Accuracy** | | | | | | | | |
| Sl. No. | Test case No. | Voltage Rail | Measuring Point | Measured Voltage(V) | Specification | | Margin (%) | PASS / FAIL |
| Min(V) | Max(V) |
| 1 | PWR 4.1 | VPS\_VOUT | C1685.1 | 0 | 0 | 0 | 0 | PASS |
| 2 | PWR 4.1 | LACID\_VBAT\_P | JTB10B.3 | 12.77 | 10.5 | 13.5 | -5.41 | PASS |
| 3 | PWR 4.1 | LT4231\_BAT\_CHRGR\_LACID | C1741.1 | 12.75 | 12.610375 | 12.929625 | -1.11 | PASS |
| 4 | PWR 4.1 | VBC\_LACID | C1686.1 | 12.73 | 12.590625 | 12.909375 | -1.11 | PASS |

**NOTE**: The detailed analysis report is embedded in the xls document attached in the end of the test case PWR.4.7.

# Test ID / Test Name: PWR.4.2 / Charge current measurement

# Purpose

Charge current for lead acid battery is designed for 10.6A.

i.e.

Charge current read from register Ibat having sub-address 0x3D, must be equal to the programmed charge current (10.66A).

**NOTE:** Charge current will decrease when charging voltage increases.

# Test and Measurement Method

Connect lead acid battery terminals between to JTB10B.3and JTB10B.4 Connect a debug board to GBC board in order to access TIVA through CCS. Through I2C channel 0, lead acid battery charger U82 can be accessed. Program the charge current as 10.66A by writing into Icharge \_target register at address 0x1A. Read register Ibat having sub-address 0x3D. This value gives the charging current of the lead acid battery. Repeat the same procedure for different values such as 2A, 4A, 6A and 8A as charge current for verification. Please refer to Section **4.2.3.4** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature - 25˚C

Operating Voltage - +Lead Acid Battery Voltage (12V nominal, 9.5V to 13.8V)

System load –Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0014

Software versions – NA

# Test Results

The register read value must be equal to the current measured across resistor R9959.

**The detailed analysis report for lead acid battery charge current test case executed is embedded in the xls document attached herewith.**



**NOTE:** PASS Criteria: IBAT value read from register 0x3D and current measured across R9959 should be equal.

# Test ID / Test Name: PWR.4.3 / Load current measurement

# Purpose

The purpose of this test case is to measure the current drawn from the battery when system is powered ON by lead acid battery.

# Test and Measurement Method

This test is conducted by isolating input side of Intel microprocessor, by removing R10067. Connect the lead acid battery at JTB10B.3.

Connect a debug board to GBC board in order to access TIVA through CCS. Through I2C channel 0, lead acid battery charger U82 can be accessed. Read register IIN having sub-address 0x3E. This value gives the load current of GBC board.

Measure the voltage drop across R9959 (battery sense resistor).

Load current is given by. Please refer to Section **4.2.3.5** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature - 25˚C (Lab temperature was maintained at 25˚C during testing)

Operating Voltage – Lead Acid battery voltage

System load – Idle/Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0018

Software versions – NA

# Test Results

The register read value must be equal to the current measured across resistor R9960.

# Measurement Logs

**The detailed analysis report for lead acid battery Load current test case executed is embedded in the xls document attached herewith.**



**NOTE:** PASS criteria: IIN value read from register 0x3E and current measured across R9960 should be equal.

# Test ID / Test Name: PWR.4.4 / LDO Output voltage

# Purpose

The purpose of this test case is to measure the battery charger (U82) internal INTVCC LDO voltage.

# Test and Measurement Method

This test is conducted by isolating input side of Tiva and Intel microprocessor, by removing R10054 and R10067 respectively. Connect the lead acid battery at JTB10B.3. Measure the battery charger internal LDO voltage at C1767.1. Please refer to Section **4.2.3.6** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature - 25˚C

Operating Voltage – Lead Acid battery voltage

System load – Idle/Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0018

Software versions – NA

# Test Results

Internal LDO voltage is measured and is within the expected limit (i.e. between 4.3V and 5.5V).

# Measurement Logs

|  |  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **Lead Acid Battery - LDO Output Voltage** | | | | | | | | | |
| Sl. No. | Test case No. | Voltage Rail | Measuring Point | Measured Voltage(V) | Expected Voltage(V) | Specification | | Margin (%) | PASS/FAIL | |
| Min(V) | Max(V) |
| 1 | PWR 4.4 | INT\_VCC\_LACID | C1767.1 | 4.87 | 5 | 4.3 | 5.5 | -9.09 | PASS | |

**NOTE**: The detailed analysis report is embedded in the xls document attached in the end of this section.

# Test ID / Test Name: PWR.4.5 / Temperature Measurement

# Purpose

The purpose of this test case is to measure the temperature of battery charger IC U82 Microcontroller when it’s fully operational.

# Test and Measurement Method

Connect lead acid battery. Connect a debug board to GBC board in order to access TIVA through CCS. Through I2C channel 0, lead acid battery charger, U82 can be accessed. Read register DIE\_TEMPERATURE having sub-address 0x3F. Please refer to Section **4.2.3.7** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature - 23˚C

Operating Voltage – Lead Acid battery voltage

System load – Idle/Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0018

Software versions – NA TIVA RTOS VER.33 lead acid battery charger configuration code

# Test Results

The measured value is well within operating temperature of U82 i.e. -40C to +125C

# Measurement Logs

|  |  |  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **Sl. No** | **Register** | **Register Address** | **Hex Value** | **Decimal Value** | **Parameter** | **Value** | **Specification** | | **Margin (%)** | **PASS / FAIL** |
| **Min**  **(deg C)** | **Max (deg C)** |
| 1 | DIE\_TEMP | 0x3F | 3568 | 13672 | LTC4015 temperature (deg C) | 36.447 | -40 | 125 | 191.12 | PASS |

**The detailed analysis report with waveform captured for lead acid battery die temperature test case executed is embedded in the xls document attached herewith.**

****

# Test ID / Test Name: PWR.4.6 / Charge control

# Purpose

This test case indicates the programmed charge current for lead acid battery.

# Test and Measurement Method

Connect lead acid battery at connector JTB10B. Connect a debug board to GBC board in order to access TIVA through CCS. Through I2C channel 0, lead acid battery charger U82 can be accessed. Write the desired charge current to register 0x1A, *ICHARGE\_TARGET.* Read the register 0x3D (*Ibat*) to measure the charge current. Please refer to Section **4.2.3.8** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – Lead Acid battery and AUX supply: +18V DC

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0005

Software versions – TIVA RTOS VER.33 lead acid battery charger configuration code

# Test Results

The read value from register 0x3D and 0x1A should be the same.

# Measurement Logs



**NOTE:** PASS criteria: Programmed value of register 0x1A should be equal to the read value from register 0x3D.

# Test ID / Test Name: PWR.4.7 / Lead Acid and LiON battery or ‘ring circuit

# Purpose

The purpose of this test case is to check OR’ing between lead acid battery and lithium ion battery when solar or AUX power supply is absent. Measure the current drawn from the battery when system is powered ON by lithium ion battery.

# Test and Measurement Method

Connect both lead acid battery and lithium ion battery. If lead acid battery measures >10.35V. lead acid battery will be selected as the power supply source. Please refer to Section **4.2.3.9** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature - 25˚C

Operating Voltage – Lithium ion battery voltage or lead acid battery

System load – Idle/Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0005

Software versions – NA

# Test Results

When lead acid battery voltage is greater than 10.35V, the power source for GBC will be lead acid and is verified by this test.

# Measurement Logs

|  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **Lead Acid and Lithium Ion Battery - OR’ing Circuit** | | | | | | | | |
| **Sl. No** | **Test Case ID** | **VBC\_ LION (V)**  **@C3M98.1** | **VBC\_ LACID (V)**  **@C3M97.1** | **VPOUT\_BUCK (V) @ C3M96.1** | **Specification** | | **Margin (%)** | **PASS / FAIL** |
| **Min** | **Max** |
| 1 | PWR.4.7 | 12.37 | 11.17 | 11.12 | 10.35 | 13.5 | -7.44 | PASS |

**NOTE:** VPOUT\_BUCK = VBC\_LACID only if voltage of lead acid battery voltage is >10.35

**The detailed analysis report for lead acid battery charger test cases executed is embedded in the xls document attached herewith.**

# Test ID / Test Name: PWR.4.8 / Power delivery

# Purpose

The purpose of the test case is to validate the power delivery of Lead Acid battery.

# Test and Measurement Method

This test is conducted by measuring the voltage at the sense resistors R9959 and R10044 and calculating the current and power. The efficiency is calculated as η = 100% \* Pout / Pin. Please refer to Section **4.2.3.10** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0002

Software versions – NA

# Test Results

The efficiency is calculated to be 69.39%.

# Measurement Logs

|  |  |  |  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **Lead Acid Power Delivery** | | | | | | | | | | | |
| Section | Probing points | Resistor Value (mΩ) | Voltage (V) | Measured Voltage across sense resistor (mV) | Current (A) | Power (W) | Calculated Efficiency (%) | Specification (%) | | Design Margin (%) |
| Min | Max |
| Input Section | R9959 | 5 | 11.89 | 0.8 | 0.16 | 1.9024 | 69.39 | 60 | 70 | -0.87709 |
| Output Section | R10044 | 10 | 12 | 1.1 | 0.11 | 1.32 |

**NOTE:** This test case was carried out for typical load condition. Full load condition will be tested in next version.

**The detailed analysis report for power delivery of Lead Acid battery is embedded in the xls document attached herewith**.



# Lithium Ion Battery

# Test ID / Test Name: PWR.5.1 / Output Voltage Accuracy

# Purpose

The purpose of this test case is to check the output voltage accuracy of battery charger U85 (LTC4015).

# Test and Measurement Method

This test is conducted by isolating input side of Tiva and Intel microprocessor, by removing R10054 and R10067 respectively. Measure the voltages at C1718.1, JTB8.1, C1715.1, and C1718.1. Please refer to Section **4.2.4.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature - 25˚C

Operating Voltage - AUX voltage range +16V DC to +24V DC and lithium ion battery (9V to 12.6V)

System load – Idle/Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0005

Software versions – NA

# Test Results

Measured battery voltage at various input points are within the specified limits.

# Measurement Logs

|  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **Lithium Ion Battery – Output Voltage Accuracy** | | | | | | | | |
| Sl. No. | Test case No. | Voltage Rail | Measuring Point | Measured Voltage(V) | Specification | | Margin (%) | PASS / FAIL |
| Min(V) | Max(V) |
| 1 | PWR 5.1 | VPS\_VOUT | C1718.1 | 0 | 0 | 0 | 0 | PASS |
| 2 | PWR 5.1 | LION\_VBAT\_P | JTB8.1 | 11.67 | 11.1 | 12.6 | -5.14 | PASS |
| 3 | PWR 5.1 | VBC\_LION | C1715.1 | 11.68 | 11.1 | 12.6 | -5.23 | PASS |

**NOTE**: The detailed analysis report with waveform captured is embedded in the xls document attached in the end of the test case PWR 5.5.

# Test ID / Test Name: PWR.5.2 / Charge Current Measurement

# Purpose

Charge current for lithium ion battery is designed for 1.45A.

i.e.

Charge current read from register Ibat having sub-address 0x3D, must be equal to the programmed charge current (1.45A).

**NOTE:** Charge current will decrease when charging voltage increases.

# Test and Measurement Method

Connect lithium ion battery terminals between to JTB8.1 and JTB8.2. Connect a debug board to GBC board in order to access TIVA through CCS. Through I2C channel 0, lithium ion battery charger U85 can be accessed. Read register Ibat having sub-address 0x3D. This value gives the charging current of the lithium ion battery. The read value must be equal to the measured value across R10039. Please refer to Section **4.2.4.4** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature - 25˚C

Operating Voltage – Lithium ion battery Voltage (9V to 12.6V)

System load –Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0014

Software versions – TIVA RTOS VER.33 code for lithium ion battery configuration

# Measurement Logs

****

**NOTE:** PASS Criteria: Measured value across R10039 and read value from register 0x3D must be equal

# Test ID / Test Name: PWR.5.3 / Load current measurement

# Purpose

The purpose of this test case is to measure the current drawn from the battery when system is powered ON by lithium ion battery.

# Test and Measurement Method

Connect lead acid battery. Connect a debug board to GBC board in order to access TIVA through CCS. Through I2C channel 0, lithium ion battery charger U85 can be accessed. Read register IIN having sub-address 0x3E. IIN register outputs the value of total load current. Please refer to Section **4.2.4.5** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature - 25˚C

Operating Voltage – Lithium ion battery voltage

System load – Idle/Typical + External electronic load

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0005

Software versions – TIVA RTOS VER.33 code for lithium ion battery configuration

# Test Results

Current measured across R9961 must be equal to value read from register 0x3E.

# Measurement Logs

****

**NOTE:** PASS Criteria: Measured value across R9961 and read value from register 0x3E must be equal

# Test ID / Test Name: PWR.5.4 / LDO Output Voltage

# Purpose

The purpose of this test case is to ensure the internal LDO output voltage of Lithium Ion battery charger U85 must be equal to 5V.

# Test and Measurement Method

Connect Lithium Ion battery terminals between to JTB8.1 and JTB8.2. Measure the battery charger U85 internal LDO output voltage at C1765.1. The above measured voltage should be equal to 5V to ensure proper functionality of GBC module. Please refer to Section **4.2.4.6** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature - 25˚C

Operating Voltage – Lithium ion battery Voltage (9V to 12.6V)

System load –Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0014

Software versions – NA

# Test Result

Measured LDO voltage is within the prescribed limit.i.e. between 4.3V and 5.5V

# Measurement Logs

|  |  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **Lithium Ion Battery - LDO Output Voltage** | | | | | | | | | |
| Sl. No. | Test case No. | Voltage Rail | Measuring Point | Measured Voltage(V) | Expected Voltage(V) | Specification | | Margin % | PASS/FAIL |
| Min(V) | Max(V) |
| 1 | PWR 5.4 | INT\_VCC\_LION | C1765.1 | 5.037 | 5 | 4.3 | 5.5 | -9.09 | PASS |

# Test ID / Test Name: PWR.5.5 / Temperature Measurement

# Purpose

The purpose of this test case is to measure the temperature of battery charger IC U85 when it’s fully operational.

# Test and Measurement Method

Connect lithium ion battery terminals between to JTB8.1and JTB8.2 Connect a debug board to GBC board in order to access TIVA through CCS. Through I2C channel 0, lithium ion battery charger U85 can be accessed. Read register DIE\_TEMPERATURE having sub-address 0x3F. Please refer to Section **4.2.4.7** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature - 25˚C

Operating Voltage – Lithium ion battery Voltage (9V to 12.6V)

System load –Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0014

Software versions – TIVA RTOS VER.33 code for lithium ion battery configuration

# Test Result

Read temperature is within the prescribed limits of the lithium ion battery, U85 IC.

# Measurement Logs

|  |  |  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **Sl.No** | **Register** | **Register Address** | **Hex Value** | **Decimal Value** | **Parameter** | **Value** | **Specification** | | **Margin(%)** | **PASS / FAIL** |
| **Min( deg C)** | **Max(deg C)** |
| 1 | DIE\_TEMP | 0x3F | 35c1 | 13761 | LTC4015 temperature (deg C) | 38.399 | -40 | 125 | 196.00 | PASS |

**** ****

# Test ID / Test Name: PWR.5.6 / Charge control (JEITA)

# Purpose

This test case indicates the current at which the lithium ion battery should be charged at a given temperature.

# Test and Measurement Method

Connect lithium ion battery at connector JTB8. Connect a debug board to GBC board in order to access TIVA through CCS. Through I2C channel 0 lithium ion battery charger U85 can be accessed. Write to registers from JEITA\_T1 (sub- address 0x1F) to JEITA\_T6 (sub- address 0x24) with temperature range from 0◦C to 60◦C. Read register *DIE\_TEMP* (sub-address 0x3F)to know the temperature. The battery should charge with a current corresponding to the measured temperature. Measure the charging current by measuring voltage across R10039. Charging current can be calculated by . Also read the register *IBAT* (sub-address 0x3D). Please refer to Section **4.2.4.8** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – Lithium Ion battery + AUX supply: +18V DC

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0005

Software versions – TIVA RTOS VER.33 code for lithium ion battery configuration

# Test Results

The value read by register 0x3D and the measured current across resistor R10039, should be same.

# Measurement Logs

****

# Test ID / Test Name: PWR.5.7 / Lion – Lead Acid and LiON battery or ‘ing circuit

# Purpose

The purpose of this test case is to check or ‘ing between lithium ion and lead acid battery when solar or AUX power supply is absent.

# Test and Measurement Method

Connect both lead acid battery and lithium ion battery. If lead acid battery measures <10.35V, lithium ion battery will be selected as the power supply source. Please refer to Section **4.2.4.9** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature - 25˚C

Operating Voltage – Lithium ion battery voltage or lead acid battery

System load – Idle/Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0005

Software versions – NA

# Test Results

When lead acid battery voltage is greater than 10.35V, the power source for GBC will be from lead acid and is verified by this test.

# Measurement Logs

|  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **Lead Acid and Lithium Ion Battery - OR’ing Circuit** | | | | | | | | |
| **Sl. No** | **Test Case ID** | **VBC\_LION(V)**  **@C3M97.1** | **VBC\_LACID(V)**  **@C3M98.1** | **VPOUT\_BUCK (V) @ C3M96.1** | **Specification** | | **Margin (%)** | **PASS / FAIL** |
| **Min** | **Max** |
| 1 | PWR.5.7 | 12.38 | 10.3 | 12.37 | 11.1 | 13.5 | -8.37 | PASS |

**NOTE:** VPOUT\_BUCK = VBC\_LION only if voltage of lead acid battery voltage is < 10.35



# Test ID / Test Name: PWR.5.8 / Charge time

# Purpose

This test case indicates the total time for which lithium ion is in charging phase.

# Test and Measurement Method

Connect lithium ion battery at connector JTB8. Connect a debug board to GBC board in order to access TIVA through CCS. Through I2C channel 0 lithium ion battery charger U85 can be accessed. Read register *MAX\_CHARGE\_TIMER* having sub-address 0x30. This register outputs the value of total time (in seconds) the lithium ion battery is in charging state. Please refer to Section **4.2.4.10** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – Lithium Ion battery + AUX supply: +18V DC

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0005

Software versions – TIVA RTOS VER.33 code for lithium ion battery configuration

# Test Results

By reading the register 0x30, it is validated that charge time read equals to the actual time of charging of lithium ion battery. , i.e. 618 seconds (10 min 30 seconds)

# Measurement Logs



# Test ID / Test Name: PWR.5.9 / Power delivery

# Purpose

The purpose of the test case is to validate the power delivery of Lithium Ion Battery.

# Test and Measurement Method

This test is conducted by measuring the voltage at the sense resistors R10039 and R10044 and calculating the current and power. The efficiency is calculated as η = 100% \* Pout / Pin. Please refer to Section **4.2.4.11** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0002

Software versions – NA

# Test Results

The efficiency is calculated to be 64.64%.

# Measurement Logs

|  |  |  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **Lithium Ion Power Delivery** | | | | | | | | | | |
| Section | Probing points | Resistor Value (mΩ) | Voltage (V) | Measured Voltage across sense resistor (mV) | Current (A) | Power (W) | Calculated Efficiency (%) | Specification (%) | | Design Margin (%) |
| Min | Max |
| Input Section | R10039 | 22 | 12.48 | 3.6 | 0.164 | 2.042 | 64.64 | 60 | 70 | -7.66178 |
| Output Section | R10044 | 10 | 12 | 1.1 | 0.110 | 1.320 |

**NOTE:** This test case was carried out for typical load condition. Full load condition will be tested in next version.

**The detailed analysis report for power delivery of Lithium Ion battery is embedded in the xls document attached herewith**.



# Buck-Boost

# Test ID / Test Name: PWR.6.1 / Line regulation

# Purpose

The purpose of this test case is to check the ability of the Buck-Boost converter to maintain its specified output voltage over changes in the input line voltage.

# Test and Measurement Method

This test is conducted by isolating input side of buck-boost converter (U88) by removing R10071 resistor and connecting and external DC power supply. Isolate input side of Tiva and Intel microprocessor, by removing R10054 and R10067 respectively. The input voltage is then varied in steps and output voltage is measured at R10044.2. Validate the output voltage accuracy at each step. Please refer to Section **4.2.5.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature - 25˚C

Operating Voltage - +9V DC to 22V DC

System load – Idle/Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0018

Software versions – NA

# Test Results

The output voltage accuracy of buck boost converter is within 2% of expected voltage under various supply input and load conditions.

# Measurement Logs

|  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- |
| **Line regulation without electronic load (Probed at C1800)** | | | | | | |
| Supply Voltage (V) | Output Current (A) | Output Voltage (V) | Specification | | Margin (%) | Pass/Fail |
| Min(V) | Max(V) |
| 9 | 0.04 | 11.92 | 11.76 | 12.24 | -1.36 | PASS |
| 11.1 | 0.04 | 11.93 | 11.76 | 12.24 | -1.45 | PASS |
| 12.6 | 0.04 | 11.94 | 11.76 | 12.24 | -1.53 | PASS |
| 16 | 0.04 | 12.01 | 11.76 | 12.24 | -1.88 | PASS |
| 18 | 0.04 | 12.03 | 11.76 | 12.24 | -1.72 | PASS |
| 20 | 0.04 | 12.03 | 11.76 | 12.24 | -1.72 | PASS |
| 22 | 0.04 | 12.04 | 11.76 | 12.24 | -1.63 | PASS |

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| **Line regulation with electronic load (Probed at C1800)** | | | | | | | |
| Supply Voltage (V) | Load Current (A) | Output Current (A) | Output Voltage (V) | Specification | | Margin (%) | Pass/Fail |
| Min(V) | Max(V) |
| 9 | 0.5 | 0.68 | 11.98 | 11.76 | 12.24 | -1.87 | PASS |
| 9 | 1 | 1.35 | 11.99 | 11.76 | 12.24 | -1.96 | PASS |
| 9 | 1.5 | 2.05 | 11.98 | 11.76 | 12.24 | -1.87 | PASS |
| 11.1 | 0.5 | 0.59 | 11.99 | 11.76 | 12.24 | -1.96 | PASS |
| 11.1 | 1 | 1.12 | 12 | 11.76 | 12.24 | -1.96 | PASS |
| 11.1 | 1.5 | 1.67 | 11.99 | 11.76 | 12.24 | -1.96 | PASS |
| 12.6 | 0.5 | 0.51 | 11.99 | 11.76 | 12.24 | -1.96 | PASS |
| 12.6 | 1 | 0.98 | 11.99 | 11.76 | 12.24 | -1.96 | PASS |
| 12.6 | 1.5 | 1.47 | 12 | 11.76 | 12.24 | -1.96 | PASS |
| 16 | 0.5 | 0.39 | 11.99 | 11.76 | 12.24 | -1.96 | PASS |
| 16 | 1 | 0.78 | 11.96 | 11.76 | 12.24 | -1.70 | PASS |
| 16 | 1.5 | 1.16 | 12.05 | 11.76 | 12.24 | -1.55 | PASS |
| 18 | 0.5 | 0.36 | 12.02 | 11.76 | 12.24 | -1.80 | PASS |
| 18 | 1 | 0.69 | 12.03 | 11.76 | 12.24 | -1.72 | PASS |
| 18 | 1.5 | 1.04 | 12.06 | 11.76 | 12.24 | -1.47 | PASS |
| 20 | 0.5 | 0.33 | 12.04 | 11.76 | 12.24 | -1.63 | PASS |
| 20 | 1 | 0.64 | 12.05 | 11.76 | 12.24 | -1.55 | PASS |
| 20 | 1.5 | 0.94 | 12.1 | 11.76 | 12.24 | -1.14 | PASS |
| 22 | 0.5 | 0.3 | 12.01 | 11.76 | 12.24 | -1.88 | PASS |
| 22 | 1 | 0.58 | 12.04 | 11.76 | 12.24 | -1.63 | PASS |
| 22 | 1.5 | 0.86 | 12.06 | 11.76 | 12.24 | -1.47 | PASS |

**The detailed analysis report with waveform captured for Buck-Boost Line Regulation test case executed is embedded in the xls document attached herewith.**



# Test ID / Test Name: PWR.6.2 / Load regulation

# Purpose

The purpose of this test case is to check the capability of Buck-Boost converter to maintain a constant output voltage over changes in the load.

# Test and Measurement Method

This test is conducted by isolating input side of buck-boost converter (U88) by removing R10071 resistor and connecting and external DC power supply. Isolate input side of Tiva and Intel microprocessor, by removing R10054 and R10067 respectively. The input voltage is then varied in steps and output voltage is measured at R10044.2. Connect an external load at R10063.1 and vary in steps of 0.5A. Please refer to Section **4.2.5.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Idle/Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0018

Software versions – NA

# Test Results

The output voltage accuracy of buck boost converter is within 2% of expected voltage under various load conditions.

# Measurement Logs

|  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- |
| **Load Regulation (Input Voltage - 18V)** | | | | | | |
| Load Current (A) | Output Current (A) | Output Voltage (V) (avg) | Specification | | Margin (%) | Pass/Fail |
| Min(V) | Max(V) |
| 0.5 | 0.39 | 11.88 | 11.76 | 12.24 | -1.02 | PASS |
| 1 | 0.73 | 11.87 | 11.76 | 12.24 | -0.94 | PASS |
| 1.5 | 1.07 | 11.89 | 11.76 | 12.24 | -1.11 | PASS |

**The detailed analysis report with waveform captured for Buck-Boost Load Regulation test case executed is embedded in the xls document attached herewith.**



# Test ID / Test Name: PWR.6.3 / Ripple measurement

# Purpose

The purpose of this test case is to check the maximum peak-to-peak ripple voltage of Buck-Boost converter output under different load conditions and input voltage.

# Test and Measurement Method

This test is conducted by isolating input side of buck-boost converter (U88) by removing R10071 resistor and connecting and external DC power supply. Isolate input side of Tiva and Intel microprocessor, by removing R10054 and R10067 respectively. The input voltage is then varied in steps and output voltage is measured at R10044.2. Connect an external load at R10063.1 and vary in steps of 0.5A. Setting oscilloscope in AC coupling mode, measure the ripple voltage across C1800. Please refer to Section **4.2.5.4** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Idle/Typical/Full

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0018

Software versions – NA

# Test Results

The maximum peak-to-peak ripple voltage measured is found to be less than 5% of the input voltage.

# Measurement Logs

|  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- |
| **Ripple Measurement for line regulation** | | | | | | |
| Supply Voltage (V) | Load Current (A) | Ripple Voltage (mV) | Specification | | Design Margin (%) | Pass/Fail |
| Min(mV) | Max(mV) |
| 9 | 0.5 | 52 | 0 | 450 | -88.44 | PASS |
| 9 | 1 | 62 | 0 | 450 | -86.22 | PASS |
| 9 | 1.5 | 64 | 0 | 450 | -85.78 | PASS |
| 11.1 | 0.5 | 44 | 0 | 555 | -92.07 | PASS |
| 11.1 | 1 | 58 | 0 | 555 | -89.55 | PASS |
| 11.1 | 1.5 | 56 | 0 | 555 | -89.91 | PASS |
| 12.6 | 0.5 | 44 | 0 | 630 | -93.02 | PASS |
| 12.6 | 1 | 50 | 0 | 630 | -92.06 | PASS |
| 12.6 | 1.5 | 52 | 0 | 630 | -91.75 | PASS |
| 16 | 0.5 | 24 | 0 | 800 | -97.00 | PASS |
| 16 | 1 | 24 | 0 | 800 | -97.00 | PASS |
| 16 | 1.5 | 25 | 0 | 800 | -96.88 | PASS |
| 18 | 0.5 | 29 | 0 | 900 | -96.78 | PASS |
| 18 | 1 | 28 | 0 | 900 | -96.89 | PASS |
| 18 | 1.5 | 29 | 0 | 900 | -96.78 | PASS |
| 20 | 0.5 | 31 | 0 | 1000 | -96.90 | PASS |
| 20 | 1 | 30 | 0 | 1000 | -97.00 | PASS |
| 20 | 1.5 | 30 | 0 | 1000 | -97.00 | PASS |
| 22 | 0.5 | 33 | 0 | 1100 | -97.00 | PASS |
| 22 | 1 | 34 | 0 | 1100 | -96.91 | PASS |
| 22 | 1.5 | 34 | 0 | 1100 | -96.91 | PASS |

**The detailed analysis report with waveform captured for Buck-Boost Ripple measurement test case executed is embedded in the xls document attached herewith.**



# Test ID / Test Name: PWR.6.4 / Load Current Measurement

# Purpose

The purpose of this test case is to measure the current drawn by Buck-Boost Converter when it is fully operational.

# Test and Measurement Method

This test is conducted by measuring voltage across sense resistor R10044 (0.01ohm). The measured value is then used to derive current drawn by the system. Please refer to Section **4.2.5.5** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Idle/Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0021

Software versions – NA

# Test Results

The current drawn by the Buck-Boost is close to typical current consumption of Intel (600mA), TIVA (120mA) and miscellaneous IC’s.

# Measurement Logs

|  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- |
| **Buck-Boost converter - Load Current measurement** | | | | | | |
| Voltage across sense resistor R10044 | Resistance (ohm) | Current (A) | Specification | | Design Margin (%) | Pass/Fail |
| Min | Max |
| 7.638 mV | 0.01 | 0.7638 | 0.4 | 0.8 | -4.53 | PASS |

**The detailed analysis report with waveform captured for Buck-Boost Load Current Measurement test case executed is embedded in the xls document attached herewith.** 

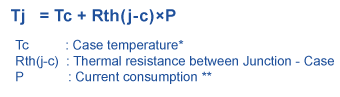
# Test ID / Test Name: PWR.6.5 / Temperature Measurement

# Purpose

The purpose of this test case is to measure the operating junction temperature of Buck Boost converter when it’s fully operational under ambient temperature.

# Test and Measurement Method

This test is conducted by measuring the case temperature via using Fluke 59 Mini IR Thermometer measured on U88.And then calculating junction operating temperature using the below formula:



The derived operating junction temperature value is well within operating temperature range of the device. Please refer to Section **4.2.5.6** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0018

Software versions – NA

# Test Results

The temperature measured at the Buck Boost converter is well within the designed spec.

# Measurement Logs

|  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- |
| **Temperature Measurement** | | | | | | |
| Measuring point | Case Temperature (degree Celsius) | Calculated operating junction temperature (degree Celsius) | Specification (degree Celsius) | | Design Margin (%) | Pass/Fail |
| Min | Max |
| U88 | 45.17 | 53.05 | -40 | 125 | 232.63 | PASS |

**The detailed analysis report with waveform captured for each of the Buck Boost temperature measurement test cases executed is embedded in the xls document attached herewith.**

****

# TIVA Power Supply

# Test ID / Test Name: PWR.7.3 / Ripple measurement

# Purpose

The purpose of this test case is to check the maximum peak-to-peak ripple voltage of DC-DC converter output under different load conditions and input voltage.

# Test and Measurement Method

This test is conducted by isolating both input and output side of DC-DC converter (U70) by removing relevant resistors. The load connected is varied for different currents along with input voltage. Please refer to Section **4.2.6.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Idle/Typical/Full

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0002

Software versions – NA

# Test Results

The maximum peak-to-peak ripple voltage measured is found to be less than 10mVp-p of the output voltage.

# Measurement Logs

|  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- |
| **Ripple Measurement for TIVA power supply** | | | | | | |
| Supply Voltage (V) | Measuring Point | Ripple Voltage (mV) | Specification | | Design Margin (%) | Pass/Fail |
| Min(mV) | Max(mV) |
| 18 | C502 | 6.3 | 0 | 10 | -37 | PASS |

**NOTE**: The detailed analysis report with waveform captured is embedded in the xls document attached in the end of this section.

# Test ID / Test Name: PWR.7.4 / Load Current Measurement

# Purpose

The purpose of this test case is to measure the current drawn by TIVA microcontroller when it’s fully operational.

# Test and Measurement Method

This test is conducted by measuring voltage across shunt resistor R10054 (0.002ohm). The measured value is 0.26mV. So the current drawn by the device is 130mA. The same has been validated by reading through I2C. Please refer to Section **4.2.6.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0002

Software versions – NA

# Test Results

The current drawn by the TIVA controller is within the designed spec.

# Measurement Logs

|  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **Load current Measurement for Tiva power supply** | | | | | | | | |
| Voltage across shunt (mV) | Measuring Point | Resistance (Ohm) | Current (mA) | Read Value through I2C (mA) | Specification (mA) | | Design Margin (%) | Pass/Fail |
| Min | Max |
| 0.26 | R10054 | 0.002 | 130 | 137 | 120 | 140 | -5.11 | PASS |

**NOTE**:

1. PASS criteria – Calculated value must be equal to read value through I2C.
2. The detailed analysis report with waveform captured is embedded in the xls document attached in the end of this section.

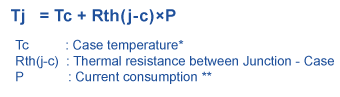
# Test ID / Test Name: PWR.7.5 / Temperature Measurement

# Purpose

The purpose of this test case is to measure the operating junction temperature of TIVA microcontroller when it’s fully operational and under ambient temperature.

# Test and Measurement Method

This test is conducted by measuring the temperature via using Fluke 59 Mini IR Thermometer measured on U72. And then calculating junction operating temperature using the below formula:



The derived operating junction temperature value is well within operating temperature of the device. Please refer to Section **4.2.6.4** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – PT11605002

Software versions – NA

# Test Results

The temperature measured at the TIVA controller is well within the designed spec.

# Measurement Logs

|  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- |
| **Temperature Measurement** | | | | | | |
| Case Temperature (degree Celsius) | Measuring Point | Calculated operating junction temperature (degree Celsius) | Specification (degree Celsius) | | Design Margin (%) | Pass/Fail |
| Min | Max |
| 41 | U72 | 46.05 | -40 | 85 | 215.13 | PASS |

**The detailed analysis report with waveform captured for each of the TIVA power supply test case executed is embedded in the xls document attached herewith**.



# FET Switch

# Test ID / Test Name: PWR.9.3 / Ripple Measurement

# Purpose

The purpose of this test case is to check the maximum peak-to-peak ripple voltage of FET switch.

# Test and Measurement Method

To measure the ripple voltage, coupling mode is changed to AC and Bandwidth to 20M in oscilloscope. Ripple voltage is measured across the capacitor C1A4. Please refer to Section **4.2.7.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature - 25˚C

Operating Voltage - +18V DC

System load – Idle/Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0021

Software versions – NA

# Test Results

The ripple voltage accuracy is within 5% of expected ripple voltage.

# Measurement Logs

|  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- |
| **FET switch - Ripple Measurement** | | | | | | |
| Voltage Rail | Measuring Point | Ripple Voltage(mV) | Specification | | Design Margin (%) | Pass/Fail |
| Min (mV) | Max (mV) |
| V12\_A | C1A4 | 27 | 0 | 600 | -95.5 | PASS |

**The detailed analysis report with waveform captured for FET switch Ripple Measurement test case executed is embedded in the xls document attached herewith.**

****

# Test ID / Test Name: PWR.9.4 / Load Current Measurement

# Purpose

The purpose of this test case is to measure the current drawn by FET switch when it is fully operational.

# Test and Measurement Method

This test is conducted by measuring voltage across shunt resistor R10067 (0.002ohm). The measured value is then used to derive current drawn by the system. The same has been validated by reading through I2C. Please refer to Section **4.2.7.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0021

Software versions – NA

# Test Results

The current drawn by the FET switch is within the designed spec.

# Measurement Logs

|  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **FET switch - Load Current Measurement** | | | | | | | | |
| Voltage across shunt resistor R10067 | Measurement Point | Resistance (ohm) | Current (A) | Read Through I2C | Specification | | Design Margin (%) | Pass/Fail |
| Min | Max |
| 1.230 mV | R10067 | 0.002 | 0.615 | 0.556 A | 0.605 | 0.625 | 10.61 | FAIL |

**NOTE:**

Resolution for failure - Changed the TIVA configuration settings. The read current readings is now matching with the actual drawn current

1. PASS criteria – Calculated value must be equal to read value through I2C.

**The detailed analysis report with waveform captured for FET switch Load Current Measurement test case executed is embedded in the xls document attached herewith.**

****

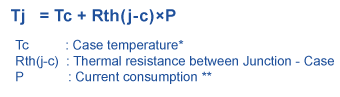
# Test ID / Test Name: PWR.9.5/ Temperature Measurement

# Purpose

The purpose of this test case is to measure the operating junction temperature of FET switch U248 when it is fully operational.

# Test and Measurement Method

This test is conducted by measuring the temperature via using Fluke 59 Mini IR Thermometer measured on U248. And then calculating junction operating temperature using the below formula:



The derived operating junction temperature value is well within range of operating temperature of the device. Please refer to Section **4.2.7.4** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature - 25˚C

Operating Voltage –18V

System load – Idle/Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0021

Software versions – NA

# Test Results

The measured value is well within operating temperature of the device.

# Measurement logs

|  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- |
| **Temperature Measurement of FET Switch** | | | | | | |
| Case Temperature (degree Celsius) | Measurement Point | Calculated operating junction temperature (degree Celsius) | Specification (degree Celsius) | | Design Margin (%) | Pass/Fail |
| Min | Max |
| 44.2 | U248 | 49 | -40 | 125 | 222.50 | PASS |

**The detailed analysis report with waveform captured for FET switch Temperature Measurement test case executed is embedded in the xls document attached herewith.**



# PMIC

# Test ID / Test Name: PWR.10.2 / Voltage accuracy of all output voltages

# Purpose

The purpose of the test case is to measure the output voltage rails of PMIC and to ensure that these voltages are in specified limits for the proper operation of Intel SoC.

# Test and Measurement Method

This test is conducted by probing at appropriate locations to measure the voltage rails as depicted in the below table. The measured values are in-line to Intel SoC requirement and should match with the pre-programmed voltages as per IDT9145-I0 specification. Please refer to Section **4.2.8.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0021

Software versions – NA

# Test Results

The measured values match with the pre-programmed voltages as per IDT9145-I0 specification.

# Measurement Logs

|  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- |
| **PMIC Output Supply Accuracy** | | | | | | |
| Voltage Rail | Measuring Points | Output Voltage (V) | Specification | | Margin (%) | Pass/Fail |
| Min(V) | Max(V) |
| V1P8\_A | C3M17 | 1.792 | 1.764 | 1.836 | -1.59 | PASS |
| VDDQ | C4M10 | 1.345 | 1.323 | 1.377 | -1.66 | PASS |
| V5\_A | C3M24 | 5.08 | 4.9 | 5.1 | -0.39 | PASS |
| V1P5\_S | C3M8 | 1.495 | 1.47 | 1.53 | -1.70 | PASS |
| VSFR\_SX | C3M30 | 1.345 | 1.323 | 1.377 | -1.66 | PASS |
| V1P35\_S | C3M22 | 1.342 | 1.323 | 1.377 | -1.44 | PASS |
| V1P2\_A | C2N9 | 1.245 | 1.225 | 1.275 | -1.63 | PASS |
| V1P2\_S | C2N11 | 1.244 | 1.225 | 1.275 | -1.55 | PASS |
| VTT\_DDR | C4P17 | 0.664 | 0.62775 | 0.72225 | -5.77 | PASS |
| V1P8\_IFSUP | C1B7 | 1.793 | 1.764 | 1.836 | -1.64 | PASS |
| VUSBPHY | C3M10 | 3.283 | 3.234 | 3.366 | -1.52 | PASS |
| V3P3\_A | C3M11 | 3.293 | 3.234 | 3.366 | -1.82 | PASS |
| VCC\_S | C2B34 | 0.91 | 0.98 | 1.02 | 7.14 | FAIL |
| VNN\_S | C2B1 | 0.948 | 0.931 | 0.969 | -1.83 | PASS |
| VDDQ | C1B4 | 1.343 | 1.323 | 1.377 | -1.51 | PASS |
| V1P05\_S | C3M180 | 1.057 | 1.029 | 1.071 | -1.31 | PASS |
| V1P0\_A | C3M19 | 1 | 0.98 | 1.02 | -1.96 | PASS |
| V12\_A | C3L18 | 12.09 | 11.76 | 12.24 | -1.23 | PASS |

**NOTE:** Failure is attributed to IDT9145 PMIC and is addressed with IDT9180 PMIC. Rev C design now uses IDT9180 PMIC.

**The detailed analysis report with waveform captured for PMIC voltage accuracy Measurement test case executed is embedded in the xls document attached herewith.** ****

# Test ID / Test Name: PWR.10.3/ Secondary supplies enable functionality

# Purpose

The purpose of the test case is to validate secondary supply rails of PMIC by checking status of dependency rails with respect to change in status (high or low).

# Test and Measurement Method

Impact of High level status of PMIC\_SLP\_S0IX is verified by measuring dependency power rails VSFRX and V1P0SX\_EN at appropriate locations as mentioned in the below table and ensuring those are enabled. Upon which remove R1B22 to make PMIC\_SLP\_S0IX low and ensure dependency power rails VSFRX and V1P0SX\_EN are disabled. Please refer to Section **4.2.8.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0021

Software versions – NA

# Test Results

This test case verifies the impact of Secondary power supplies on dependency power rails as per the IDT9145 specification.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| **Secondary supplies enable functionality** | | | | | | | |
| Power rail | Power rail Status | Dependency rails | Measuring Points | Dependency rail status | Specification | Design Margin (%) | Pass/Fail |
| Expected rail status |  |
| PMIC\_SLP\_S0IX | High | VSFRX | C3M30 | Enable | Enable | NA | PASS |
| V1P0SX\_EN | C3B21 | Enable | Enable | PASS |
| Low | VSFRX | C3M30 | Disable | Disable | PASS |
| V1P0SX\_EN | C3B21 | Disable | Disable | PASS |
| PMIC\_SLP\_S3 | High | V1P05\_S | c3M180 | Enable | Enable | PASS |
| V1P02\_S | C2N11 | Enable | Enable | PASS |
| V1P5\_S | C3M8 | Enable | Enable | PASS |
| V1P35\_S | C3M22 | Enable | Enable | PASS |
| Low | V1P05\_S | c3M180 | Disable | Disable | PASS |
| V1P02\_S | C2N11 | Disable | Disable | PASS |
| V1P5\_S | C3M8 | Disable | Disable | PASS |
| V1P35\_S | C3M22 | Disable | Disable | PASS |

# Test ID / Test Name: PWR.10.5/ PMIC debug circuit functionality

# Purpose

The purpose of the test case is to validate debug circuit of PMIC.

# Test and Measurement Method

This test case is conducted by probing dependency power rails of PMIC\_SLP\_S0IX and PMIC\_SLP\_S3 at appropriate locations as depicted in below table. High level status of PMIC\_THERMTRIP is checked in debug circuit by removing R4M16 to isolate PMIC\_THERMTRIP from Intel SOC and ensure all the power rails are turned on. Please refer to Section **4.2.8.4** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0021

Software versions – NA

# Test Results

The debug circuit functionality is verified and validated

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| **PMIC debug circuit functionality** | | | | | | | |
| Power rail | Power rail Status | Dependency rails | Measuring Points | Dependency rail status | Specification | Design Margin (%) | Pass/Fail |
| Expected rail status |
| PMIC\_SLP\_S0IX | High | VSFRX | C3M30 | Enable | Enable | NA | PASS |
| V1P0SX\_EN | C3B21 | Enable | Enable | PASS |
| Low | VSFRX | C3M30 | Disable | Disable | PASS |
| V1P0SX\_EN | C3B21 | Disable | Disable | PASS |
| PMIC\_SLP\_S3 | High | V1P05\_S | C3M180 | Enable | Enable | PASS |
| V1P02\_S | C2N11 | Enable | Enable | PASS |
| V1P5\_S | C3M8 | Enable | Enable | PASS |
| V1P35\_S | C3M22 | Enable | Enable | PASS |
| Low | V1P05\_S | C3M180 | Disable | Disable | PASS |
| V1P02\_S | C2N11 | Disable | Disable | PASS |
| V1P5\_S | C3M8 | Disable | Disable | PASS |
| V1P35\_S | C3M22 | Disable | Disable | PASS |
| PMIC\_THERMTRIP | High | All Power rails |  | Enable | Enable | PASS |
| Low | All Power rails |  | Disable | Disable | PASS |

# System Power sequence

# Test ID / Test Name: PWR.11.1 / Power-up

# Purpose

The purpose of the test case is to validate the Power-up sequence of the system including GBC and RF-SDR board.

# Test and Measurement Method

This test is conducted by probing the signals “ATOM\_12V\_ONOFF” (Intel atom) and “TRXFE\_12V\_ONOFF” (RF-SDR) at R10753 and R10580 respectively. The power sequence is measured while powering on the system. Please refer to Section **4.2.9.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0010

Debug board Serial Number - WZ1628LIFE2DEBUG0018

Software versions – TIVA RTOS code

# Test Results

Power up sequence is verified and is in the following order.

* + - 1. Intel atom
      2. RF-SDR

# Measurement Logs

|  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- |
| Sl.No | Measuring Point | Measured sequence | Specification | Design Margin (%) | Result |
| Expected sequence |
| **System power-up sequence** | | | | | |
| 1 | R10753 | ATOM\_12V\_ONOFF | ATOM\_12V\_ONOFF | NA | PASS |
| 2 | R10580 | TRXFE\_12V\_ONOFF | TRXFE\_12V\_ONOFF |

**NOTE:** There is no time delay requirement for the power up sequence.

**The detailed analysis report with waveform captured for system power up sequence is embedded in the xls document attached herewith.**



# Test ID / Test Name: PWR.11.2 / Power-down

# Purpose

The purpose of the test case is to validate the Power-down sequence of the system including GBC and RF-SDR board.

# Test and Measurement Method

This test is conducted by probing the signals “ATOM\_12V\_ONOFF” (Intel atom) and “TRXFE\_12V\_ONOFF” (RF-SDR) at R10753 and R10580 respectively. The power sequence is measured while powering off the system. Please refer to Section **4.2.9.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0010

Debug board Serial Number - WZ1628LIFE2DEBUG0018

Software versions – TIVA RTOS code

# Test Results

Power down sequence is verified and is in the following order.

1. RF-SDR
2. Intel atom

# Measurement Logs

|  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- |
| Sl.No | Measuring Point | Measured sequence | Specification | Design Margin (%) | Result |
| Expected sequence |
| **System power-down sequence** | | | | | |
| 1 | R10580 | TRXFE\_12V\_ONOFF | TRXFE\_12V\_ONOFF | NA | PASS |
| 2 | R10753 | ATOM\_12V\_ONOFF | ATOM\_12V\_ONOFF |
|  |  |  |  |  |

**NOTE:** There is no time delay requirement for the power down sequence.

**The detailed analysis report with waveform captured for system power down sequence is embedded in the xls document attached herewith.**



# Test ID / Test Name: PWR.11.3 / Soft Reset

# Purpose

The purpose of the test case is to validate the soft reset for the system.

# Test and Measurement Method

This test is conducted by connecting debug board to GBC board and restarting the system after it boots up. The system is restarted either by giving the command “sudo reboot” in the terminal or by clicking the restart button. Please refer to Section **4.2.9.5** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0002

Debug board Serial Number - WZ1628LIFE2DEBUG0018

Software versions – Linux 14.4.4

# Test Results

Soft Reset for the system is verified.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **Soft Reset** | | | | | | | |
| NA | | | | | | | |

**The snapshots of Soft Reset for the system are attached herewith.**



# Test ID / Test Name: PWR.11.4 / Hard Reset

# Purpose

The purpose of the test case is to validate the hard reset of the system.

# Test and Measurement Method

This test is conducted by connecting debug board to GBC board and restarting the system after it boots up. The system is restarted by pressing switch (S2). Please refer to Section **4.2.9.6** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0002

Debug board Serial Number - WZ1628LIFE2DEBUG0018

Software versions – Linux 14.4.4

# Test Results

Hard Reset for the system is verified.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **Hard Reset** | | | | | | | |
| NA | | | | | | | |

**The snapshots of Hard Reset for the system are attached herewith.**



# CPU

# Intel Atom

# Test ID / Test Name: CPU.1.1/ Boot configuration

# Purpose

The purpose of the test case is to validate SPI NOR Flash memory by accessing the device and loading the CoreBoot image

# Test and Measurement Method

This test is conducted by programming SPI NOR FLASH device using SF100 ISP IC programmer. Please refer to Section **5.2.1.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0016

Software versions – NA

# Test Results

This test case verifies successfully programming and configuring the SPI NOR FLASH.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **Boot configuration** | | | | | | | |
| NA | | | | | | | |

**Snapshot of SF100 programmer GUI and its programming execution is embed in the image below.**



# Test ID / Test Name: CPU.1.2/ Power-on sequence

# Purpose

The purpose of the test case is to validate sequence of PMIC power rails while powering on the system.

# Test and Measurement Method

This test is conducted by probing at appropriate locations using logic analyzer to check the sequence of power rails as depicted in the below table and the trigger is set to 550mV. The measured sequence should be as per the IDT9145-I0 specification. Please refer to Section **5.2.1.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0021

Software versions – NA

# Test Results

This test case verifies the Cold Boot Sequence (Power on sequence) of Intel SOC.

# Measurement Logs

|  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- |
| **Power-on sequence** | | | | | | |
| Sl. No | Logic analyzer bits | Measurement Points | Measured sequence | Specification | Design Margin (%) | Result |
| Expected sequence |
| 1 | D5 | R2B40.1 | PWRBTNIN | PWRBTNIN | NA | PASS |
| 2 | D0 | C1B7.1 | VUSBPHY | V1P8\_IFSUP |
| 3 | D1 | C3M10 | V1P0\_A | VUSBPHY |
| 4 | D2 | C3M19.1 | V1P2\_A | V1P0\_A |
| 5 | D3 | C2N9.2 | V1P8\_A | V1P2\_A |
| 6 | D4 | C3M17.1 | VDDQ | V1P8\_A |
| 7 | D6 | C4M10.2 | V1P8\_IFSUP\* | VDDQ |
| 8 | D7 | C2B34.1 | VCC | VCC |
| 9 | D8 | C3M8.1 | V1P5\_S | V1P5\_S |
| 10 | D9 | C3M22.1 | V1P35\_S | V1P35\_S |
| 11 | D10 | C3B33.1 | COREPWROK | COREPWROK |

**NOTE:**

1. \*Even though V1P8\_IFSUP is not in sequence we can consider this test case as PASS. Because V1P8\_IFSUP is not used for Intel SOC**.**

2. PMIC IC has been changed in next version from 9145 to 9180. IDT team has tested power on and power down sequence and the reports for the same are attached below.

**The detailed analysis report with waveform captured for power on sequence test case is embed in the excel document attached herewith.**

**** ****

# Test ID / Test Name: CPU.1.3/ Power-down sequence

# Purpose

The purpose of the test case is to validate sequence of PMIC power rails while powering off the system.

# Test and Measurement Method

This test is conducted by probing at appropriate locations using logic analyzer to check the sequence of power rails while powering off the device as depicted in the below table and the trigger is set to 550mV. The measured sequence should be as per the IDT9145 specification. Please refer to Section **5.2.1.4** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load –Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0021

Software versions – NA

# Test Results

This test case fails to verify the Cold Off Sequence (Power down sequence) of Intel SOC.

# Measurement Logs

|  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- |
| **Power-down sequence** | | | | | | |
| Sl.No | Logic analyzer bits | Measurement Points | Measured sequence | Specification | Design Margin (%) | Result |
| Expected sequence |
| 1 | D11 | R2B13.1 | PLTRST\_B | PLTRST\_B | NA | FAIL |
| 2 | D10 | C3B33.1 | COREPWROK | COREPWROK |
| 3 | D12 | C2B22.1 | VDDQ\_VTT | VDDQ\_VTT |
| 4 | D7 | C2B34.1 | VCC | VCC |
| 5 | D13 | C3A12.1 | VNN | V3P3S |
| 6 | D15 | C2B1.1 | V1P2\_A | VNN |
| 7 | D3 | C2N9.2 | V1P0\_A | V1P2\_A |
| 8 | D4 | C3M17.1 | V1P8\_A | V1P8\_A |
| 9 | D2 | C3M19.1 | V3P3S | V1P0\_A |

**NOTE:** Failure resolution: Issue is attributed to IDT9145 PMIC and is addressed with IDT9180 PMIC. Rev C design now uses IDT9180 PMIC.

**The detailed analysis report with waveform captured for power down sequence test case is embed in the excel document attached herewith**.



# PMIC (IDTP9145) - I2C

# Test ID / Test Name: CPU.2.1 / Electrical validation

# Purpose

The purpose of the test case is to validate the electrical characteristics of I2C interface between Intel Atom processor and PMIC.

# Test and Measurement Method

This test is conducted by probing the I2C signal at R1B14.2 (SCL), R1B8.2 (SDA) after running the script “./soc\_i2c0\_pmic\_read\_kernel\_4.4.0.31.sh” in the terminal. The measured values are well with-in the limit as specified in the IDT9145 PMIC datasheet specification. Please refer to Section **5.2.2.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0002

Software versions – Linux 14.4.4 with PMIC I2C code

# Test Results

The electrical characteristics of I2C interface between Intel Atom processor and PMIC is within the designed spec.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **PMIC - U2B3** | | | | | | | |
| SOC\_I2C\_SCL | R1B14.2 | VLOW (max) (V) | 0.08 | -0.5 | 0.54 | 116.00 | PASS |
| VHIGH (min) (V) | 1.8 | 1.26 | 2.3 | -21.74 | PASS |
| Rise time (ns) | 163.8 | 0 | 300 | -45.40 | PASS |
| Fall time (ns) | 152.9 | 0 | 300 | -49.03 | PASS |
| Frequency (kHz) | 384.6 | 0 | 400 | -3.85 | PASS |
| SOC\_I2C\_SDA | R1B8.2 | VLOW (max) (V) | 0.08 | -0.5 | 0.54 | 116.00 | PASS |
| VHIGH (min) (V) | 1.8 | 1.26 | 2.3 | -21.74 | PASS |
| Rise time (ns) | 284.8 | 0 | 300 | -5.07 | PASS |
| Fall time (ns) | 163.8 | 0 | 300 | -45.40 | PASS |

**The detailed analysis report with waveform captured for PMIC I2C - Electrical validation is embedded in the xls document attached herewith.**

****

# Test ID / Test Name: CPU.2.2/ Signal integrity

# Purpose

The purpose of the test case is to validate the signal integrity of I2C interface between Intel Atom processor and PMIC.

# Test and Measurement Method

This test is conducted by probing the I2C signal at R1B14.2 (SCL), R1B8.2 (SDA) after running the script “./soc\_i2c0\_pmic\_read\_kernel\_4.4.0.31.sh” in the terminal. The measured values are well with-in the limit as specified in the IDT9145 PMIC datasheet specification. Please refer to Section **5.2.2.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0002

Software versions – Linux 14.4.4 with PMIC I2C code

# Test Results

The signal integrity of I2C interface between Intel Atom processor and PMIC is not within the designed spec.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **PMIC - U2B3** | | | | | | | |
| SOC\_I2C\_SCL | R1B14.2 | Positive Over-shoot (%) | 11.63 | 0 | 10 | 16.3 | FAIL |
| Negative Over-shoot (%) | 20.93 | 0 | 10 | 109.3 | FAIL |
| SOC\_I2C\_SDA | R1B8.2 | Positive Over-shoot (%) | 9.3 | 0 | 10 | -7 | PASS |
| Negative Over-shoot (%) | 9.3 | 0 | 10 | -7 | PASS |
| Data set-up time (ns) | 1450 | 100 | 2500 | -42 | PASS |
| Data hold time (ns) | 990 | 300 | 2500 | -60.40 | PASS |

**NOTE:** Failure Resolution: Series termination changed to 33 Ohms in Rev C.

**The detailed analysis report with waveform captured for PMIC I2C -** **Signal integrity is embedded in the xls document attached herewith.**

****

# Test ID / Test Name: CPU.2.3/ Functional validation

# Purpose

The purpose of the test case is to validate the I2C interface of PMIC IC.

# Test and Measurement Method

This test is conducted by accessing I2C0 bus and reading chip revision register value 0x05 from address 0x01. Please refer to Section **5.2.2.4** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0002

Software versions – Linux 14.4.4 with PMIC I2C code

# Test Results

INTEL atom processor able to read chip revision register of PMIC and the same has been validated.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **PMIC** | | | | | | | |
| NA | | | | | | | |

**The snapshot of functional validation of PMIC I2C is attached herewith**.



# DDR (TS512MSK64W6H-I) - SMBus

# Test ID / Test Name: CPU.5.1/ Electrical validation

# Purpose

The purpose of the test case is to validate the electrical characteristics of SMBus interface between Intel Atom processor and DDR Memory.

# Test and Measurement Method

This test is conducted by probing the SMBus signal at U4D1.6 (SDA) and U4D1.7 (CLK) after running the script “./pcu\_smb\_ddr3spd\_read.sh” in the terminal. The measured values are well with-in the limit as specified in the DDR datasheet specification. Please refer to Section **5.2.3.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0002

Software versions – Linux 14.4.4 with DDR3 SMB code

# Test Results

The electrical characteristics of SMBus interface between Intel Atom processor and DDR Memory is within the designed spec.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **DDR-SMB (Before Level Shifter)** | | | | | | | |
| PCU\_SMB\_CLK | U4D1.2 | VLOW (max) (V) | 0 | -0.5 | 0.54 | 100.00 | PASS |
| VHIGH (min) (V) | 1.8 | 1.26 | 5.5 | -42.86 | PASS |
| Rise time (ns) | 710 | 0 | 1000 | -29.00 | PASS |
| Fall time (ns) | 8 | 0 | 300 | -97.33 | PASS |
| Frequency (kHz) | 100 | 0 | 100 | 0.00 | PASS |
| PCU\_SMB\_DAT | U4D1.3 | VLOW (max) (V) | 0 | -0.5 | 0.54 | 100.00 | PASS |
| VHIGH (min) (V) | 1.8 | 1.26 | 5.5 | -42.86 | PASS |
| Rise time (ns) | 740 | 0 | 1000 | -26.00 | PASS |
| Fall time (ns) | 10 | 0 | 300 | -96.67 | PASS |
| **DDR-SMB (After Level Shifter)** | | | | | | | |
| SMB\_DDR3\_CLK | U4D1.7 | VLOW (max) (V) | 0.4 | -0.5 | 0.99 | 180.00 | PASS |
| VHIGH (min) (V) | 2.8 | 2.31 | 3.8 | -21.21 | PASS |
| Rise time (ns) | 860 | 0 | 1000 | -14.00 | PASS |
| Fall time (ns) | 52 | 0 | 300 | -82.67 | PASS |
| Frequency (kHz) | 83.3 | 0 | 100 | -16.70 | PASS |
| SMB\_DDR3\_DAT | U4D1.6 | VLOW (max) (V) | 0.4 | -0.5 | 0.99 | 180.00 | PASS |
| VHIGH (min) (V) | 2.8 | 2.31 | 3.8 | -21.21 | PASS |
| Rise time (ns) | 980 | 0 | 1000 | 2.00 | PASS |
| Fall time (ns) | 56 | 0 | 300 | -81.33 | PASS |

**The detailed analysis report with waveform captured for DDR SMBus - Electrical validation is embedded in the xls document attached herewith.**



# Test ID / Test Name: CPU.5.2 / Signal integrity

# Purpose

The purpose of the test case is to validate the signal integrity of SMBus interface between Intel Atom processor and DDR Memory.

# Test and Measurement Method

This test is conducted by probing the SMBus signal at U4D1.6 (SDA) and U4D1.7 (CLK) after running the script “./pcu\_smb\_ddr3spd\_read.sh” in the terminal. The measured values are well with-in the limit as specified in the DDR datasheet specification. Please refer to Section **5.2.3.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0002

Software versions – Linux 14.4.4 with DDR3 SMB code

# Test Results

The Signal integrity characteristics of SMBus interface between Intel Atom processor and DDR Memory is not within the designed spec.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **DDR-SMB (Before Level Shifter)** | | | | | | | |
| PCU\_SMB\_CLK | U4D1.2 | Positive Over-shoot (V) | 0 | 0 | 0.18 | -100.00 | PASS |
| Negative Over-shoot (V) | 0 | 0 | 0.18 | -100.00 | PASS |
| PCU\_SMB\_DAT | U4D1.3 | data set-up time (ns) | 3000 | 250 | 10000 | -70.00 | PASS |
| data hold time (ns) | 1680 | 300 | 10000 | -83.20 | PASS |
| Positive Over-shoot (V) | 0 | 0 | 0.18 | -100.00 | PASS |
| Negative Over-shoot (V) | 0.34 | 0 | 0.18 | 88.89 | FAIL |
| **DDR-SMB (After Level Shifter)** | | | | | | | |
| SMB\_DDR3\_CLK | U4D1.7 | Positive Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| Negative Over-shoot (V) | 0.32 | 0 | 0.33 | -3.03 | PASS |
| SMB\_DDR3\_DAT | U4D1.6 | data set-up time (ns) | 3000 | 250 | 10000 | -70.00 | PASS |
| data hold time (ns) | 1660 | 300 | 10000 | -83.40 | PASS |
| Positive Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| Negative Over-shoot (V) | 0.36 | 0 | 0.33 | 9.09 | FAIL |

**NOTE:** Failure Resolution: Series termination changed to 10 Ohms in Rev C.

**The detailed analysis report with waveform captured for DDR SMBus - Signal integrity is embedded in the xls document attached herewith.**



# Test ID / Test Name: CPU.5.3 / Functional validation

# Purpose

The purpose of the test case is to validate the SMBus interface of DDR Memory.

# Test and Measurement Method

This test is conducted by reading I2C9 bus at address 50H by reading device register address from 128 to 145. . Please refer to Section **5.2.3.4** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0002

Software versions – Linux 14.4.4 with DDR3 SMB code

# Test Results

INTEL atom processor able to read DDR registers and the same has been validated.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **DDR-SMB** | | | | | | | |
| NA | | | | | | | |

**The snapshots of functional validation of DDR SMBus are attached herewith**.

# PCU (ADT7481) - SMBus

# Test ID / Test Name: CPU.6.1/ Electrical validation

# Purpose

The purpose of the test case is to validate the electrical characteristics of SMBus interface between Intel Atom processor and temperature sensor.

# Test and Measurement Method

This test is conducted by probing the I2C signal at U3A1.10 (SCL), U3A1.9 (SDA) after running the script “./pcu\_smb\_tsensor\_read.sh” in the terminal. The measured values are well with-in the limit as specified in the Temperature Sensor datasheet specification. Please refer to Section **5.2.4.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0002

Software versions – Linux 14.4.4 with Temp sensor SMB code

# Test Results

The electrical characteristics of SMBus interface between Intel Atom processor and temperature sensor is within the designed spec.

# Measurement Logs

|  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **PCU - SMB (Before Level Shifter)** | | | | | | | | |
| PCU3\_SMB\_CLK | U2A1.2 | VLOW (max) (V) | 0 | | -0.5 | 0.54 | 100.00 | PASS |
| VHIGH (min) (V) | 1.8 | | 1.26 | 5.5 | -42.86 | PASS |
| Rise time (ns) | 700 | | 0 | 1000 | -30.00 | PASS |
| Fall time (ns) | 8.4 | | 0 | 300 | -97.20 | PASS |
| Frequency (kHz) | 92.592 | | 0 | 100 | -7.41 | PASS |
| PCU3\_SMB\_DAT | U2A1.3 | VLOW (max) (V) | 0 | | -0.5 | 0.54 | 100.00 | PASS |
| VHIGH (min) (V) | 1.8 | | 1.26 | 5.5 | -42.86 | PASS |
| Rise time (ns) | 750 | | 0 | 1000 | -25.00 | PASS |
| Fall time (ns) | 11.6 | | 0 | 300 | -96.13 | PASS |
| **PCU-SMB (After Level Shifter)** | | | | | | | | |
| SMB\_3P3\_CLK | U3A1.10 | VLOW (max) (V) | | 0.4 | -0.5 | 0.8 | 180.00 | PASS |
| VHIGH (min) (V) | | 2.8 | 2.1 | 3.8 | -26.32 | PASS |
| Rise time (ns) | | 630 | 0 | 1000 | -37.00 | PASS |
| Fall time (ns) | | 62 | 0 | 300 | -79.33 | PASS |
| Frequency (kHz) | | 98.039 | 0 | 100 | -1.96 | PASS |
| SMB\_3P3\_DAT | U3A1.9 | VLOW (max) (V) | | 0.4 | -0.5 | 0.8 | 180.00 | PASS |
| VHIGH (min) (V) | | 2.8 | 2.1 | 3.8 | -26.32 | PASS |
| Rise time (ns) | | 650 | 0 | 1000 | -35.00 | PASS |
| Fall time (ns) | | 60 | 0 | 300 | -80.00 | PASS |

**The detailed analysis report with waveform captured for PCU SMBus - Electrical validation is embedded in the xls document attached herewith.**

****

# Test ID / Test Name: CPU.6.2 / Signal Integrity

# Purpose

The purpose of the test case is to validate the Signal Integrity of SMBus interface between Intel Atom processor and temperature sensor.

# Test and Measurement Method

This test is conducted by probing the I2C signal at U3A1.10 (SCL), U3A1.9 (SDA) after running the script “./pcu\_smb\_tsensor\_read.sh” in the terminal. The measured values are well with-in the limit as specified in the Temperature Sensor datasheet specification. Please refer to Section **5.2.4.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0002

Software versions – Linux 14.4.4 with Temp sensor SMB code

# Test Results

The Signal Integrity characteristics of SMBus interface between Intel Atom processor and temperature sensor is not within the designed spec.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **PCU-SMB (Before Level Shifter)** | | | | | | | |
| PCU3\_SMB\_CLK | U2A1.2 | Positive Over-shoot (V) | 0 | 0 | 0.18 | -100.00 | PASS |
| Negative Over-shoot (V) | 0 | 0 | 0.18 | -100.00 | PASS |
| PCU3\_SMB\_DAT | U2A1.3 | data set-up time (ns) | 3720 | 250 | 10000 | -62.80 | PASS |
| data hold time (ns) | 1690 | 300 | 10000 | -83.10 | PASS |
| Positive Over-shoot (V) | 0 | 0 | 0.18 | -100.00 | PASS |
| Negative Over-shoot (V) | 0.2516 | 0 | 0.18 | 39.78 | FAIL |
| **PCU-SMB (After Level Shifter)** | | | | | | | |
| SMB\_3P3\_CLK | U3A1.10 | Positive Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| Negative Over-shoot (V) | 0.23 | 0 | 0.33 | -30.30 | PASS |
| SMB\_3P3\_DAT | U3A1.9 | data set-up time (ns) | 3040 | 250 | 10000 | -69.60 | PASS |
| data hold time (ns) | 1620 | 300 | 10000 | -83.80 | PASS |
| Positive Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| Negative Over-shoot (V) | 0.28 | 0 | 0.33 | -15.15 | PASS |

**NOTE:** Failure Resolution: Series termination changed to 10 Ohms in Rev C.

**The detailed analysis report with waveform captured for PCU SMBus - Signal Integrity is embedded in the xls document attached herewith.**



# Test ID / Test Name: CPU.6.3 / Functional validation

# Purpose

The purpose of the test case is to validate the SMBus interface of temperature sensor.

# Test and Measurement Method

This test is conducted by reading I2C9 bus at address 3DH and 3EH for respective device ID and manufacture ID and read values 81H and 41H respectively. Please refer to Section **5.2.4.4** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0002

Software versions – Linux 14.4.4 with Temp sensor SMB code

# Test Results

INTEL atom processor able to read Device and Manufacture ID of temperature sensor and the same has been validated.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **PCU - SMB** | | | | | | | |
| NA | | | | | | | |

**The snapshot of functional validation of PCU SMBus is attached herewith**.



# Springville 1 - MDI

# Test ID / Test Name: CPU.7.1/ Signal characteristics

# Purpose

The purpose of this test case is to verify MDI (interface between [Marvell](http://www.marvell.com/switching/link-street/)Switch (88E6071) to Springville (WGI210AT)) signal characteristics.

# Test and Measurement Method

This test is conducted by connecting a Linux PC to port A of GBC board and starting communication between them by pinging each other. The MDI transmitting signals (from Springville to Switch) are measured at R962 (MDI0P) and R963 (MDI0N) and MDI receiving signals (from Switch to Springville) are measured at L1M2.6 (MDI1P) and L1M2.8 (MDI1N). Please refer to Section **5.2.5.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0002

Software versions – Linux 14.4.4

# Test Results

The signal characteristics of MDI signals are as per the specification and the data rate is 100Mbps.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **Springville 1 - MDI** | | | | | | | |
| MDI0P, MDI0N | R962.2, R963.2 | Vp-p (V) | 1.012 | 0.950 | 1.05 | -3.62 | PASS |
| Overshoot (%) | 0.86 | 0 | 5 | -82.80 | PASS |
| Undershoot (%) | 2.01 | 0 | 5 | -59.80 | PASS |
| Data rate (Mbps) | 100 | NA | 100 | 0.00 | PASS |
| MDI1P, MDI1N | L1M2.6, L1M2.8 | Vp-p (V) | 1.012 | 0.950 | 1.05 | -3.62 | PASS |
| Overshoot (%) | 0.86 | 0 | 5 | -82.80 | PASS |
| Undershoot (%) | 2.01 | 0 | 5 | -59.80 | PASS |
| Data rate (Mbps) | 100 | NA | 100 | 0.00 | PASS |

**The detailed analysis report with waveform captured for signal characteristics of Springville MDI test case is embedded in the xls document attached herewith.**

****

# Test ID / Test Name: CPU.7.2/ Functional validation

# Purpose

The purpose of the test case is to validate the function of springville1-MDI.

# Test and Measurement Method

This test is conducted by connecting a Linux PC to port A of GBC board and starting communication between them by giving command “ping IPaddress (IP address of Linux PC)” in the terminal of GBC system and “ping IPaddress (IP address of GBC system)” in Linux PC. Please refer to Section **5.2.5.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0002

Software versions – Linux 14.4.4

# Test Results

Communication is established between Springville and Marvell switch through MDI interface over 100Mbps data rate.

**The snapshot of functional validation of Springville MDI is attached herewith.**

**  **

# TIVA - UART

# Test ID / Test Name: CPU.8.1 / Electrical validation

# Purpose

The purpose of the test case is to validate the electrical characteristics of UART interface between Tiva controller and Intel Atom processor.

# Test and Measurement Method

This test is conducted by probing the UART TX signal at R10550 and UART RX signal at R10472 respectively. UART TX is measured by sending data from TIVA to SOC. UART RX is measured by sending data from SOC to TIVA. Please refer to Section **5.2.6.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0021

Debug board Serial Number - WZ1628LIFE2DEBUG0018

Software versions – Linux 14.4.4

# Test Results

The electrical characteristics of UART interface between Tiva controller and Intel Atom processor fails.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **UART TX** | | | | | | | |
| ISO\_TIVA\_SOC\_UART3\_TX | R10550 | VLOW (V) | 0 | -0.378 | 0.63 | 100.00 | PASS |
| VHIGH (V) | 1.8 | 1.17 | 2.232 | -19.35 | PASS |
| Positive Overshoot (V) | 0.17 | 0 | 0.18 | -5.56 | PASS |
| Negative Overshoot (V) | 0.22 | 0 | 0.18 | 22.22 | FAIL |
| **UART RX** | | | | | | | |
| TIVA\_SOC\_UART3\_RX | R10472 | VLOW (V) | -0.18 | 0 | 1.155 | -115.58 | FAIL |
| VHIGH (V) | 3.16 | 2.145 | 4 | -21.00 | PASS |
| Positive Overshoot (V) | 0.9 | 0 | 0.33 | 172.73 | FAIL |
| Negative Overshoot (V) | 0.96 | 0 | 0.33 | 190.91 | FAIL |

**NOTE:** Failure Resolution: Series termination changed to 49.9 Ohms in Rev C.

**The detailed analysis report with waveform captured for Electrical validation of TIVA – UART test case is embedded in the xls document attached herewith**.



# Test ID / Test Name: CPU.8.2 / Functional validation

# Purpose

The purpose of the test case is to validate the function of UART interface between Tiva controller and Intel Atom processor.

# Test and Measurement Method

The function of UART is validated by sending message from SOC to TIVA to request the Intel temperature reading and getting the response from TIVA. Please refer to Section **5.2.6.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0021

Debug board Serial Number - WZ1628LIFE2DEBUG0018

Software versions – Linux 14.4.4

# Test Results

The UART interface between Tiva controller and Intel Atom processor is validated.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **TIVA- UART** | | | | | | | |
| NA | | | | | | | |

**The snapshots of Functional validation of UART interface between Tiva controller and Intel Atom processor are attached herewith.**

**  **

# Memory - DDR

# Test ID / Test Name: CPU.9.1 / Reference voltage measurement

# Purpose

The purpose of the test case is to measure the reference voltages of DDR (DDR\_VREF and DDR\_VTT).

# Test and Measurement Method

This test is conducted by probing the voltage at R2P7.1/R3P12.1 and C4P17.1 for DDR\_VREF and DDR\_VTT respectively. The measured reference values have to be in the range 0.64 - 0.725V. The VDDQ voltage has also been measured at C3P14.1 to validate the reference voltage (VREF = VDDQ/2, VDDQ = 1.35V). Please refer to Section **5.2.7.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0021

Software versions – NA

# Test Results

The voltage measured at DDR\_VREF and DDR\_VTT are in the range 0.64 - 0.725V.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| **Memory - DDR Reference voltage measurement** | | | | | | | |
| Test | Probing Point | Measured Voltage (V) | Expected Voltage(V) | Specification | | Design Margin (%) | Result |
| Min(V) | Max(V) |
| VDDQ | C3P14.1 | 1.33 | 1.35 | 1.28 | 1.45 | -3.90625 | PASS |
| VREF/DQ | R2P7.1 | 0.671 | 0.675 | 0.64 | 0.725 | -4.84375 | PASS |
| VREFCA | R3P12.1 | 0.671 | 0.675 | 0.64 | 0.725 | -4.84375 | PASS |
| VTT\_DDR | C4P17.1 | 0.657 | 0.675 | 0.64 | 0.725 | -2.65625 | PASS |

**The detailed analysis report with waveform captured for Reference voltage measurement test case is embedded in the xls document attached herewith.**



# Test ID / Test Name: CPU.9.2 / VREF Schmoo test

# Purpose

The purpose of the test case is to validate the DDR module by varying VREF voltage within the limits at different temperatures.

# Test and Measurement Method

This test is conducted by executing ‘memtester’ utility on SoC for different voltages of DDR\_VREF at different temperatures. DDR\_VREF can be varied by changing the voltage divide resistors, R2P11, R2P7, R3P6 and R3P12 such that there can be three co-ordinates within the specified range of DDR module. In each co-ordinate, memtester utility is executed at six different temperatures to validate VREF Schmoo. Please refer to Section **5.2.7.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Temperature – -20˚C to +70˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0002

Software versions – Linux 14.4.4 with memtester utility

# Test Results

The ‘memtester’ utility passes for various DDR\_VREF voltages under different temperature conditions.

# Measurement Logs

* + - 1. **Memory - DDR VREF measurement**

|  |  |  |  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **Memory - DDR VREF measurement** | | | | | | | | | | | |
| Sl. No. | Probing Point | Temperature Condition (°C) | Resistor Value (kΩ) - R2P7/R3P12 | Resistor Value (kΩ) - R2P11/R3P6 | Measured Voltage (V) | Expected Voltage (V) | Specification | | Design Margin (%) | Pass/Fail |
| Min (V) | Max (V) |
| 1 | R2P7 | -20 | 4.42 | 4.7 | 0.616 | 0.654 | 0.64 | 0.725 | 3.75 | FAIL |
| 2 | 0 | 4.42 | 4.7 | 0.631 | 0.654 | 0.64 | 0.725 | 1.41 | FAIL |
| 3 | 20 | 4.42 | 4.7 | 0.626 | 0.654 | 0.64 | 0.725 | 2.19 | FAIL |
| 4 | 25 | 4.42 | 4.75 | 0.662 | 0.651 | 0.64 | 0.725 | -3.44 | PASS |
| 5 | 40 | 4.42 | 4.7 | 0.611 | 0.654 | 0.64 | 0.725 | 4.53 | FAIL |
| 6 | 70 | 4.42 | 4.7 | 0.614 | 0.654 | 0.64 | 0.725 | 4.06 | FAIL |
| 7 | -20 | 4.99 | 4.7 | 0.671 | 0.695 | 0.64 | 0.725 | -4.84 | PASS |
| 8 | 0 | 4.99 | 4.7 | 0.659 | 0.695 | 0.64 | 0.725 | -2.97 | PASS |
| 9 | 20 | 4.99 | 4.7 | 0.663 | 0.695 | 0.64 | 0.725 | -3.59 | PASS |
| 10 | 25 | 4.99 | 4.7 | 0.708 | 0.695 | 0.64 | 0.725 | -2.34 | PASS |
| 11 | 40 | 4.99 | 4.7 | 0.66 | 0.695 | 0.64 | 0.725 | -3.13 | PASS |
| 12 | 70 | 4.99 | 4.7 | 0.66 | 0.695 | 0.64 | 0.725 | -3.13 | PASS |
| 13 | -20 | 5.11 | 4.42 | 0.693 | 0.724 | 0.64 | 0.725 | -4.41 | PASS |
| 14 | 0 | 5.11 | 4.42 | 0.686 | 0.724 | 0.64 | 0.725 | -5.38 | PASS |
| 15 | 20 | 5.11 | 4.42 | 0.681 | 0.724 | 0.64 | 0.725 | -6.07 | PASS |
| 16 | 25 | 5.11 | 4.42 | 0.718 | 0.724 | 0.64 | 0.725 | -0.97 | PASS |
| 17 | 40 | 5.11 | 4.42 | 0.679 | 0.724 | 0.64 | 0.725 | -6.09 | PASS |
| 18 | 70 | 5.11 | 4.42 | 0.689 | 0.724 | 0.64 | 0.725 | -4.97 | PASS |

**NOTE:** Reason for failure - Measurements have been taken placing the board in thermal chamber and the length of the wire soldered to the measuring points were very long which caused the drop and hence the failures.

* + - 1. **Memory - DDR VDDQ measurement**

|  |  |  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **Memory - DDR VDDQ measurement** | | | | | | | | | | |
| Sl. No. | Probing Point | Temperature Condition (°C) | Resistor Value (kΩ) - R2P7/R3P12 | Resistor Value (kΩ) - R2P11/R3P6 | Measured Voltage (V) | Expected Voltage (V) | Specification | | Design Margin (%) | Pass/Fail |
| Min (V) | Max (V) |
| 1 | C3P14 | -20 | 4.42 | 4.7 | 1.289 | 1.35 | 1.28 | 1.45 | -0.70 | PASS |
| 2 | 0 | 4.42 | 4.7 | 1.319 | 1.35 | 1.28 | 1.45 | -3.05 | PASS |
| 3 | 20 | 4.42 | 4.7 | 1.316 | 1.35 | 1.28 | 1.45 | -2.81 | PASS |
| 4 | 25 | 4.42 | 4.75 | 1.379 | 1.35 | 1.28 | 1.45 | -4.90 | PASS |
| 5 | 40 | 4.42 | 4.7 | 1.288 | 1.35 | 1.28 | 1.45 | -0.63 | PASS |
| 6 | 70 | 4.42 | 4.7 | 1.323 | 1.35 | 1.28 | 1.45 | -3.36 | PASS |
| 7 | -20 | 4.99 | 4.7 | 1.33 | 1.35 | 1.28 | 1.45 | -3.91 | PASS |
| 8 | 0 | 4.99 | 4.7 | 1.323 | 1.35 | 1.28 | 1.45 | -3.36 | PASS |
| 9 | 20 | 4.99 | 4.7 | 1.323 | 1.35 | 1.28 | 1.45 | -3.36 | PASS |
| 10 | 25 | 4.99 | 4.7 | 1.368 | 1.35 | 1.28 | 1.45 | -5.66 | PASS |
| 11 | 40 | 4.99 | 4.7 | 1.317 | 1.35 | 1.28 | 1.45 | -2.89 | PASS |
| 12 | 70 | 4.99 | 4.7 | 1.329 | 1.35 | 1.28 | 1.45 | -3.83 | PASS |
| 13 | -20 | 5.11 | 4.42 | 1.329 | 1.35 | 1.28 | 1.45 | -3.83 | PASS |
| 14 | 0 | 5.11 | 4.42 | 1.321 | 1.35 | 1.28 | 1.45 | -3.20 | PASS |
| 15 | 20 | 5.11 | 4.42 | 1.322 | 1.35 | 1.28 | 1.45 | -3.28 | PASS |
| 16 | 25 | 5.11 | 4.42 | 1.364 | 1.35 | 1.28 | 1.45 | -5.93 | PASS |
| 17 | 40 | 5.11 | 4.42 | 1.321 | 1.35 | 1.28 | 1.45 | -3.20 | PASS |
| 18 | 70 | 5.11 | 4.42 | 1.316 | 1.35 | 1.28 | 1.45 | -2.81 | PASS |

**The snapshot of execution of ‘memtester’ utility for VREF Schmoo test is attached herewith.**



**The detailed analysis report with waveform captured for VREF Schmoo test is embedded in the xls document attached herewith.**

****

# Test ID / Test Name: CPU.9.3 / Functional validation

# Purpose

The purpose of the test case is to validate the entire DDR memory using memtest option at boot stage.

# Test and Measurement Method

This test is conducted by executing memtest function during boot stage. The results of memtest are captured to check for any errors. Please refer to Section **5.2.7.4** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0021

Software versions – CoreBoot with memtest option

# Test Results

The memtest test is executed with zero errors.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **Memory - DDR** | | | | | | | |
| NA | | | | | | | |

**The snapshot of execution of memtest option for functional validation of DDR memory is attached herewith.**



# Test ID / Test Name: CPU.9.4 / Throughput measurement

# Purpose

The purpose of the test case is to validate the DDR memory for its latency and bandwidth.

# Test and Measurement Method

This test is conducted by running “make results see”.exe after unpacking the downloaded source code (lmbench 3.0). The results will be saved in lmbench directory. Read / Write throughputs which are read in Mbps data speed present in the last result columns. Please refer to Section **5.2.7.5** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0021

Software versions – Linux 14.4.4 with lmbench 3.0

# Test Results

The read / write throughputs are measured in Mbps. The throughput of Mem read and Mem write is 4414 MB/s and 2758 MB/s respectively.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **Memory – DDR ; Throughput measurement** | | | | | | | |
| NA | | | | | | | |

**The log of throughput measurement for DDR memory is attached herewith.**



# Memory SPI NOR Flash

# Test ID / Test Name: CPU.10.1 / Electrical validation

# Purpose

The purpose of the test case is to validate the electrical characteristics of SPI interface of SPI NOR Flash.

# Test and Measurement Method

This test is conducted by probing the SPI signal at R10762.2 (CLK), R1M11.2 (MISO) while system booting. The measured values should follow pass criteria, as specified in the below table. Please refer to Section **5.2.8.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0018

Software versions – Core boot

# Test Results

The Electrical characteristics of SPI interface of SPI NOR Flash is within the designed spec.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **SPI\_NOR\_Flash** | | | | | | | |
| SOC\_FLASH\_CLK | R10762 | VLOW (max) (V) | -4.47e-13 | -0.5 | 0.54 | 100.00 | PASS |
| VHIGH (min) (V) | 1.64 | 1.26 | 2.2 | -25.45 | PASS |
| Rise time (V/ns) | 0.1906 | 0.1 | 3 | -90.60 | PASS |
| Fall time (V/ns) | 0.1682 | 0.1 | 3 | -68.20 | PASS |
| Frequency (MHz) | 33.33 | 0 | 50 | -33.34 | PASS |
| SOC\_FLASH\_MISO | R10764 | VLOW (max) (V) | 0.02 | -0.5 | 0.54 | 104.00 | PASS |
| VHIGH (min) (V) | 1.82 | 1.26 | 2.2 | -17.27 | PASS |
| Rise time (V/ns) | 0.2028 | 0.1 | 3 | -93.24 | PASS |
| Fall time (V/ns) | 0.2025 | 0.1 | 3 | -93.25 | PASS |

**The detailed analysis report with waveform captured for SPI NOR Flash electrical validation test case is embed in the excel document attached herewith.**



# Test ID / Test Name: CPU.10.2 / Signal Integrity

# Purpose

The purpose of the test case is to validate the signal integrity of SPI interface of SPI NOR Flash.

# Test and Measurement Method

This test is conducted by probing the SPI signal at R10762.2 (CLK), R1M11.2 (MISO) while system booting. The measured values should follow pass criteria, as specified in the below table. Please refer to Section **5.2.8.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0018

Software versions – Core boot

# Test Results

The Signal integrity characteristics of SPI interface of SPI NOR Flash is within the designed spec.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| **SPI\_NOR\_Flash** | | | | | | | |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test Result |
| Min | Max |
| SOC\_FLASH\_CLK | R10762 | Positive Over-shoot (V) | 0.074 | 0 | 0.18 | -58.8889 | PASS |
| Negative Over-shoot (V) | 0.074 | 0 | 0.18 | -58.8889 | PASS |
| SOC\_SPI\_MISO | R1M11.2 | Positive Over-shoot (V) | 0.102 | 0 | 0.18 | -43.3333 | PASS |
| Negative Over-shoot (V) | 0.122 | 0 | 0.18 | -32.2222 | PASS |
| data set-up time (ns) | 13.7 | 2 | 100 | -86.3 | PASS |
| data hold time (ns) | 33 | 0 | 100 | -67 | PASS |

**NOTE:** Re-measurement taken by changing R1M11 from 22 Ohm to 49.9 Ohm to decrease Overshoot and Undershoot of MISO signal.

**The detailed analysis report with waveform captured for SPI NOR Flash electrical validation test case is embed in the excel document attached herewith.**



# Storage - mSATA

# Test ID / Test Name: CPU.11.1 / Signal Integrity

# Purpose

The purpose of the test case is to validate the signal integrity of mSATA signals by plotting the eye diagram.

# Test and Measurement Method

This test is conducted by plotting eye diagram of TX lines (SATA\_TXP0/N0) and RX lines (SATA\_RXN0/P0) and analyzing the eye characteristics as per mSATA standard. The TX lines are probed at C1833.1 and C1834.1. The RX lines are probed at C1835.2 and C1836.2. Please refer to Section **5.2.9.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0021

Software versions – Linux 14.4.4

# Test Results

The eye height fails for both mSATA TX and RX lines. All other parameters of mSATA TX and RX lines are within the specified limits.

# Measurement Logs

|  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- |
| Storage - mSATA Signal integrity -MSATA Transmit | | | | | | |
| Probing points | Parameters | Measured Value | Specification | | Design Margin (%) | Result |
| Min | Max |
| C1833.1 and C1834.1 | Eye jit RMS (ps) | 4.3 | NA | 100 | -95.70 | PASS |
| Eye Width (ps) | 304.858 | 166.66 | NA | -82.92 | PASS |
| Eye Height (mV) | 520.1 | 695.2 | NA | 25.19 | FAIL |
| Data TIE (ps) | 0.088 | -11 | 11 | 100.80 | PASS |
| Data Rate (Gb/s) | 3 | NA | 3 | 0.00 | PASS |
| Voltage peak to peak (mV) | 949.46 | 800 | NA | -18.68 | PASS |
|  |  |  |  |  |  |  |
| Storage - mSATA Signal integrity -MSATA Receive | | | | | | |
| Probing points | Parameters | Measured Value | Specification | | Design Margin | Result |
| Min | Max | (%) |
| C1835.2 and C1836.2 | Eye jit RMS (ps) | 11.436 | NA | 100 | -88.56 | PASS |
| Eye Width (ps) | 279.435 | 166.66 | NA | -67.67 | PASS |
| Eye Height (mV) | 304.2 | 695.2 | NA | 56.24 | FAIL |
| Data TIE (ps) | 0.512 | -11 | 11 | 104.65 | PASS |
| Data Rate (Gb/s) | 3.06 | NA | 3 | 2.00 | PASS |
| Voltage peak to peak (mV) | 1210.13 | 800 | NA | -51.27 | PASS |

**NOTE:** Failure Resolution: New mSATA drives are being planned for Rev C and SATA characteristics will be revalidated in Rev C.

**The detailed analysis report with waveform captured for Signal Integrity of mSATA memory is embedded in the xls document attached herewith**.



# Test ID / Test Name: CPU.11.2 / IO Stress

# Purpose

The purpose of the test case is to validate mSATA memory access when mSATA lines are under stress.

# Test and Measurement Method

This test is conducted by using FIO utility, which will stress the mSATA lines to their maximum performance. While they are under stress, mSATA memory should be accessible with no errors. Please refer to Section **5.2.9.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0002

Software versions – Linux 14.4.4 with FIO utility configured

# Test Results

FIO utility results show that there are no errors in accessing mSATA memory.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **Storage – mSATA** | | | | | | | |
| NA | | | | | | | |

**The snapshots of execution of FIO utility for validating IO Stress of mSATA memory is attached herewith.**

****

# SpringVille1 – PCIe

# Test ID / Test Name: CPU.13.1 and CPU.13.2 / Electrical Validation, Eye – plotting

# Purpose

The purpose of this test case is to check and validate the electrical parameters and signal integrity of PCIe interface between Intel processor (U3) and Springville1 (U2M1).

# Test and Measurement Method

* Transmitter Tests:

1. Remove Springville1 IC (U2M1). Terminate the Tx lane1 lines from Intel processor by mounting a 50-ohm resistor on pin no 23 and 24 of U2M1. By doing so, PCIe compliance pattern as per section *4.2.8* of PCIe base specification ver. *2.1* is generated.
2. Probe PCIE1\_TXP\_LAN and PCIE1\_TXN\_LAN at C2B30.1 and C2B29.1 respectively.
3. Run the test utility N5393D in the iminium oscilloscope. To configure the test suite, select PCIe version as 2.0, Transmitter tests, Device1, Lane1, and speed as 2.5GT/s. In select tests option in utility, select transmitter tests and run all the selected test cases.
4. The test utility generates the test report for all the test cases selected with the pass or fail criteria and its % margin.

* Receiver Tests:

1. Mount back Springville1 IC (U2M1). Terminate the Rx lane1 lines from Springville1 (U2M1) by lifting capacitor side C2M4.1 and C2M6.1 and terminating the line by mounting a 50-ohm resistor. By doing so, PCIe compliance pattern as per section *4.2.8* of PCIe base specification ver. *2.1* is generated.
2. Probe PCIE1\_RXP\_LAN and PCIE1\_RXN\_LAN at C2M4.1 and C2M6.1 respectively.
3. Run the test utility N5393D in the infiniium oscilloscope. To configure the test suite, select PCIe version as 2.0, Receiver tests, Device1, Lane1, and speed as 2.5GT/s. In select tests option in utility, select receiver tests and run all the selected test cases.
4. The test utility generates the test report for all the test cases selected with the pass or fail criteria and its % margin.

Please refer to Section **5.2.10** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature - 25˚C

Operating Voltage - +18V DC

System load –Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0018

Software version – NA

# Test Results

The test result generated by the test utility should be within the mentioned range in the PCIe Ver.*2.1* base specification.

# Measurement Logs

* Transmitter:

|  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- |
| **PCIe - Springville1 \_Transmitter Test** | | | | | | |
| **Sl. No** | **Test Name** | **Measured Value** | **Pass Margin** | | **% Pass Margin** | **PASS / FAIL** |
|  | |
| **Min** | **Max** |
| 1 | Unit Interval Test (UI) (ps) | 400.025 | 399.88 | 400.12 | 39.6 | PASS |
| 2 | Template Test | - | - | - | 100 | PASS |
| 3 | Median-to-Max jitter(ps) | 17.03 |  | 50 | 65.9 | PASS |
| 4 | Eye Width(mUI) | 891 | 750 |  | 18.8 | PASS |
| 5 | Peak Differential Output Voltage(Transition) (mV) | 923.5 | 800 | 1200 | 30.9 | PASS |
| 6 | Peak Differential Output Voltage (Non -Transition) (mV) | 682.7 | 504 | 1200 | 25.7 | PASS |
| 7 | Rise/Fall time (ps) | 78.13 | 50 |  | 56.3 | PASS |
| 8 | De-emphasized voltage ratio (dB) | -2.6 | -4.5 | -2.5 | 5 | PASS |
| 9 | RMS AC peak common mode voltage (mV) | 19.8 |  | 20 | 1 | PASS |
| 10 | Avg DC common mode voltage (mV) | 2.3 | 0 | 3600 | 0.1 | PASS |
| 11 | Avg DC common mode voltage output variation (mV) | 72.3 |  | 100 | 27.7 | PASS |
| 12 | Avg DC common mode line delta (mV) | 4.653 |  | 25 | 81.4 | PASS |

**The detailed analysis report for PCIe – springville1 transmitter test case executed is attached herewith.**



* Receiver:

|  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- |
| **PCIe - Springville1 \_Receiver Test** | | | | | | |
| **Sl. No** | **Test Name** | **Measured Value** | **Pass Margin** | | **% Pass Margin** | **PASS / FAIL** |
| **Min** | **Max** |
| 1 | Unit Interval Test (UI) (ps) | 400.028 | 399.88 | 400.12 | 38.3 | PASS |
| 2 | Template Test | - | - | - | 100 | PASS |
| 3 | Median-to-Max jitter(ps) | 18.7 |  | 120 | 84.4 | PASS |
| 4 | Eye Width(mUI) | 893 | 400 |  | 123.3 | PASS |
| 5 | Peak Differential Output Voltage (mV) | 225.2 | 175 | 1200 | 4.9 | PASS |
| 6 | RMS AC peak common mode input voltage (mV) | 57.3 |  | 150 | 61.8 | PASS |

**The detailed analysis report for PCIe – springville1 receiver test case executed is attached herewith.**



# SpringVille2 – PCIe

# Test ID / Test Name: CPU.14.1 and CPU14.2 / Electrical Validation, Eye – plotting

# Purpose

The purpose of this test case is to check and validate the electrical parameters and signal integrity of PCIe interface between Intel processor (U3) and Springville2 (U2M2).

# Test and Measurement Method

* Transmitter Tests:

1. Remove Springville2 IC (U2M2). Terminate the Tx lane2 lines from Intel processor by mounting a 50-ohm resistor on pin no 23 and 24 of U2M2. By doing so, PCIe compliance pattern as per section *4.2.8* of PCIe base specification ver. *2.1* is generated.
2. Probe PCIE2\_TXP\_LAN and PCIE2\_TXN\_LAN at C2B32.1 and C2B31.1 respectively.
3. Run the test utility N5393D in the infiniium oscilloscope. To configure the test suite, select PCIe version as 2.0, Transmitter tests, Device1, Lane2, and speed as 2.5GT/s. In select tests option in utility, select transmitter tests and run all the selected test cases.
4. The test utility generates the test report for all the test cases selected with the pass or fail criteria and its % margin.

* Receiver Tests:

1. Mount back Springville2 IC (U2M2). Terminate the Rx lane2 lines from Springville2 (U2M2) by lifting capacitor side C2M22.1 and C2M21.1 and terminating the line by mounting a 50-ohm resistor. By doing so, PCIe compliance pattern as per section *4.2.8* of PCIe base specification ver. *2.1* is generated.
2. Probe PCIE2\_RXP\_LAN and PCIE2\_RXN\_LAN at C2M22.1 and C2M21.1 respectively.
3. Run the test utility N5393D in the infiniium oscilloscope. To configure the test suite, select PCIe version as 2.0, Receiver tests, Device1, Lane2, and speed as 2.5GT/s. In select tests option in utility, select receiver tests and run all the selected test cases.
4. The test utility generates the test report for all the test cases selected with the pass or fail criteria and its % margin.

Please refer to Section **5.2.11** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature - 25˚C

Operating Voltage - +18V DC

System load –Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0018

Software version – NA

# Test Results

The test result generated by the test utility should be within the mentioned range in the PCIe Ver.*2.1* base specification.

# Measurement Logs

* Transmitter:

|  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- |
| **PCIe - Springville2 \_Transmitter Test** | | | | | | |
| **Sl. No** | **Test Name** | **Measured Value** | **Pass Margin** | | **% Pass / Fail Margin** | **PASS / FAIL** |
| **Min** | **Max** |
| 1 | Unit Interval Test (UI) (ps) | 400.025 | 399.88 | 400.12 | 39.6 | PASS |
| 2 | Template Test | - | - | - | -100 | FAIL |
| 3 | Median-to-Max jitter(ps) | 16.28 |  | 50 | 64.7 | PASS |
| 4 | Eye Width(mUI) | 899 | 750 |  | 19.9 | PASS |
| 5 | Peak Differential Output Voltage(Transition) (mV) | 861.8 | 800 | 1200 | 15.5 | PASS |
| 6 | Peak Differential Output Voltage (Non -Transition) (mV) | 639.6 | 504 | 1200 | 19.5 | PASS |
| 7 | Rise/Fall time (ps) | 60.31 | 50 |  | 20.6 | PASS |
| 8 | De-emphasized voltage ratio (dB) | -2.6 | -4.5 | -2.5 | 5 | PASS |
| 9 | RMS AC peak common mode voltage (mV) | 13.7 |  | 20 | 13.5 | PASS |
| 10 | Avg DC common mode voltage (mV) | 4.5 | 0 | 3600 | 0.1 | PASS |
| 11 | Avg DC common mode voltage output variation (mV) | 62.7 |  | 100 | 37.3 | PASS |
| 12 | Avg DC common mode line delta (mV) | 4.867 |  | 25 | 80.5 | PASS |

**NOTE:** This test will be re-performed in RevC by varying the de-emphasis settings.

**The detailed analysis report for PCIe – springville2 transmitter test case executed is attached herewith.**



* Receiver:

|  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- |
| **PCIe - Springville2 \_Receiver Test** | | | | | | |
| **Sl. No** | **Test Name** | **Measured Value** | **Pass Margin** | | **% Pass Margin** | **PASS / FAIL** |
| **Min** | **Max** |
| 1 | Unit Interval Test (UI) (ps) | 400.026 | 399.88 | 400.12 | 39.2 | PASS |
| 2 | Template Test | - | - | - | 100 | PASS |
| 3 | Median-to-Max jitter(ps) | 20.52 |  | 120 | 82.9 | PASS |
| 4 | Eye Width(mUI) | 799 | 400 |  | 99.8 | PASS |
| 5 | Peak Differential Output Voltage (mV) | 515.8 | 175 | 1200 | 33.2 | PASS |

**The detailed analysis report for PCIe – springville2 receiver test case executed is attached herewith.**



# TRXFE – GPIO

**NOTE:** CPU 15.1 cannot be done because the GPIO line is connected to Test points in RF-SDR board.

# Test ID / Test Name: CPU.15.2 / Control outputs functional validation

# Purpose

The purpose of the test case is to execute the control outputs functional validation of TRXFE- GPIO signals.

# Test and Measurement Method

This test is conducted by toggling the GPIO lines by using GPIO Sysfs Interface in Linux. Please refer to Section **5.2.12.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0010

Software versions – Linux 14.4.4

# Test Results

The toggling of TRXFE- GPIO signals is verified.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **TRXFE – GPIO: Control outputs** | | | | | | | |
| NA | | | | | | | |

**The snapshots of execution of Control outputs functional validation of TRXFE- GPIO are attached herewith**.

**  **

# Test ID / Test Name: CPU.15.3 / Signaling characteristics

# Purpose

The purpose of the test case is to validate the signal characteristics of TRXFE- GPIO signals.

# Test and Measurement Method

This test is conducted by probing the TRXFE - GPIO lines before level shifter at R10546, R10547, R10548 and R10549 and after level shifter at R10542, R10543, R10528 and R10529 respectively and verifying the signal characteristics. The GPIO lines are toggled using GPIO Sysfs Interface in Linux. Please refer to Section **5.2.12.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0010

Software versions – Linux 14.4.4

# Test Results

The signal characteristic of TRXFE- GPIO signals is within the requirement limits.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min(V) | Max(V) |
| **TRXFE - GPIO (Before Level Shifter)** | | | | | | | |
| SOC\_TRXFE\_GPIO1 | R10546 | VLOW (V) | 0 | 0 | 0.63 | -100.00 | PASS |
| VHIGH (V) | 1.8 | 1.17 | 1.8 | 0.00 | PASS |
| Positive Over-shoot (V) | 0 | 0 | 0.18 | -100.00 | PASS |
| Negative Over-shoot (V) | 0 | 0 | 0.18 | -100.00 | PASS |
| SOC\_TRXFE\_GPIO2 | R10547 | VLOW (V) | 0 | 0 | 0.63 | -100.00 | PASS |
| VHIGH (V) | 1.8 | 1.17 | 1.8 | 0.00 | PASS |
| Positive Over-shoot (V) | 0 | 0 | 0.18 | -100.00 | PASS |
| Negative Over-shoot (V) | 0 | 0 | 0.18 | -100.00 | PASS |
|  | R10548 | VLOW (V) | 0 | 0 | 0.63 | -100.00 | PASS |
| SOC\_TRXFE\_GPIO3 | VHIGH (V) | 1.8 | 1.17 | 1.8 | 0.00 | PASS |
| Positive Over-shoot (V) | 0 | 0 | 0.18 | -100.00 | PASS |
| Negative Over-shoot (V) | 0 | 0 | 0.18 | -100.00 | PASS |
| SOC\_TRXFE\_GPIO4 | R10549 | VLOW (V) | 0 | 0 | 0.63 | -100.00 | PASS |
| VHIGH (V) | 1.8 | 1.17 | 1.8 | 0.00 | PASS |
| Positive Over-shoot (V) | 0 | 0 | 0.18 | -100.00 | PASS |
| Negative Over-shoot (V) | 0 | 0 | 0.18 | -100.00 | PASS |
| **TRXFE - GPIO (After Level Shifter)** | | | | | | | |
| ISO\_SOC\_TRXFE\_GPIO1 | R10542 | VLOW (V) | 0 | -0.3 | 0.8 | 100.00 | PASS |
| VHIGH (V) | 3.3 | 2 | 3.6 | -8.33 | PASS |
| Positive Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| Negative Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| ISO\_SOC\_TRXFE\_GPIO2 | R10543 | VLOW (V) | 0 | -0.3 | 0.8 | 100.00 | PASS |
| VHIGH (V) | 3.3 | 2 | 3.6 | -8.33 | PASS |
| Positive Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| Negative Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| ISO\_SOC\_TRXFE\_GPIO3 | R10528 | VLOW (V) | 0 | -0.3 | 0.8 | 100.00 | PASS |
| VHIGH (V) | 3.3 | 2 | 3.6 | -8.33 | PASS |
| Positive Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| Negative Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| ISO\_SOC\_TRXFE\_GPIO4 | R10529 | VLOW (V) | 0 | -0.3 | 0.8 | 100.00 | PASS |
| VHIGH (V) | 3.3 | 2 | 3.6 | -8.33 | PASS |
| Positive Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| Negative Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |

**The detailed analysis report with waveform captured for Signaling characteristics of TRXFE- GPIO is embedded in the xls document attached herewith**.



# TIVA –GPIO

# Test ID / Test Name: CPU.17.1 / Control inputs functional validation

# Purpose

The purpose of the test case is to execute the control inputs functional validation of TIVA- GPIO signals.

# Test and Measurement Method

This test is conducted by toggling the GPIO lines from TIVA controller using CCS software and checking the status of the GPIO lines in SOC by using GPIO Sysfs Interface in Linux. Please refer to Section **5.2.13.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0010

Software versions – Linux 14.4.4

# Test Results

The toggling of TIVA- GPIO signals is verified.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **TIVA - GPIO: Control inputs** | | | | | | | |
| NA | | | | | | | |

**The snapshots of execution of control inputs functional validation of TIVA- GPIO is attached herewith**.

# Test ID / Test Name: CPU.17.2 / Control outputs functional validation

# Purpose

The purpose of the test case is to execute the control outputs functional validation of TIVA- GPIO signals.

# Test and Measurement Method

This test is conducted by toggling the GPIO lines by using GPIO Sysfs Interface in Linux. Please refer to Section **5.2.13.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0010

Software versions – Linux 14.4.4

# Test Results

The toggling of TIVA- GPIO signals is verified and TIVA\_SOC\_GPIO1 fails.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **TIVA - GPIO: Control outputs** | | | | | | | |
| NA | | | | | | | |

**The snapshots of execution of Control outputs functional validation of TIVA- GPIO is attached herewith**.

** **

# Test ID / Test Name: CPU.17.3 / Signaling characteristics

# Purpose

The purpose of the test case is to validate the signal characteristics of TIVA- GPIO signals.

# Test and Measurement Method

This test is conducted by probing the GPIO2 signal at R10514 before level shifter and at R10516 after level shifter and verifying the signal characteristics. The GPIO line is toggled using GPIO Sysfs Interface in Linux. Please refer to Section **5.2.13.4** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0010

Software versions – Linux 14.4.4

# Test Results

The signal characteristic of TIVA- GPIO signals is within the requirement limits.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min(V) | Max(V) |
| **TIVA\_GPIO (Before Level Shifter)** | | | | | | | |
| ISO\_TIVA\_SOC\_GPIO2 | R10514 | VLOW (V) | 0 | 0.00 | 0.63 | -100.00 | PASS |
| VHIGH (V) | 1.8 | 1.17 | 1.80 | 0.00 | PASS |
| Positive Over-shoot (V) | 0 | 0.00 | 0.18 | -100.00 | PASS |
| Negative Over-shoot (V) | 0 | 0.00 | 0.18 | -100.00 | PASS |
| **TIVA\_GPIO (After Level Shifter)** | | | | | | | |
| TIVA\_SOC\_GPIO2 | R10516 | VLOW (V) | 0 | 0.00 | 1.16 | -100.00 | PASS |
| VHIGH (V) | 3.3 | 2.15 | 4.00 | -17.50 | PASS |
| Positive Over-shoot (V) | 0.3 | 0.00 | 0.33 | -9.09 | PASS |
| Negative Over-shoot (V) | 0.1 | 0.00 | 0.33 | -69.70 | PASS |

**The detailed analysis report with waveform captured for signaling characteristics of TIVA- GPIO is embedded in the xls document attached herewith.**

****

# TRXFE- FX3 - USB 2.0

# Test ID / Test Name: CPU.19.1 / Electrical validation

# Purpose

The purpose of the test case is to validate the electrical characteristics of USB2.0 interface between GBC and RF-SDR.

# Test and Measurement Method

This test is conducted by probing the USB2.0 signal at R206.2 (USB\_DP0), R208.2 (USB\_DN0).Capture one frame of data (USB 2.0 signals) and save as .csv format. Then input this file to USBET20 tool. This will produces the familiar .html results files of the analysis. Please refer to Section **5.2.14.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0021

Debug board Serial Number - WZ1628LIFE2DEBUG0018

RF-SDR Board Serial Number - WZ1630LIFE2SDR0006

Software versions – Linux 14.4.4

# Test Results

The electrical characteristics of USB2.0 interface between GBC and RF-SDR is verified.

# Measurement Logs

**The detailed analysis report generated by “USBET20” tool for FX3-USB2.0 -** **Electrical validation is attached herewith.**

****

# Test ID / Test Name: CPU.19.2 / Throughput measurement

# Purpose

The purpose of the test case is to validate USB 2.0 throughput.

# Test and Measurement Method

This test is conducted by Installing the FX3 Utility and running the installation script. (./install.sh). The cyusb\_linux application is run. The process is started under the Data Transfers tab. Please refer to Section **5.2.14.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0021

Software versions – Linux 14.4.4 with cyusb\_linux application

# Test Results

The throughput of USB2.0 is 22.588 MB/s.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **USB 2.0 - Throughput measurement** | | | | | | | |
| NA | | | | | | | |

**The log of throughput measurement for USB 2.0 is attached herewith.**



# Test ID / Test Name: CPU.19.3 / Functional validation

# Purpose

The purpose of the test case is to validate USB 2.0 interface between GBC and RF-SDR board.

# Test and Measurement Method

This test is conducted by connecting debug board and RF-SDR board to GBC board and giving the command “**sudo uhd\_usrp\_probe**” in the terminal. Please refer to Section **5.2.14.4** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0021

Debug board Serial Number - WZ1628LIFE2DEBUG0018

RF-SDR Board Serial Number - WZ1630LIFE2SDR0006

Software versions – Linux 14.4.4

# Test Results

The functional validation of USB 2.0 interface between GBC and RF-SDR board is verified.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **TRXFE- FX3 - USB 2.0** | | | | | | | |
| NA | | | | | | | |

**The snapshot of functional validation of USB 2.0 interface between GBC and RF-SDR board is attached herewith**.

****

# TRXFE- FX3 - USB 3.0

# Test ID / Test Name: CPU.20.2 / Throughput measurement

# Purpose

The purpose of the test case is to validate USB 3.0 throughput.

# Test and Measurement Method

This test is conducted by Installing the FX3 Utility and running the installation script. (./install.sh). The cyusb\_linux application is run. The process is started under the Data Transfers tab after selecting streamer. Please refer to Section **5.2.15.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0021

Software versions – Linux 14.4.4 with cyusb\_linux application

# Test Results

The throughput of USB3.0 is 240.007 MB/s.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **USB 3.0 - Throughput measurement** | | | | | | | |
| NA | | | | | | | |

**The log of throughput measurement for USB 3.0 is attached herewith.**



# Test ID / Test Name: CPU.20.3 / Functional validation

# Purpose

The purpose of the test case is to validate USB 3.0 interface between GBC and RF-SDR board.

# Test and Measurement Method

This test is conducted by connecting debug board and RF-SDR board to GBC board and giving the command “**sudo uhd\_usrp\_probe**” in the terminal. Please refer to Section **5.2.15.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0021

Debug board Serial Number - WZ1628LIFE2DEBUG0018

RF-SDR Board Serial Number - WZ1630LIFE2SDR0006

Software versions – Linux 14.4.4

# Test Results

The functional validation of USB 3.0 interface between GBC and RF-SDR board is verified.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **TRXFE- FX3 - USB 3.0** | | | | | | | |
| NA | | | | | | | |

**The snapshot of functional validation of USB 3.0 interface between GBC and RF-SDR is attached herewith**.



# Debug USB 2.0

# Test ID / Test Name: CPU.21.1 / Functional validation

# Purpose

The purpose of the test case is to validate USB 2.0 in debug board.

# Test and Measurement Method

This test is conducted by connecting debug board to GBC board and connecting a USB 2.0 in debug board and giving the command “**lsusb –t**”/” **lsusb** -**v**” in the terminal. Please refer to Section **5.2.16** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0002

Debug board Serial Number - WZ1628LIFE2DEBUG001

Software versions – Linux 14.4.4

# Test Results

The functional validation of USB 2.0 in debug board is verified.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **Debug USB 2.0** | | | | | | | |
| NA | | | | | | | |

**The snapshots of functional validation of USB 2.0 in debug board are attached herewith**.



# Debug USB 3.0

# Test ID / Test Name: CPU.22.1 / Functional validation

# Purpose

The purpose of the test case is to validate USB 3.0 in debug board.

# Test and Measurement Method

This test is conducted by connecting debug board to GBC board. Board is turned on with CoreBoot loaded. Once Linux comes up, the USB3.0 signals at USB switch (U48) is routed to debug connector by toggling operation mode select pin of Mux/Demux switch (U48) using GPIO Sysfs Interface in Linux. A USB3.0 pen drive/HDD is connected to debug port and “lsusb –t” command is given in the terminal which shows the device is listed under USB3.0 Bus/Hub. This confirms that the USB3.0 enumeration is happening at GBC. Please refer to Section **5.2.17** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0002

Debug board Serial Number - WZ1628LIFE2DEBUG0018

Software versions – Linux 14.4.4

# Test Results

The functional validation of USB 3.0 in debug board is verified.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **Debug USB 3.0** | | | | | | | |
| NA | | | | | | | |

**The snapshots of functional validation of USB 3.0 in debug board are attached herewith**.



# Debug - Ethernet

# Test ID / Test Name: CPU.23.1 / Functional validation

# Purpose

The purpose of the test case is to validate Ethernet port in debug board.

# Test and Measurement Method

This test is conducted by connecting debug board to GBC board and connecting a PC to the Ethernet port of debug board. The connection between GBC system and the external PC is verified using “ping” command. Please refer to Section **5.2.18** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0002

Debug board Serial Number - WZ1628LIFE2DEBUG0018

Software versions – Linux 14.4.4

# Test Results

The functional validation of Ethernet port in debug board is verified.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **Debug - Ethernet** | | | | | | | |
| NA | | | | | | | |

**The snapshots of functional validation of Ethernet port in debug board are attached herewith**.

# Display-HDMI

# Test ID / Test Name: CPU.24.1 / Functional validation with debug port

# Purpose

The purpose of the test case is to validate HDMI port in debug board.

# Test and Measurement Method

This test is conducted by connecting debug board to GBC board and connecting a monitor to the HDMI port of debug board. Please refer to Section **5.2.19** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0002

Debug board Serial Number - WZ1628LIFE2DEBUG0018

Software versions – Linux 14.4.4

# Test Results

The functional validation of HDMI port in debug board is verified.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **Display-HDMI** | | | | | | | |
| NA | | | | | | | |

**The snapshots of functional validation of HDMI port in debug board are attached herewith**.

# Debug - UART

# Test ID / Test Name: CPU.25.1 / Functional validation

# Purpose

The purpose of the test case is to validate UART interface in debug board.

# Test and Measurement Method

This test is conducted by connecting debug board to GBC board and connecting a PC (with Docklight software) to the USB port (J1N4) of debug board. The Docklight software will be running in the PC. The Intel Atom processor sends boot log through the USB port to the PC during board power up. The data sent can be verified in the application software. Please refer to Section **5.2.20** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0002

Debug board Serial Number - WZ1628LIFE2DEBUG0018

Software versions – Linux 14.4.4

# Test Results

The functional validation of UART interface in debug board is verified.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **Debug-UART** | | | | | | | |
| NA | | | | | | | |

**The log of functional validation of UART interface in debug board is attached herewith**.



# RFSDR – PCIe

# Test ID / Test Name: CPU.26.1 and CPU26.2 / RFSDR-PCIe0

# Purpose

The purpose of this test case is to check and validate the electrical parameters and signal integrity of PCIe interface at 5GT/s between Intel processor (U3) and RFSDR board.

# Test and Measurement Method

* Transmitter Tests:

1. Terminate PCIe transmitter lane 0 lines with a 50-ohm resistor. By doing so, PCIe compliance pattern as per section *4.2.8* of PCIe base specification ver. *2.1* is generated.
2. For low power mode: voltage swing of PCIE signals from 600mV to 800V), modify bit 9:7 of “LCTL2\_LSTS2” register with offset 70h to 010b
3. From AWG (arbitrary waveform generator), generate bursts a 100MHz signal for 1ms duration. Connect the output of AWG to *PCIE0\_RXP.* This ensures the PCIe Tx lines to be transmitting data at 5GT/s speed.
4. Probe PCIE0\_TXP PCIE0\_TXN at C2000.1 and C1999.1 respectively.
5. Run the test utility N5393D in the infiniium oscilloscope. To configure the test suite, select PCIe version as 2.0, Transmitter tests, Device1, Lan01, and speed as 5GT/s. In select tests option in utility, select transmitter tests and run all the selected test cases.
6. The test utility generates the test report for all the test cases selected with the pass or fail criteria and its % margin.

Please refer to Section **5.2.21** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature - 25˚C

Operating Voltage - +18V DC

System load –Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0021

Software version – NA

# Test Results

The test result generated by the test utility should be within the mentioned range in the PCIe Ver.*2.1* base specification.

# Measurement Logs

|  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- |
| **PCIe0 - 5GT/s\_ -6dB Full power level - Writing to register 70h** | | | | | | |
| **Sl. No** | **Test Name** | **Measured Value** | **Pass Margin** | | **% Pass Margin** | **PASS / FAIL** |
| **Min** | **Max** |
| 1 | Unit Interval Test (UI) (ps) | 200.013 | 199.94 | 200.06 | 39.2 | PASS |
| 2 | Rise/Fall time (ps) | 50.63 | 30 | >30 | 68.8 | PASS |
| 3 | Tmin - Pulse(mUI) | 938 | 900 | >900 | 4.2 | PASS |
| 4 | Deemphasized Voltage Ratio -3.5dB (dB) | -2.8 | -4.5 | -2.5 | 15 | PASS |
| 5 | Deterministic Jitter > 1.5 MHz (mUI) | 32 | <150 | 150 | 78.7 | PASS |
| 6 | Random Jitter < 1.5 MHz(ps) | 1.72 | <3 | 3 | 42.7 | PASS |
| 7 | Template Test | - | - | - | 100 | PASS |
| 8 | Eye Width(mUI) | 846 | 750 | >750 | 12.8 | PASS |
| 9 | Peak Differential Output Voltage(Transition) (mV) | 722.9 | 400 | 1200 | 40.4 | PASS |
| 10 | Peak Differential Output Voltage (Non -Transition) (mV) | 523.4 |  | 1200 | 29.7 | PASS |

**The detailed analysis report for PCIe 0 – RFSDR transmitter test case executed for the above case is attached herewith.**



# TIVA

# TIVA Access

# Test ID / Test Name: TIV.1.1 / Configuration

# Purpose

The purpose of this test case is to access TIVA through JTAG and configuring with the help of CCS debug software.

# Test and Measurement Method

Connect debug board to a GBC board. To access CCS debug software, connect USB cable from host PC to connector J1N2 on debug board. Configure the debugger in CCS, and load the program onto TIVA (U72). Please refer to Section **6.2.1.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature - 25˚C

Operating Voltage - +18V DC

System load –Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0021

Software versions – TIVA RTOS code

# Test Results

Program is successfully loaded into TIVA through CCS debug software.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **TIVA Configuration** | | | | | | | |
| NA | | | | | | | |

** **

# Test ID / Test Name: TIV.1.2 / System Reset sequence

# Purpose

The purpose of the test case is to validate TIVA system reset sequence.

# Test and Measurement Method

This test is conducted by probing the signals “TIVA\_RESET\_TO\_PROC”, “TIVA\_ETHSW\_RESET”, “TIVA\_TRXFE\_RESET”, “TIVA\_SYNC\_RESET” at R10523, R10438, 0165 and R10519 respectively. The TIVA system reset sequence.is measured while resetting the system from TIVA controller. Please refer to Section **6.2.1.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0004

Debug board Serial Number - WZ1628LIFE2DEBUG0018

Software versions – TIVA RTOS code

# Test Results

TIVA system reset sequence is verified and is in the following order.

* + - 1. TIVA\_RESET\_TO\_PROC
      2. TIVA\_ETHSW\_RESET
      3. TIVA\_TRXFE\_RESET
      4. TIVA\_SYNC\_RESET

# Measurement Logs

|  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- |
| Sl.No | Measurement Points | Measured sequence | Specification | Design Margin (%) | Result |
| Expected sequence |
| TIVA system reset sequence | | | | | |
| 1 | R10523 | TIVA\_RESET\_TO\_PROC | TIVA\_RESET\_TO\_PROC | NA | PASS |
| 2 | R10438 | TIVA\_ETHSW\_RESET | TIVA\_ETHSW\_RESET |
| 3 | R10165 | TIVA\_TRXFE\_RESET | TIVA\_TRXFE\_RESET |
| 4 | R10519 | TIVA\_SYNC\_RESET | TIVA\_SYNC\_RESET |

**NOTE:** There is no time delay requirement for the System reset sequence.

**The detailed analysis report with waveform captured for TIVA system reset sequence is embedded in the xls document attached herewith.**



# PSE – I2C (LTC4274AIUHF)

# Test ID / Test Name: TIV.2.1 / Electrical validation

# Purpose

The purpose of the test case is to validate the electrical characteristics of I2C interface of PSE controller.

# Test and Measurement Method

This test is conducted by probing the I2C signal at U206.2 (TIVA\_PSE\_I2C8\_SDA) and U206.3 (TIVA\_PSE\_I2C8\_SCLK) before isolator, U206.7 (PSE\_I2CSDA) and U206.6 (PSE\_I2CSCL) after isolator on the GBC board. The measured values are well with-in the limit as specified in the I2C isolator and PSE datasheet specification. Please refer to Section **6.2.2.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0001

Software versions – TIVA RTOS code

# Test Results

The electrical characteristics of I2C interface with PSE is within the designed spec.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **PSE (Before Isolator)** | | | | | | |  |
| TIVA\_PSE\_I2C8\_SCLK | U206.3 | VLOW (max) (V) | 0 | 0 | 0.5 | -100.00 | PASS |
| VHIGH (min) (V) | 3.3 | 2.31 | 3.3 | 0.00 | PASS |
| Rise time (ns) | 964 | 0 | 1000 | -3.60 | PASS |
| Fall time (ns) | 32.8 | 0 | 300 | -89.07 | PASS |
| Frequency (kHz) | 96.15 | 0 | 100 | -3.85 | PASS |
| TIVA\_PSE\_I2C8\_SDA | U206.2 | VLOW (max) (V) | 0.26 | 0 | 0.5 | -48.00 | PASS |
| VHIGH (min) (V) | 3 | 2.31 | 3.3 | -9.09 | PASS |
| Rise time (ns) | 240 | 0 | 1000 | -76.00 | PASS |
| Fall time (ns) | 36.4 | 0 | 300 | -87.87 | PASS |
| **PSE (After Isolator)** | | | | | | |  |
| PSE\_I2CSCL | U206.6 | VLOW (max) (V) | -0.08 | -0.5 | 0.8 | 84.00 | PASS |
| VHIGH (min) (V) | 3.06 | 2.2 | 3.8 | -19.47 | PASS |
| Rise time (ns) | 492 | 0 | 1000 | -50.80 | PASS |
| Fall time (ns) | 49 | 0 | 300 | -83.67 | PASS |
| Frequency (kHz) | 96.9 | 0 | 100 | -3.10 | PASS |
| PSE\_I2CSDA | U206.7 | VLOW (max) (V) | -0.1 | -0.5 | 0.8 | 80.00 | PASS |
| VHIGH (min) (V) | 2.8 | 2.2 | 3.8 | -26.32 | PASS |
| Rise time (ns) | 488 | 0 | 1000 | -51.20 | PASS |
| Fall time (ns) | 47 | 0 | 300 | -84.33 | PASS |

**The detailed analysis report with waveform captured for PSE I2C - Electrical validation is embedded in the xls document attached herewith.**

****

# Test ID / Test Name: TIV.2.2 / Signal Integrity

# Purpose

The purpose of the test case is to validate the signal integrity of I2C interface of PSE controller.

# Test and Measurement Method

This test is conducted by probing the I2C signal at U206.2 (TIVA\_PSE\_I2C8\_SDA) and U206.3 (TIVA\_PSE\_I2C8\_SCLK) before isolator, U206.7 (PSE\_I2CSDA) and U206.6 (PSE\_I2CSCL) after isolator on the GBC board. The measured values are well with-in the limit as specified in the I2C isolator and PSE datasheet specification. Please refer to Section **6.2.2.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0001

Software versions – TIVA RTOS code

# Test Results

The Signal integrity characteristics of I2C interface with PSE is within the designed spec.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **PSE (Before Isolator)** | | | | | | |  |
| TIVA\_PSE\_I2C8\_SCLK | U206.3 | Positive Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| Negative Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| TIVA\_PSE\_I2C8\_SDA | U206.2 | data set-up time (ns) | 1750 | 240 | 10000 | -82.50 | PASS |
| data hold time (ns) | 2980 | 240 | 10000 | -70.20 | PASS |
| Positive Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| Negative Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| **PSE (After Isolator)** | | | | | | |  |
| PSE\_I2CSCL | U206.6 | Positive Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| Negative Over-shoot (V) | 0.16 | 0 | 0.33 | -51.52 | PASS |
| PSE\_I2CSDA | U206.7 | data set-up time (ns) | 2500 | 240 | 10000 | -75.00 | PASS |
| data hold time (ns) | 2980 | 240 | 10000 | -70.20 | PASS |
| Positive Over-shoot (V) | 0.18 | 0 | 0.33 | -45.45 | PASS |
| Negative Over-shoot (V) | 0.24 | 0 | 0.33 | -27.27 | PASS |

**The detailed analysis report with waveform captured for PSE I2C -** **Signal Integrity is embedded in the xls document attached herewith.**

****

# Test ID / Test Name: TIV.2.3 / Functional validation

# Purpose

The purpose of the test case is to validate the I2C interface of PSE controller.

# Test and Measurement Method

This test is conducted by reading I2C8 bus at address 2FH and read back the device ID 70H. Please refer to Section **6.2.2.4** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0001

Software versions – TIVA RTOS code

# Test Results

TIVA is able to read device ID from PSE device.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **PSE** | | | | | | | |
| NA | | | | | | | |

**The snapshot of functional validation of PSE I2C is attached herewith**.



# Power Monitor (INA226) – I2C

# Test ID / Test Name: TIV.3.1 / Electrical validation

# Purpose

The purpose of the test case is to validate the electrical characteristics of I2C interface of Power monitor IC.

# Test and Measurement Method

This test is conducted by probing the I2C signal at U182.5 (SCL), U182.4 (SDA). The measured values are well with-in the limit as specified in the INA226 power monitor datasheet specification. Please refer to Section **6.2.3.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0001

Software versions – TIVA RTOS code

# Test Results

The electrical characteristics of I2C interface of power monitor is within the designed spec.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **Power Monitor (INA226) - U185** | | | | | | | |
| TIVA\_PWRMNTR\_I2C6\_SCLK | U185.5 | VLOW (max) (V) | 0 | -0.5 | 0.99 | 100.00 | PASS |
| VHIGH (min) (V) | 3.3 | 2.31 | 6 | -42.86 | PASS |
| Rise time (ns) | 720 | 0 | 1000 | -28.00 | PASS |
| Fall time (ns) | 19.6 | 0 | 300 | -93.47 | PASS |
| Frequency (kHz) | 96.52 | 0 | 100 | -3.48 | PASS |
| TIVA\_PWRMNTR\_I2C6\_SDA | U185.4 | VLOW (max) (V) | 0 | -0.5 | 0.99 | 100.00 | PASS |
| VHIGH (min) (V) | 3.4 | 2.31 | 6 | -43.33 | PASS |
| Rise time (ns) | 704 | 0 | 1000 | -29.60 | PASS |
| Fall time (ns) | 52 | 0 | 300 | -82.67 | PASS |

**NOTE:**

1. Rise time and fall time passes for t70%-30%. Values are taken for t10%-90%.
2. Re-measurement taken by changing the pull-up value from 10K to 4.75K and Rise time and Fall time passes.

**The detailed analysis report with waveform captured for Power Monitor I2C -** **Electrical validation is embedded in the xls document attached herewith.**



# Test ID / Test Name: TIV.3.2 / Signal Integrity

# Purpose

The purpose of the test case is to validate the signal integrity of I2C interface of Power monitor IC.

# Test and Measurement Method

This test is conducted by probing the I2C signal at U182.5 (SCL), U182.4 (SDA). The measured values are well with-in the limit as specified in the I2C specification standard, please refer to Section **6.2.3.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0001

Software versions – TIVA RTOS code

# Test Results

The Signal integrity characteristics of I2C interface with Current and Power monitor IC is within the designed spec.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **Power Monitor (INA226) - U185** | | | | | | | |
| TIVA\_PWRMNTR\_I2C6\_SCLK | U185.5 | Positive Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| Negative Over-shoot (V) | 0.3 | 0 | 0.33 | -9.09 | PASS |
| TIVA\_PWRMNTR\_I2C6\_SDA | U185.4 | data set-up time (ns) | 1700 | 250 | 10000 | -83.00 | PASS |
| data hold time (ns) | 3000 | 300 | 10000 | -70.00 | PASS |
| Positive Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| Negative Over-shoot (V) | 0.12 | 0 | 0.33 | -63.64 | PASS |

**The detailed analysis report with waveform captured for Power Monitor I2C - Signal Integrity is embedded in the xls document attached herewith.**



# Test ID / Test Name: TIV.3.3 / Functional validation

# Purpose

The purpose of the test case is to validate the I2C interface of Power monitor IC.

# Test and Measurement Method

This test is conducted by reading I2C6 bus at address 40H and Manufacture ID, 5449 is read from Address FEh. Please refer to Section **6.2.3.4** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0001

Software versions – TIVA RTOS code

# Test Results

TIVA is able to access the power monitor through I2C bus and read Manufacture ID from the device.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **Power Monitor** | | | | | | | |
| NA | | | | | | | |

**The snapshots of functional validation of Power Monitor are attached herewith**.



# RF-SDR board – I2C (PCA9557PW,118)

# Test ID / Test Name: TIV.4.1 / Electrical validation

# Purpose

The purpose of the test case is to validate the electrical characteristics of I2C interface of IO expander in RF-SDR board.

# Test and Measurement Method

This test is conducted by probing the I2C signal at R1089.2 and R2034 (SCL), R1088.2 and R2033 (SDA) at RF SDR Board while it’s integrated with GBC board. The measured values are well with-in the limit as specified in the PCA9557 IO expander datasheet specification. Please refer to Section **6.2.4.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0001

Software versions – TIVA RTOS code

# Test Results

The electrical characteristics of I2C interface with IO expander is within the designed spec.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **RF-SDR IO Exp- I2C (Before Level Shifter)** | | | | | | | |
| TIVA\_TRXFECONN\_I2C2\_SCLK | R1089.2 | VLOW (max) (V) | 0 | -0.5 | 0.99 | 100.00 | PASS |
| VHIGH (min) (V) | 3.3 | 2.31 | 5.5 | -40.00 | PASS |
| Rise time (ns) | 216 | 0 | 300 | -28.00 | PASS |
| Fall time (ns) | 2.3 | 0 | 300 | -99.23 | PASS |
| Frequency (kHz) | 357.1 | 0 | 400 | -10.73 | PASS |
| TIVA\_TRXFECONN\_I2C2\_SDA | R1088.2 | VLOW (max) (V) | 0 | -0.5 | 0.99 | 100.00 | PASS |
| VHIGH (min) (V) | 3.3 | 2.31 | 5.5 | -40.00 | PASS |
| Rise time (ns) | 244 | 0 | 300 | -18.67 | PASS |
| Fall time (ns) | 2.8 | 0 | 300 | -99.07 | PASS |
| **RF-SDR IO Exp- I2C (After Level Shifter)** | | | | | | | |
| SYS\_I2C\_2\_SCL | R2034 | VLOW (max) (V) | 0.4 | -0.5 | 0.99 | 180.00 | PASS |
| VHIGH (min) (V) | 2.8 | 2.31 | 5.5 | -21.21 | PASS |
| Rise time (ns) | 56 | 0 | 300 | -81.33 | PASS |
| Fall time (ns) | 35 | 0 | 300 | -88.33 | PASS |
| Frequency (kHz) | 357.1 | 0 | 400 | -10.73 | PASS |
| SYS\_I2C\_2\_SDA | R2033 | VLOW (max) (V) | 0.4 | -0.5 | 0.99 | 180.00 | PASS |
| VHIGH (min) (V) | 2.8 | 2.31 | 5.5 | -21.21 | PASS |
| Rise time (ns) | 64 | 0 | 300 | -78.67 | PASS |
| Fall time (ns) | 42 | 0 | 300 | -86.00 | PASS |

**The detailed analysis report with waveform captured for RF SDR IO Expander I2C - Electrical validation is embedded in the xls document attached herewith.**

****

# Test ID / Test Name: TIV.4.2 / Signal Integrity

# Purpose

The purpose of the test case is to validate the signal integrity of I2C interface of IO expander in RF-SDR board.

# Test and Measurement Method

This test is conducted by probing the I2C signal at R1089.2 and R2034 (SCL), R1088.2 and R2033 (SDA) at RF SDR Board. The measured values are well with-in the limit as specified in the PCA9557 IO expander datasheet specification. Please refer to Section **6.2.4.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0001

Software versions – TIVA RTOS code

# Test Results

The Signal integrity characteristics of I2C interface with IO expander is within the designed spec.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **RF-SDR IO Exp (Before Level Shifter)** | | | | | | | |
| TIVA\_TRXFECONN\_I2C2\_SCLK | R1089.2 | Positive Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| Negative Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| TIVA\_TRXFECONN\_I2C2\_SDA | R1088.2 | data set-up time (ns) | 456 | 100 | 2500 | -81.76 | PASS |
| data hold time (ns) | 548 | 300 | 2500 | -78.08 | PASS |
| Positive Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| Negative Over-shoot (V) | 0.1088 | 0 | 0.33 | -67.03 | PASS |
| **RF-SDR IO Exp (After Level Shifter)** | | | | | | | |
| SYS\_I2C\_2\_SCL | R2034 | Positive Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| Negative Over-shoot (V) | 0.22 | 0 | 0.33 | -33.33 | PASS |
| SYS\_I2C\_2\_SDA | R2033 | data set-up time (ns) | 664 | 100 | 2500 | -73.44 | PASS |
| data hold time (ns) | 330 | 300 | 2500 | -10.00 | PASS |
| Positive Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| Negative Over-shoot (V) | 0.22 | 0 | 0.33 | -33.33 | PASS |

**The detailed analysis report with waveform captured for RF SDR IO Expander I2C - Signal Integrity is embedded in the xls document attached herewith.**

****

# Test ID / Test Name: TIV.4.3 / Functional validation

# Purpose

The purpose of the test case is to validate the I2C interface of IO expander in RF-SDR board.

# Test and Measurement Method

This test is conducted by reading I2C2 bus and writing data in input register. Register 0x3 is written with value 0xfe (slave address 0x1b) and Register 0x1 is written with value 0xaa (slave address 0x1e). Please refer to Section 6.2.4.4 in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0001

Software versions – TIVA RTOS code

# Test Results

TIVA is able to write data in input register of IO expander.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **RF SDR IO Exp** | | | | | | | |
| NA | | | | | | | |

**The snapshot of functional validation of IO Expander in RF-SDR Board is attached herewith**.



# Temp Sensor (SE98ATP, 547) – I2C

# Test ID / Test Name: TIV.5.1 / Electrical validation

# Purpose

The purpose of the test case is to validate the electrical characteristics of I2C interface of temperature sensor.

# Test and Measurement Method

This test is conducted by probing the I2C signal at R10255.2/ R10221.2 (SCL), R10256.2/ R10222.2 (SDA). The measured values are well with-in the limit as specified in the SE98ATP, 547 Temp sensor datasheet specification. Please refer to Section **6.2.5.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0001

Software versions – TIVA RTOS code

# Test Results

The electrical characteristics of I2C interface of temperature sensor is within the designed spec.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **Temp Sensor - U215 (Near Tiva)** | | | | | | | |
| TIVA\_TEMPSEN\_I2C1\_SCLK | R10255.2 | VLOW (max) (V) | 0 | -0.5 | 0.99 | 100.00 | PASS |
| VHIGH (min) (V) | 3.4 | 2.31 | 4.3 | -20.93 | PASS |
| Rise time (ns) | 570 | 0 | 1000 | -43.00 | PASS |
| Fall time (ns) | 16 | 0 | 300 | -94.67 | PASS |
| Frequency (kHz) | 94.34 | 0 | 100 | -5.66 | PASS |
| TIVA\_TEMPSEN\_I2C1\_SDA | R10256.2 | VLOW (max) (V) | 0 | -0.5 | 0.99 | 100.00 | PASS |
| VHIGH (min) (V) | 3.4 | 2.31 | 4.3 | -20.93 | PASS |
| Rise time (ns) | 600 | 0 | 1000 | -40.00 | PASS |
| Fall time (ns) | 16 | 0 | 300 | -94.67 | PASS |
| **Temp Sensor - U210 (Far from Tiva)** | | | | | | | |
| TIVA\_TEMPSEN\_I2C1\_SCLK | R10221.2 | VLOW (max) (V) | 0 | -0.5 | 0.99 | 100.00 | PASS |
| VHIGH (min) (V) | 3.3 | 2.31 | 4.3 | -23.26 | PASS |
| Rise time (ns) | 570 | 0 | 1000 | -43.00 | PASS |
| Fall time (ns) | 18 | 0 | 300 | -94.00 | PASS |
| Frequency (kHz) | 94.34 | 0 | 100 | -5.66 | PASS |
| TIVA\_TEMPSEN\_I2C1\_SDA | R10222.2 | VLOW (max) (V) | 0 | -0.5 | 0.99 | 100.00 | PASS |
| VHIGH (min) (V) | 3.3 | 2.31 | 4.3 | -23.26 | PASS |
| Rise time (ns) | 600 | 0 | 1000 | -40.00 | PASS |
| Fall time (ns) | 36 | 0 | 300 | -88.00 | PASS |

**The detailed analysis report with waveform captured for Temp Sensor I2C - Electrical validation is embedded in the xls document attached herewith**.



# Test ID / Test Name: TIV.5.2 / Signal Integrity

# Purpose

The purpose of the test case is to validate the signal integrity of I2C interface of temperature sensor.

# Test and Measurement Method

This test is conducted by probing the I2C signal at R10255.2/ R10221.2 (SCL), R10256.2/ R10222.2 (SDA). The measured values are well with-in the limit as specified in the I2C specification standard, but need tweaking the layout design for better HOLD time. Please refer to Section **6.2.5.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0001

Software versions – TIVA RTOS code

# Test Results

The Signal integrity characteristics of I2C interface with temperature sensor is within the designed spec except the Hold time which needs tweaking in layout design in next version.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **Temp Sensor - U215 (Near Tiva)** | | | | | | | |
| TIVA\_TEMPSEN\_I2C1\_SCLK | R10255.2 | Positive Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| Negative Over-shoot (V) | 0.2 | 0 | 0.33 | -39.39 | PASS |
| TIVA\_TEMPSEN\_I2C1\_SDA | R10256.2 | data set-up time (ns) | 2460 | 250 | 10000 | -75.40 | PASS |
| data hold time (ns) | 3000 | 200 | 3450 | -13.04 | PASS |
| Positive Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| Negative Over-shoot (V) | 0.3 | 0 | 0.33 | -9.09 | PASS |
| **Temp Sensor - U210 (Far from Tiva)** | | | | | | | |
| TIVA\_TEMPSEN\_I2C1\_SCLK | R10221.2 | Positive Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| Negative Over-shoot (V) | 0.3 | 0 | 0.33 | -9.09 | PASS |
| TIVA\_TEMPSEN\_I2C1\_SDA | R10222.2 | data set-up time (ns) | 2460 | 250 | 10000 | -75.40 | PASS |
| data hold time (ns) | 3000 | 200 | 3450 | -13.04 | PASS |
| Positive Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| Negative Over-shoot (V) | 0.2 | 0 | 0.33 | -39.39 | PASS |

**The detailed analysis report with waveform captured for Temp Sensor I2C - Signal Integrity is embedded in the xls document attached herewith**.



# Test ID / Test Name: TIV.5.3 / Functional validation

# Purpose

The purpose of the test case is to validate the I2C interface of temperature sensor.

# Test and Measurement Method

This test is conducted by reading I2C1 bus at address 18H, 19F, 1AH, 1CH, 1DH and 1FH. The Device ID is read from register 0x6 with value 0x1131. The Manufacture ID is read from register 0x7 with value 0xa102. Please refer to Section **6.2.5.4** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0001

Software versions – TIVA RTOS code

# Test Results

TIVA is able to access the temperature sensor through I2C bus and read manufacture ID from the device.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **Temp Sensor** | | | | | | | |
| NA | | | | | | | |

**The snapshots of functional validation of temperature sensor are attached herewith**.

# Sync Board I2C (PCA9557PW,118)

# Test ID / Test Name: TIV.6.1 / Electrical Validation

# Purpose

The purpose of the test case is to validate the electrical characteristics of I2C interface of GPIO Expander in sync board.

# Test and Measurement Method

This test is conducted by probing the I2C signal at U1.1-SCL (Near Via), U1.2-SDA (Near Via). The measured values are well with-in the limit as specified in the PCA9557PW,118 GPIO Expander datasheet specification. Please refer to Section **6.2.6.2** of ‘SYNC Board’ Test specifications (Rev 0.1) for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number- WZ1630LIFE2GBC0006

SYNC Board Serial Number- WZ1627LIFE1SYNC0011

Software versions – TIVA RTOS code

# Test Results

The electrical characteristics of I2C interface with GPIO Expander is within the designed specification.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **Sync board – I2C (PCA9557PW,118)** | | | | | | | |
| TIVA\_SYNCCONN\_I2C7\_SCLK | U1.1 | VLOW (max) (V) | -0.2 | -0.5 | 0.99 | 60.00 | PASS |
| VHIGH (min) (V) | 3.2 | 2.31 | 5.5 | -38.53 | PASS |
| Rise time (ns) | 450 | 0 | 1000 | -55.00 | PASS |
| Fall time (ns) | 5.6 | 0 | 300 | -98.13 | PASS |
| Frequency (kHz) | 90.9 | 0 | 100 | -9.10 | PASS |
| TIVA\_SYNCCONN\_I2C7\_SDA | U1.2 | VLOW (max) (V) | 0 | -0.5 | 0.99 | 100.00 | PASS |
| VHIGH (min) (V) | 3.3 | 2.31 | 5.5 | -40.00 | PASS |
| Rise time (ns) | 450 | 0 | 1000 | -55.00 | PASS |
| Fall time (ns) | 39 | 0 | 300 | -87.00 | PASS |

**The detailed analysis report with waveform captured for Sync board I2C - Electrical validation is embedded in the xls document attached herewith**.



# Test ID / Test Name: TIV.6.2 / Signal Integrity

# Purpose

The purpose of the test case is to validate the electrical characteristics of I2C interface of GPIO Expander in sync board.

# Test and Measurement Method

This test is conducted by probing the I2C signal at U1.1-SCL (Near Via), U1.2-SDA (Near Via). The measured values are well with-in the limit as specified in the PCA9557PW,118 GPIO Expander datasheet specification. Please refer to Section **6.2.6.3** of ‘SYNC Board’ Test specifications (Rev 0.1) for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number- WZ1630LIFE2GBC0006

SYNC Board Serial Number- WZ1627LIFE1SYNC0011

Software versions – TIVA RTOS code

# Test Results

The Signal Integrity characteristics of I2C interface with GPIO Expander is within the designed specification.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **Sync board – I2C (PCA9557PW,118)** | | | | | | | |
| TIVA\_SYNCCONN\_I2C7\_SCLK | U1.1 | Positive Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| Negative Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| TIVA\_SYNCCONN\_I2C7\_SDA | U1.2 | data set-up time (ns) | 2520 | 250 | 10000 | -74.80 | PASS |
| data hold time (ns) | 296 | 0 | 10000 | -97.04 | PASS |
| Positive Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| Negative Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |

**The detailed analysis report with waveform captured for Sync board I2C - Signal Integrity is embedded in the xls document attached herewith**.



# Test ID / Test Name: TIV.6.3 / Functional Validation

# Purpose

The purpose of the test case is to validate the I2C interface of GPIO expander in sync board.

# Test and Measurement Method

This test is conducted by reading I2C7 bus at address 1FH. Input register data, 0x3 is written with value 0x1f. Please refer to Section **6.2.6.4** of ‘SYNC Board’ Test specifications (Rev 0.1) for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number- WZ1630LIFE2GBC0006

SYNC Board Serial Number- WZ1627LIFE1SYNC0011

Software versions – TIVA RTOS code

# Test Results

TIVA is able to write data in input register of GPIO Expander in Sync board.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **Sync board** | | | | | | | |
| NA | | | | | | | |

**The snapshot of functional validation of GPIO Expander in SYNC Board is attached herewith**.



# LED board – I2C (SX1509BIULTRT)

# Test ID / Test Name: TIV.7.1 / Electrical validation

# Purpose

The purpose of the test case is to validate the electrical characteristics of I2C interface of GPIO Expander in LED board.

# Test and Measurement Method

This test is conducted by probing the I2C signal at R24.2 (SCL), R23.2 (SDA) at LED board while it’s integrated with GBC board. The measured values are well with-in the limit as specified in the SX1509BIULTRT GPIO Expander datasheet specification. Please refer to Section **6.2.7.2** of ‘LED Board’ Test specifications (Rev 0.1) for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0006

Software versions – TIVA RTOS code

# Test Results

The electrical characteristics of I2C interface with GPIO Expander is within the designed spec.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **LED board – I2C (SX1509BIULTRT)** | | | | | | | |
| LED\_I2C\_SCL | U1.25 | VLOW (max) (V) | 0 | -0.4 | 0.99 | 100.00 | PASS |
| VHIGH (min) (V) | 3.3 | 2.31 | 3.3 | 0.00 | PASS |
| Rise time (ns) | 630 | 0 | 1000 | -37.00 | PASS |
| Fall time (ns) | 30.4 | 0 | 300 | -89.87 | PASS |
| Frequency (kHz) | 83.33 | 0 | 100 | -16.67 | PASS |
| LED\_I2C\_SDA | U1.24 | VLOW (max) (V) | 0.2 | -0.4 | 0.99 | 150.00 | PASS |
| VHIGH (min) (V) | 3 | 2.31 | 3.3 | -9.09 | PASS |
| Rise time (ns) | 760 | 0 | 1000 | -24.00 | PASS |
| Fall time (ns) | 60 | 0 | 300 | -80.00 | PASS |

**The detailed analysis report with waveform captured for LED board I2C - Electrical validation is embedded in the xls document attached herewith**.

****

# Test ID / Test Name: TIV.7.2 / Signal Integrity

# Purpose

The purpose of the test case is to validate the Signal characteristics of I2C interface of GPIO Expander in LED board.

# Test and Measurement Method

This test is conducted by probing the I2C signal at R24.2 (SCL), R23.2 (SDA). The measured values are well with-in the limit as specified in the SX1509BIULTRT GPIO Expander datasheet specification. Please refer to Section **6.2.7.3** of ‘LED Board’ Test specifications (Rev 0.1) for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0006

Software versions – TIVA RTOS code

# Test Results

The Signal Integrity characteristics of I2C interface with GPIO Expander is within the designed spec.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **LED board – I2C (SX1509BIULTRT)** | | | | | | | |
| LED\_I2C\_SCL | U1.25 | Positive Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| Negative Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| LED\_I2C\_SDA | U1.24 | data set-up time (ns) | 2760 | 250 | 10000 | -72.40 | PASS |
| data hold time (ns) | 3600 | 300 | 10000 | -64.00 | PASS |
| Positive Over-shoot (V) | 0 | 0 | 0.33 | -100.00 | PASS |
| Negative Over-shoot (V) | 0.3 | 0 | 0.33 | -9.09 | PASS |

**The detailed analysis report with waveform captured for LED board I2C - Signal Integrity is embedded in the xls document attached herewith**.

****

# Test ID / Test Name: TIV.7.3 / Functional validation

# Purpose

The purpose of the test case is to validate the I2C interface of GPIO Expander in LED board.

# Test and Measurement Method

This test is conducted by reading I2C8 bus at address 3EH. Register REG\_CLOCK is read with 0x0 and REG\_MISC is read with 0x24. Please refer to Section **6.2.7.3** of ‘LED Board’ Test specifications (Rev 0.1) for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0006

Software versions – TIVA RTOS code

# Test Results

TIVA is able to registers of GPIO expander in LED board.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **LED board** | | | | | | | |
| NA | | | | | | | |

**The snapshot of functional validation of GPIO Expander in LED Board is attached herewith**.



# TIVA GPIO

# Test ID / Test Name: TIV.10.1 / Control inputs functional validation

# Purpose

The purpose of the test case is to execute the control inputs functional validation of TIVA- GPIO signals.

# Test and Measurement Method

This test is conducted by toggling the GPIO lines which are input to TIVA through hardware. Please refer to Section **6.2.8** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0018

Software versions – NA

# Test Results

Some TIVA- GPIO signals are toggling and some are not toggling.

**NOTE:** Resolution for failure – This is due to the design issue and this will be updated in the next version.

# Measurement Logs

**The list of result of control inputs functional validation of TIVA- GPIO is attached herewith**.



# TIVA GPIO

# Test ID / Test Name: TIV.11.1 / Control outputs functional validation

# Purpose

The purpose of the test case is to execute the control outputs functional validation of TIVA- GPIO signals.

# Test and Measurement Method

This test is conducted by toggling the GPIO lines which are output from TIVA by software control using CCS. Please refer to Section **6.2.9** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0018

Software versions – TIVA RTOS code

# Test Results

Some TIVA- GPIO signals are toggling and some are not toggling.

**NOTE:** Resolution for failure – This is due to the design issue and this will be updated in the next version.

# Measurement Logs

**The list of result of Control outputs functional validation of TIVA- GPIO is attached herewith**.

****

# ETH SW MGMT Interface

# Test ID / Test Name: TIV.12.1 / Functional validation

# Purpose

The purpose of the test case is to validate the TIVA in order to control and configure the Marvell switch.

# Test and Measurement Method

This test is conducted by accessing two GPIOs (PC6- MDC, PC7-MDIO) of TIVA which are connected to Marvell switch(88E6071)’s MDC/MDIO and read back the device ID 0141H. Please refer to Section **6.2.10** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0001

Software versions – TIVA RTOS code

# Test Results

TIVA is able to read device ID from Marvell device.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **ETH SW MGMT Interface** | | | | | | | |
| NA | | | | | | | |

**The snapshot of functional validation of Marvell switch is attached herewith**.



# Ethernet:

# PoE (PD) - MDI

# Test ID / Test Name: ETH.1.1/ Electrical Validation

# Purpose

The purpose of this test case is to verify MDI (interface between [Marvell](http://www.marvell.com/switching/link-street/)Switch (88E6071) to POE (PD port)) signal characteristics.

# Test and Measurement Method

This test is conducted by connecting a Linux PC to port A (PD port) of GBC board and starting communication between them by pinging each other. The MDI transmitting signals (from Port to Switch) are measured at J1A.1 (TXP) and J1A.2 (TXN) and MDI receiving signals (from Switch to Port) are measured at J1A.3 (RXP) and J1A.6 (RXN). Please refer to Section **7.2.1.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0007

Software versions – Linux 14.4.4

# Test Results

The signal characteristics of MDI signals are as per the specification and the data rate is 100Mbps.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| **PoE(PD) - MDI** | | | | | | | |
| LANSW\_ETHSW\_P1\_TXP, LANSW\_ETHSW\_P1\_TXN | J1A.1, J1A.2 | Vp-p (V) | 2.45 | 1.9 | 2.63 | -6.84 | PASS |
| Overshoot (%) | 3.05 | 0 | 10 | -69.50 | PASS |
| Undershoot (%) | 3.025 | 0 | 10 | -69.75 | PASS |
| Data rate (Mbps) | 100 | NA | 100 | 0.00 | PASS |
| ETHSW\_LANSW\_P1\_RXP, ETHSW\_LANSW\_P1\_RXN | J1A.3, J1A.6 | Vp-p (V) | 2.1 | 1.9 | 2.63 | -10.53 | PASS |
| Overshoot (%) | 1.247 | 0 | 10 | -87.53 | PASS |
| Undershoot (%) | 1.217 | 0 | 10 | -87.83 | PASS |
| Data rate (Mbps) | 100 | NA | 100 | 0.00 | PASS |

**The detailed analysis report with waveform captured for signal characteristics of PoE (PD) MDI test case is embedded in the xls document attached herewith.**

****

# Test ID / Test Name: ETH.1.2/ Functional validation

# Purpose

The purpose of the test case is to validate the function of PoE (PD) - MDI.

# Test and Measurement Method

This test is conducted by connecting a Linux PC to port A of GBC board and starting communication between them by giving command “ping IPaddress (IP address of Linux PC)” in the terminal of GBC system and “ping IPaddress (IP address of GBC system)” in Linux PC. Please refer to Section **7.2.1.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0007

Software versions – Linux 14.4.4

# Test Results

Communication is established between Port and Marvell switch through MDI interface over 100Mbps data rate.

**The snapshot of functional validation of Springville MDI is attached herewith.**

**  **

# TIVA Ethernet

# Test ID / Test Name: ETH.3.1/ Electrical Validation

# Purpose

The purpose of this test case is to verify the electrical parameters between [Marvell](http://www.marvell.com/switching/link-street/)Switch (88E6071) to TIVA.

# Test and Measurement Method

This test is conducted by connecting a debug board to GBC. Ethernet cable from PC to port A (PD port) of GBC board. Flash the relevant code to TIVA so that signals between Port 0 of marvell switch and TIVA are initiated. The transmitting signals (from Port to Switch) are measured at T10.16 (TXP) and T10.14 (TXN) and receiving signals (from TIVA to Switch) are measured at T10.11 and (RXP) and T10.9 (RXN). Please refer to Section **7.2.2.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0007

# Test Results

The electrical characteristics of Port0 Ethernet signals are as per the specification.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| **TIVA - Ethernet** | | | | | | | |
| Test | Measuring Point | Measuring Criteria | Observation | Specification | | Design Margin (%) | Test result |
| Min | Max |
| ETHSW\_TIVA\_P0\_TXP, ETHSW\_TIVA\_P0\_TXN | T10.16, T10.14 | Vp-p (V) | 2.24 | 1.9 | 2.63 | -14.83 | PASS |
| Overshoot (%) | 1.69 | 0 | 10 | -83.10 | PASS |
| Undershoot (%) | 1.61 | 0 | 10 | -83.90 | PASS |
| ETHSW\_TIVA\_P0\_RXP, ETHSW\_TIVA\_P0\_RXN | T10.11, T10.9 | Vp-p (V) | 2.2 | 1.9 | 2.63 | -15.79 | PASS |
| Overshoot (%) | 1.03 | 0 | 10 | -89.70 | PASS |
| Undershoot (%) | 0.099 | 0 | 10 | -99.01 | PASS |

**The detailed analysis report with waveform captured for electrical characteristics for TIVA – Port0 of marvel switch MDI test case is embedded in the xls document attached herewith.**

****

# Test ID / Test Name: ETH.3.2/ Functional validation

# Purpose

The purpose of the test case is to validate the function of TIVA – Marvell Switch (Port 0)

# Test and Measurement Method

This test is conducted by connecting a debug board to GBC. Ethernet cable from PC to port A (PD port) of GBC board. Flash the relevant code to TIVA so that signals between Port 0 of marvell switch and TIVA are initiated. Once IP address is assigned to TIVA, initiate the communication by pinging from PC using the TCPSendRecieve executable. Please refer to Section **7.2.2.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number – WZ1630LIFE2GBC0007

# Test Results

Communication is established between TIVA and Port 0 of Marvell switch at 100Mbps data rate.

**The snapshot of functional validation of TIVA –Ethernet interface is attached herewith.**



# Clocks

# Clock Sources

# Test ID / Test Name: CLK.1.1 / Frequency Accuracy

# Purpose

The purpose of this test case is to validate the frequency accuracy of crystal sources for 25MHz and 32.768 kHz.

# Test and Measurement Method

1. This test is conducted for the following 25MHz crystals:

i) Y3B2 at C3B22.1.

ii) Y2M3 at C2M26.2.

iii) Y2M1 at C2M2.2.

iv) X1 at C475.1.

v) X5 at C521.1

1. This test is also conducted for the following 32.768kHz crystal:

i) Y2M2 at C2N1.2

The values are captured by a frequency counter. For frequency accuracy and stability measured value (Hz) is converted to ppb by following the below procedure:

1. The difference between the ideal clock frequency and maximum frequency value is calculated (df).
2. Ppb is calculated by the equation:

Please refer to Section **8.2.1.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number- WZ1630LIFE2GBC0005

Software versions – NA

# Test Results

The frequency read at frequency counter is within the prescribed limit for Y3B2 and Y2M2 crystal.

# Measurement Logs

|  |  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **Y3B2 Clock - Frequency Accuracy** | | | | | | | | | |
| **Sl. No** | **Test Case ID** | **Ideal Clock Frequency(MHz)** | **Measured Frequency(MHz)** | **Deviation(MHz)** | **Frequency tolerance (ppb)** | **Specification** | | **Margin (%)** | **PASS / FAIL** |
| **Min(ppb)** | **Max(ppb)** |
| 1 | CLK1.1 | 25 | 24.9981645 | 0.002 | 73420 | -100000 | 100000 | -26.58 | PASS |
| 2 | CLK1.1 | 24.99816027 |
| 3 | CLK1.1 | 24.99815864 |
| 4 | CLK1.1 | 24.99815792 |

|  |  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **Y2B3 Clock - Frequency Accuracy** | | | | | | | | | |
| **Sl. No** | **Test Case ID** | **Ideal Clock Frequency(MHz)** | **Measured Frequency (MHz)** | **Deviation(MHz)** | **Frequency tolerance (ppb)** | **Margin** | | **Margin (%)** | **PASS / FAIL** |
| **Min(ppb)** | **Max(ppb)** |
| 1 | CLK1.1 | 25 | 24.99851 | 0.001487 | 59485.2 | -30000 | 30000 | 98.284 | FAIL |
| 2 | CLK1.1 | 24.99851 |
| 3 | CLK1.1 | 24.99851 |
| 4 | CLK1.1 | 24.99851 |
| 5 | CLK1.1 | 24.99851 |
| 6 | CLK1.1 | 24.99851 |

|  |  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **Y2M1 Clock - Frequency Accuracy** | | | | | | | | | |
| **Sl.No** | **Test Case ID** | **Ideal Clock Frequency(MHz)** | **Measured Frequency(MHz)** | **Deviation(MHz)** | **Frequency tolerance (ppb)** | **Specification** | | **Margin (%)** | **PASS / FAIL** |
| **Min (ppb)** | **Max (ppb)** |
| 1 | CLK1.1 | 25 | 24.99847 | 0.001529 | 61165.2 | -30000 | 30000 | 103.884 | FAIL |
| 2 | CLK1.1 | 24.99847 |
| 3 | CLK1.1 | 24.99847 |
| 4 | CLK1.1 | 24.99847 |
| 5 | CLK1.1 | 24.99847 |

|  |  |  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **Y2M2 Clock - Frequency Accuracy** | | | | | | | | | | |
| **Sl. No** | **Test Case ID** | **Ideal Clock Frequency(kHz)** | **Measured Frequency(kHz)** | **Deviation(kHz)** | **Frequency tolerance (ppb)** | **Specification** | | **Margin (%)** | **PASS / FAIL** |
| **Min(ppb)** | **Max(ppb)** |
| 1 | CLK1.1 | 32.768 | 32.76694167 | 0.00105833 | 32297.66846 | -50000 | 50000 | -35.40466 | PASS |
| 2 | CLK1.1 | 32.76693846 |
| 3 | CLK1.1 | 32.76693775 |

|  |  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **X1 Clock - Frequency Accuracy** | | | | | | | | | |
| **Sl.No** | **Test Case ID** | **Ideal Clock Frequency (MHz)** | **Measured Frequncy (MHz)** | **Deviation (MHz)** | **Frequency tolerance (ppb)** | **Specification** | | **Margin (%)** | **PASS / FAIL** |
| **Min (ppb)** | **Max (ppb)** |
| 1 | CLK1.1 | 25 | 24.99805495 | 0.00194505 | 77802 | 40000 | 50000 | 55.604 | FAIL |
| 2 | CLK1.1 | 24.99805339 |
| 3 | CLK1.1 | 24.99805276 |
| 4 | CLK1.1 | 24.99805273 |
| 5 | CLK1.1 | 24.99805229 |

|  |  |  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **X5 Clock - Frequency Accuracy** | | | | | | | | | | |
| **Sl. No** | **Test Case ID** | **Ideal Clock Frequency(MHz)** | **Measured Frequncy(MHz)** | **Deviation(MHz)** | **Frequency tolerance (ppb)** | **Specification** | | **Margin (%)** | **PASS / FAIL** |
| **Min (ppb)** | **Max (ppb)** |
| 1 | CLK1.1 | 25 | 24.99764676 | 0.00235324 | 94129.6 | -50000 | 50000 | 88.2592 | FAIL |
| 2 | CLK1.1 | 24.99764478 |
| 3 | CLK1.1 | 24.99764371 |
| 4 | CLK1.1 | 24.99764137 |

**NOTE:** Resolution for failure – TBD. This test case will be re-measured in Life-3.

**The detailed analysis report for Clock sources test case executed is attached herewith.**



# Test ID / Test Name: CLK.1.2 / Timing Jitter

# Purpose

The purpose of this test case is to validate the timing jitter of crystal clock sources.

# Test and Measurement Method

1. This test is conducted for the following 25MHz crystals:

i) Y3B2 at C3B22.1.

ii) Y2M3 at C2M26.2.

iii) Y2M1 at C2M2.2.

iv) X1 at C475.1.

v) X5 at C521.1

The jitter values are captured by an oscilloscope.

Please refer to Section **8.2.1.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number- WZ1630LIFE2GBC0002

Software versions – NA

# Test Results

The timing jitter of Y3B2 crystal is within the specified limit.

# Measurement Logs

|  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- |
| **Clock - Timing Jitter** | | | | | | | |
| **Sl.No** | **Test Case ID** | **Ideal Crystal Frequency** | **Cycle-to-cycle Jitter(ps)** | **Specification** | | **Margin (%)** | **PASS / FAIL** |
| **Min(ps)** | **Max(ps)** |
| 1 | CLK1.2 | Y3B2 - 25MHz | 145.24 | 0 | 300 | -51.59 | PASS |
| 2 | CLK1.2 | X5 - 25MHz | 59.014 | 0 | 50 | 18.03 | FAIL |
| 3 | CLK1.2 | X1 - 25MHz | 533.82 | 0 | 300 | 77.94 | FAIL |
| **Clock - Timing Jitter** | | | | | | | |
| **Sl.No** | **Test Case ID** | **Ideal Crystal Frequency** | **RMS Jitter(ps)** | **Specification** | | **Margin (%)** | **PASS / FAIL** |
| **Min(ps)** | **Max(ps)** |
| 1 | CLK1.2 | Y2M3 - 25MHz | 9.8884 | 0 | 1.5 | 559.23 | FAIL |
| 2 | CLK1.2 | Y2M1 - 25MHz | 8.16 | 0 | 1.5 | 444.00 | FAIL |
| 3 | CLK1.2 | X1 - 25MHz | 11.589 | 0 | 1.5 | 672.60 | FAIL |

**The detailed analysis report for clock sources jitter test case executed is attached herewith.**



**NOTE:** Resolution for failure – TBD. This test case will be re-measured in Life-3.

# PCIe - GBE clock

# Test ID / Test Name: CLK.2.1 / Frequency Accuracy

# Purpose

The purpose of this test case is to validate the frequency accuracy of 100MHz PCIe reference clock: PCIE0\_GBE\_CLKP.

# Test and Measurement Method

This test is conducted by probing 100MHz clock at R10647.1. The value is captured by a frequency counter for 6 iterations. For frequency accuracy and stability measured value (Hz) is converted to ppm by following the below procedure:

1. The difference between the ideal clock frequency and maximum frequency value is calculated (df).
2. Ppb is calculated by the equation:

Please refer to Section **8.2.2.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number- WZ1630LIFE2GBC0021

Software versions – NA

# Test Results

The frequency read at frequency counter is within the prescribed limit of 100MHz clock.

# Measurement Log

|  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **Clock - PCIe -GBE Clock - Frequency Accuracy** | | | | | | | | |
| **Sl. No** | **Test Case ID** | **Ideal Clock Frequency(MHz) - PCIE0\_GBE\_CLKP** | **Measured Frequency(MHz)** | **Deviation** | **Frequency tolerance (ppb)** | **Specification** | | **Margin (%)** | | **PASS / FAIL** |
| **Min (ppb)** | **Max (ppb)** |
| 1 | CLK2.1 | 100 | 99.994329 | 0.005671 | 56710 | -300000 | 300000 | 118.9033 | | PASS |
| 2 | CLK2.1 | 99.994326 |
| 3 | CLK2.1 | 99.994288 |
| 4 | CLK2.1 | 99.994235 |
| 5 | CLK2.1 | 99.994226 |
| 6 | CLK2.1 | 99.99422 |

**NOTE**: The detailed analysis report with waveform captured is embedded in the xls document attached in the end of this section.

# Test ID / Test Name: CLK.2.2 / Signal Integrity

# Purpose

The purpose of the test case is to validate the electrical characteristics of 100 MHz PCIe clock.

# Test and Measurement Method

This test is conducted by probing 100MHz clock at R10647.1. The value is captured on an oscilloscope and is within the prescribed limit by Intel microcontroller. Please refer to Section **8.2.2.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number- WZ1630LIFE2GBC0021

Software versions – NA

# Test Results

The electrical characteristics of 100 MHz PCIe Clock is within the designed spec.

# Measurement Log

|  |  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **PCIe - GBE clock - signal Integrity** | | | | | | | | | |
| **Sl. No** | **Test Case ID** | **Measuring Rail** | **Measurement location** | **Measured Parameter** | **Measured Value (V)** | **Specification** | | **Margin (%)** | **PASS/ FAIL** |
| **Min(V)** | **Max(V)** |
| 1 | CLK2.2 | PCIE0\_GBE\_CLKP | R10647.1 | Positive Over-shoot | 0.12 | 0 | 0.18 | -33.33 | PASS |
| 2 | CLK2.2 | PCIE0\_GBE\_CLKN | R10648.1 | Negative Over-shoot | 0.12 | 0 | 0.18 | -33.33 | PASS |

**NOTE**: The detailed analysis report with waveform captured is embedded in the xls document attached in the end of this section.

# Test ID / Test Name: CLK.2.3 / Timing Jitter

# Purpose

The purpose of the test case is to validate the Timing Jitter of 100 MHz PCIe Clock.

# Test and Measurement Method

This test is conducted by terminating PCIE0\_GBE\_CLKP and with a 2.2pF capacitor at R10647.1 and R10648.1. Probe at R10647.1 and R10648.1. Run the test utility N5393D in the infiniium oscilloscope. To configure the test suite, select PCIe version as 2.0, Refclk tests, Device1, Lan0. In select tests option in utility, select common clock tests and run all the selected test cases. The test utility generates the test report for all the test cases selected with the pass or fail criteria and its % margin. Please refer to Section **8.2.2.4** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number- WZ1630LIFE2GBC0021

Software versions – NA

# Test Results

The timing jitter for 100Mhz clock is checked and validated.

# Measurement Log

|  |  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **PCIe - GBE clock\_Timing Jitter** | | | | | | | | | |
| **Sl. No** | **Test Case ID** | **Measuring Rail** | **Measurement location** | **Measured Parameter** | **Measured Value (ps)** | **Specification** | | **Margin (%)** | **PASS/ FAIL** |
| **Min(V)** | **Max(V)** |
| 1 | CLK2.3 | PCIE0\_GBE\_CLKP | R10647.1 | RMS Jitter | 12.95 | NA | NA | NA | NA |
| Peak-to-peak jitter | 96.348 | 0 | 150 | -35.77 | PASS |

**The detailed analysis report with waveform captured for each of the 100MHz PCIe clock test case executed is embedded in the xls document attached herewith.**





# 40 MHz GPSDO Clock

# Test ID / Test Name: CLK.3.1 / Frequency Accuracy

# Purpose

The purpose of this test case is to validate the frequency accuracy of 40MHz reference clock for GPSDO. Please refer to Section **8.2.3.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test and Measurement Method

This test is conducted by probing 40MHz clock at R19.2. The value is captured by a frequency counter.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number- WZ1630LIFE2GBC0002

SYNC Board Serial Number- WZ1627LIFE1SYNC0011

Software versions – NA

# Test Results

The frequency read at frequency counter is within the prescribed limit of 40MHz clock.

# Measurement Log

|  |  |  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **Clock - GPSDO\_40MHz\_ Clock - Frequency Accuracy** | | | | | | | | |  | |
| **Sl. No** | **Test Case ID** | **Ideal Clock Frequency (MHz)** | **Measured Frequency (MHz)** | **Deviation (MHz)** | **Frequency tolerance (ppb)** | **Specification** | | **Margin %** | **PASS / FAIL** |
| **Min (ppb)** | **Max (ppb)** |
| 1 | CLK3.1 | 40 | 40.00008109 | 8.11E-05 | 2027.25 | -50 | 50 | 100.00016 | FAIL |
| 2 | CLK3.1 | 40.0000812 |
| 3 | CLK3.1 | 40.00008119 |
| 4 | CLK3.1 | 40.00008128 |

**NOTE:** Resolution for failure – TBD. This test case will be re-measured in Life-3.

The detailed analysis report with waveform captured is embedded in the xls document attached in the end of this section.

# Test ID / Test Name: CLK.3.2 / Signal Integrity

# Purpose

The purpose of the test case is to validate the electrical characteristics of 40 MHz GPSDO Clock.

# Test and Measurement Method

This test is conducted by probing the GPSDO Clock signal at R19.2 (Near Via). The measured values are well with-in the limit as specified in the LTE-Lite Module datasheet specification. Please refer to Section **8.2.3.3** of ‘SYNC Board’ Test specifications (Rev 0.1) for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number- WZ1630LIFE2GBC0002

SYNC Board Serial Number- WZ1627LIFE1SYNC0011

Software versions – NA

# Test Results

The electrical characteristics of 40 MHz GPSDO Clock is within the designed spec. 40MHz clock is coming out from the GPSDO Module.

# Measurement Log

|  |  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **Clock - GPSDO\_40MHz\_ Clock - Signal Integrity** | | | | | | | | | |
| **Sl. No** | **Test Case ID** | **Measuring Rail** | **Measurement location** | **Measured Parameter** | **Measured Value (V)** | **Specification** | | **Margin (%)** | **PASS/ FAIL** |
| **Min(V)** | **Max(V)** |
| 1 | CLK3.2 | LTE\_REF\_OUT\_40MHz | R19.2 | VLOW | 0.125 | 0 | 0.4 | -68.75 | PASS |
| VHIGH | 3.125 | 0.8 | 3.3 | -5.30 | PASS |

**NOTE**: The detailed analysis report with waveform captured is embedded in the xls document attached in the end of this section.

# Test ID / Test Name: CLK.3.3 / Timing Jitter

# Purpose

The purpose of the test case is to validate the Timing Jitter of 40 MHz GPSDO Clock.

# Test and Measurement Method

This test is conducted by probing the GPSDO Clock Signal Timing Jitter at R19.2 (Near Via). The measurement data will be compared with the measured data that will be made available by Jacksons Lab. Steps to measure RMS jitter through signal analyzer:

1. Connect Sync board to GBC board.
2. Configure DC power supply to give a voltage of 18V.
3. Set the central frequency to 40MHz in MXA signal Analyzer.
4. Carrier frequency will be automatically detected.
5. Go to Mode option, Select Phase Noise.
6. Go to Measure option and select Log Plot.
7. In Span option set start and stop offset values to 8kHz and 22MHz respectively
8. Select marker go to Integrated RMS Noise then select Jitter option.
9. Go to Band adjust set the left band (10 KHz) and right band (22MHz).
10. Measure the Jitter on the analyzer in pico second.
11. Select auto tune in frequency option at the end of each step.

Please refer to Section **8.2.3.4** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number- WZ1630LIFE2GBC0002

SYNC Board Serial Number- WZ1627LIFE1SYNC0011

Software versions – NA

# Test Results

The timing Jitter of 40 MHz GPSDO Clock is measured.

|  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **Clock - GPSDO\_40MHz\_ Clock - Timing Jitter** | | | | | | | | |
| **Sl. No** | **Test Case ID** | **Measuring Rail** | **Measurement location** | **Measured Parameter** | **Measured Value (ps)** | **Margin** | | **PASS/ FAIL** |
| **Min(V)** | **Max(V)** |
| 1 | CLK3.3 | LTE\_REF\_OUT\_40MHz | R10647.1 | RMS Jitter | 47.75 | NA | NA | NA |
| Peak-to-peak jitter | 355.26 | NA | NA | NA |

# Measurement Log

**The detailed analysis report with waveform captured for each of the SYNC Board Clock test case executed is embedded in the xls document attached herewith.**

  
**NOTE:**

For 40MHz clock jitter requirement, ADI indicates that the only requirement is of phase noise of Reference input. There is no requirement for jitter as there is internal PLL in ADI that cleans the clock. Therefore, measurement was done to capture the baseline performance, and was not against any specification.

# HDMI clock

# Test ID / Test Name: CLK.4.1 / Frequency Accuracy

# Purpose

The purpose of this test case is to validate the frequency accuracy of HDMI clock.

# Test and Measurement Method

Connect debug board to GBC. Probe HDMI\_CLK\_DP and HDMI\_CLK\_DN at C4N2.2 and C4N1.2 respectively. Measure the frequency value using oscilloscope. Please refer to Section **8.2.4.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number- WZ1630LIFE2GBC0002

Software versions – NA

# Test Results

The frequency read at frequency counter is within the prescribed limit of 100MHz HDMI clock.

# Measurement Log

|  |  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **Clock - 100MHz\_ Clock - Frequency Accuracy** | | | | | | | | | |
| **Sl. No** | **Test Case ID** | **Ideal Clock Frequency (MHz)** | **Measured Frequency (MHz)** | **Deviation (Hz)** | **Frequency tolerance (ppb)** | **Specification** | | **Margin (%)** | **PASS / FAIL** |
| **Min(ppb)** | **Max(ppb)** |
| 1 | CLK4.1 | 100 | 107.9 | 7.9 | 79 | -1000000 | 1000000 | 100.01 | PASS |

**NOTE**: The detailed analysis report with waveform captured is embedded in the xls document attached in the end of this section.

# Test ID / Test Name: CLK .4.2 / Signal Integrity

# Purpose

The purpose of the test case is to validate the electrical characteristics of 100 MHz HDMI Clock.

# Test and Measurement Method

Connect debug board to GBC. Probe HDMI\_CLK\_DP and HDMI\_CLK\_DN at C4N2.2 and C4N1.2 respectively. Measure the overshoot and undershoot parameters for HDMI clock using oscilloscope. Please refer to Section **8.2.4.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number- WZ1630LIFE2GBC0002

Software versions – NA

# Test Results

The electrical characteristics of 100 MHz HDMI Clock is within the designed spec.

# Measurement Log

|  |  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **Clock - 100MHz\_ Clock - Frequency Accuracy** | | | | | | | | | |
| **Sl. No** | **Test Case ID** | **Measuring Rail** | **Measurement location** | **Measured Parameter** | **Measured Value (V)** | **Specification** | | **Margin (%)** | **PASS/ FAIL** |
| **Min(V)** | **Max(V)** |
| 1 | CLK4.2 | HDMI\_CLK\_DP and HDMI\_CLK\_DN | C4N2.2 and C4N1.2 | Positive Over-shoot | 0.16 | 0 | 0.78 | -79.49 | PASS |
| Negative Over-shoot | 0.2 | 0 | 0.2 | 0.00 | PASS |

**The detailed analysis report with waveform captured for each of the 100MHz PCIe clock test case executed is embedded in the xls document attached herewith.**



# GPS 1pps clock

# Test ID / Test Name: CLK.5.1 / Frequency Accuracy

# Purpose

The purpose of this test case is to validate the 1pps clock.

# Test and Measurement Method

Connect Sync board to GBC board. Probe R48.1 on sync board in order to check 1pps clock. Measure the frequency using frequency counter. Please refer to Section **8.2.5.2** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number- WZ1630LIFE2GBC0005

SYNC Board Serial Number- WZ1627LIFE1SYNC0011

Software versions – NA

# Test Results

The frequency read at frequency counter is 1Hz and is within the prescribed limit.

# Measurement Logs

|  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **Clock - SYNC\_1pps\_ Clock - Frequency Accuracy** | | | | | | | | |
| **Sl. No** | **Test Case ID** | **Ideal Clock Frequency(Hz)** | **Measured Frequency(Hz)** | **Deviation(Hz)** | **Frequency tolerance (ppb)** | **Margin** | | **PASS / FAIL** |
| **Min(ppb)** | **Max(ppb)** |
| 1 | CLK.5.1 | 1 | 1.000002022 | 2.0215E-06 | 2021.5 | NA | NA | NA |
| 2 | CLK.5.1 | 1.000002018 |
| 3 | CLK.5.1 | 1.000002198 |
| 4 | CLK.5.1 | 1.000002037 |
| 5 | CLK.5.1 | 1.000002021 |

**NOTE**: The detailed analysis report with waveform captured is embedded in the xls document attached in the end of this section.

# Test ID / Test Name: CLK.5.2 / Signal Integrity

# Purpose

The purpose of the test case is to validate the electrical characteristics of 1pps clock.

# Test and Measurement Method

Connect Sync board to GBC board. This test is conducted by probing 1pps clock at R48.1 on the sync board. The value is captured on an oscilloscope. Please refer to Section **8.2.5.3** in latest version of “OC\_CONNECT\_1\_GBC\_Test\_Specification” document for detailed test procedure.

# Test Condition

Ambient Temperature – 25˚C

Operating Voltage – 18V

System load – Typical

# DUT Sample Information

GBC Board Serial Number- WZ1630LIFE2GBC0005

SYNC Board Serial Number- WZ1627LIFE1SYNC0011

Software versions – NA

# Test Results

# Measurement Log

|  |  |  |  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- | --- | --- | --- |
| **Sync Board - 1Hz Signal Integrity** | | | | | | | | |
| **Sl. No** | **Test Case ID** | **Measuring Rail** | **Measurement location** | **Measured Parameter** | **Measured Value** | **Margin** | | **PASS/ FAIL** |
| **Min(V)** | **Max(V)** |
| 1 | CLK.5.2 | R\_LTE\_1\_PPS\_OUT | R48.1 | Frequency | 1 Hz | NA | NA | NA |
| 2 | Voltage Peak to Peak | 3.690 V | NA | NA | NA |
| 3 | Overshoot | 160 mV | NA | NA | NA |
| 4 | Undershoot | 140 mV | NA | NA | NA |

**The detailed analysis report with waveform captured for each of the 1Hz clock test case executed is embedded in the xls document attached herewith.**

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# Revision History

|  |  |  |  |  |
| --- | --- | --- | --- | --- |
| SL.no | Date | Version | Author | Comments |
| 1 | February 9th, 2017 | 1.0 | OpenCellular Team | First Release |